



# TOTAL DOSE RADIATION TEST REPORT

**Part Type : ADC14161**

**Package : 52-Pin TQFP**

**14-Bit, 2.5 MSPS A/D Converter**

**National Semiconductor**

**Report Reference : ESA\_QCA991203T\_C**

**Issue : 01**

**Date : December 27<sup>th</sup> 1999**

**ESA Contract No 13602/99/NL/GD dated 18/06/99**

European Space Agency Contract Report

The work described in this report was done under ESA contract.  
Responsibility for the contents resides in the author or organization that prepared it

**ESTEC Technical Officer: R. Harboe Sorensen**

<b>Hirex reference :</b>	HRX/99.5072	Issue : 01	Date :	Dec. 27 <sup>th</sup> 1999
<b>Written by :</b>	J.F. PASCAL		Date :	
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# TOTAL DOSE RADIATION TEST REPORT

## on

### National Semiconductor ADC14161 14-Bit A/D Converter.

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<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor

## 1 Abstract

Under ESA/ESTEC contract n° 13602/99/NL/GD dated 18/06/99 covering "Radiation Pre-screening of High-resolution High-speed ADC's", three different 14-bit Analog to Digital converters were radiation assessed. Results from these assessments, primarily focused on the radiation sensitivity of the ADC's to Total Ionizing Dose (TID) and Single Event Effects (SEE), are reported in individual TID and SEE reports. Below summary table lists manufacturer and evaluated types, and gives references to the various reports issued.

<b>Manufacturer</b>	<b>Type</b>	<b>TID Report</b>	<b>SEE Report</b>
Analog Devices	AD9243	ESA_QCA991201T_C	ESA_QCA991201S_C
Linear Technology	LTC1414	ESA_QCA991202T_C	ESA_QCA991202S_C
National Semiconductor	ADC14161	ESA_QCA991203T_C	ESA_QCA991203S_C

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## 2 Introduction

A total dose radiation evaluation test of the National Semiconductor ADC14161 14-Bit A/D Converter has been performed with an accumulated dose of about 50 Krad(Si) at two different dose rates of 300 rad(Si)/hour and 1000 rad(Si)/hour respectively, in response to European Space Agency contract reference : 13602/99/NL/GD dated 18/06/99.

The purpose of this test was to evaluate total dose withstanding of this component, to investigate its suitability for being used in space applications. This test was conducted on commercial samples procured from National Semiconductor.

Test has been performed in accordance with Hirex proposal HRX/99.4366 issue 01.

A complete set of electrical measurements together with graphical representation of measured parameters with respect to total dose received, are provided for all samples.

SEE results for this device type can be found in SEE radiation test report: ESA\_QCA991203S\_C.

## 3 Applicable and Reference Documents

### 3.1 Applicable Documents

- ESA/SCC Basic specification N° 22900 issue 4.
- National Semiconductor ADC14161 datasheet - december 1998.
- Hirex Engineering proposal: HRX/99.4366 issue 01.

### 3.2 Reference Documents

- SOW Radiation Pre-screening of High-resolution High-speed ADC's Ref: APP-JP/99-02-057/PS/ps.
- MIL-STD-883: test methods and procedures for microcircuits.

## 4 Test Samples

6 samples of the ADC14161 device were tested (2 groups of 3 + 1 control sample). Each group was submitted to exposures at two different dose rates (a high dose rate of 1000 rad(Si)/hour and a low dose rate of 300 rad(Si)/hour respectively).

The samples were serialized before the radiation test as indicated in the following table.

Serial Number	Allocation
1	Control
2	High Dose Rate
3	High Dose Rate
4	High Dose Rate
5	Low Dose Rate
6	Low Dose Rate
7	Low Dose Rate

Identification of the ADC14161 is given below:

<b>Part Number:</b>	ADC14161CIVT	<b>Mask Set:</b>	NA
<b>Top Marking:</b>	E9752AD ADC14161 CIVT	<b>Chip Marking:</b>	NA
<b>Diffusion Lot:</b>	NA	<b>Wafer #:</b>	NA
<b>Date Code:</b>	E9752AD	<b>Project:</b>	Multi-Project

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## 5 Experimental Conditions

### 5.1 Radiation Source Dose Rate and Annealing

The dose exposures were performed at CERT-ONERA. In this irradiation facility, a Cobalt 60 source is used with the possibility to vary the dose rate by simply adjusting the distance to the source. The irradiation conditions used for this test are provided in the following tables:

<b>Irradiation Steps</b>	<b>Doserate</b>	<b>Annealing steps</b>	<b>Temperature</b>
<b>krads</b>	<b>krads/h</b>	<b>hours</b>	<b>°C</b>
0			25
7	1,0		25
22	1,0		25
28	1,0		25
43.3	1,0		25
50	1,0	0	25
		24	25
		192	100

**Table 1 : Experimental Conditions: High Dose Rate**

<b>Irradiation Steps</b>	<b>Doserate</b>	<b>Annealing steps</b>	<b>Temperature</b>
<b>krads</b>	<b>krads/h</b>	<b>hours</b>	<b>°C</b>
0			25
7.2	0,3		25
14.1	0,3		25
21	0,3		25
29.4	0,3		25
50.2	0,3	0	25
		24	25
		192	100

**Table 2 : Experimental Conditions: Low Dose Rate**

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
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## 5.2 Bias during Dose Exposures and Measurements conditions

### 5.2.1 Bias conditions

During exposures a dedicated test board was used mounted on a special board-holder made for irradiation. The test board allowed to bias the devices in accordance with the electrical circuit provided in Figure 1.

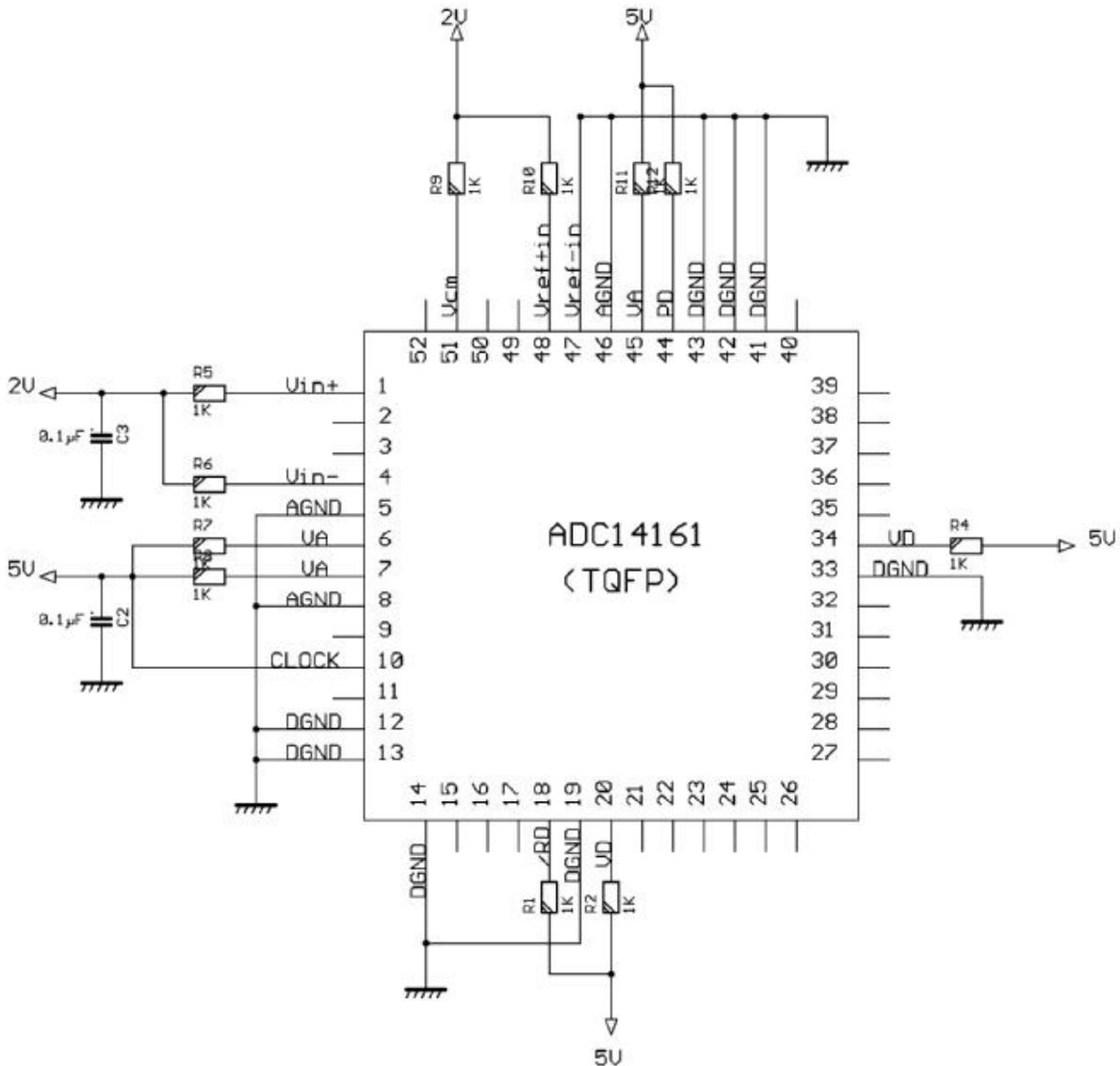


Figure 1 : Bias Conditions during Irradiation Exposures and Annealing

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
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## 5.2.2 Electrical Measurements

### 5.2.2.1 Test Setup

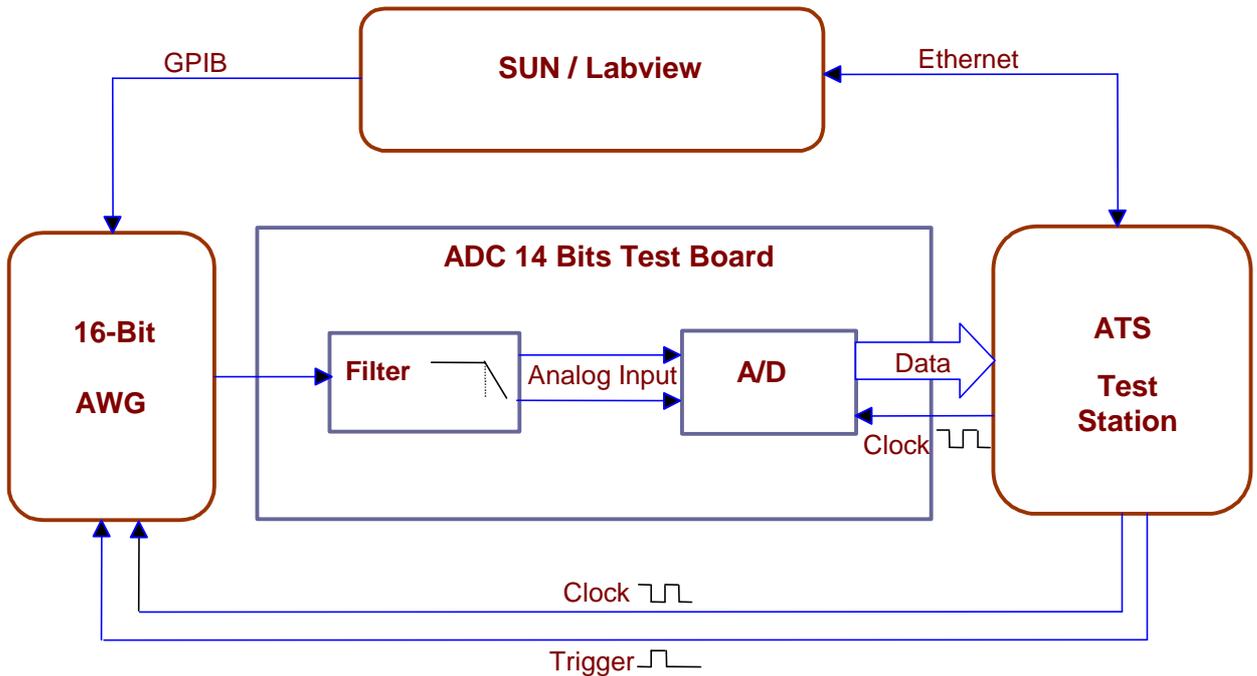
Electrical parameters test program principle for ADC14161 is provided in Figure 2.

The test Setup for this ADC includes an IMS ATS Test Station, an arbitrary waveform generator (AWG), and a filter. To ensure coherent clocking to the digital tester, ADC, and AWG, the clock from the ATS is used.

The AWG has 16 bits of resolution, and provides pure enough signal to the test board thanks to internal seventh-order butterworth and third-order Chebyshev filters. Additional filtering was also implemented on the test fixture board to clean the noise and distortion from the input signal.

After input signal is generated, the ATS acquires data output by the ADC. The dedicated Labview program analyses the data and displays the results on a SUN workstation.

The combination of high-speed digital signals and sensitive high-resolution analog signals on the same DUT requires effective techniques for isolating the digital switching transients from the analog signals. With proper grounding and fixture-board layering it is possible to effectively shield signals and maintain signal integrity. In addition minimizing grounding problems is required and was ensured by carefully selecting and connecting the socket and by using the correct decoupling methods. These constraints have led to the design of a specific multilayer test board (See photo of this board in figure 3).



**Figure 2 : ADC14161 test program principle**

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor

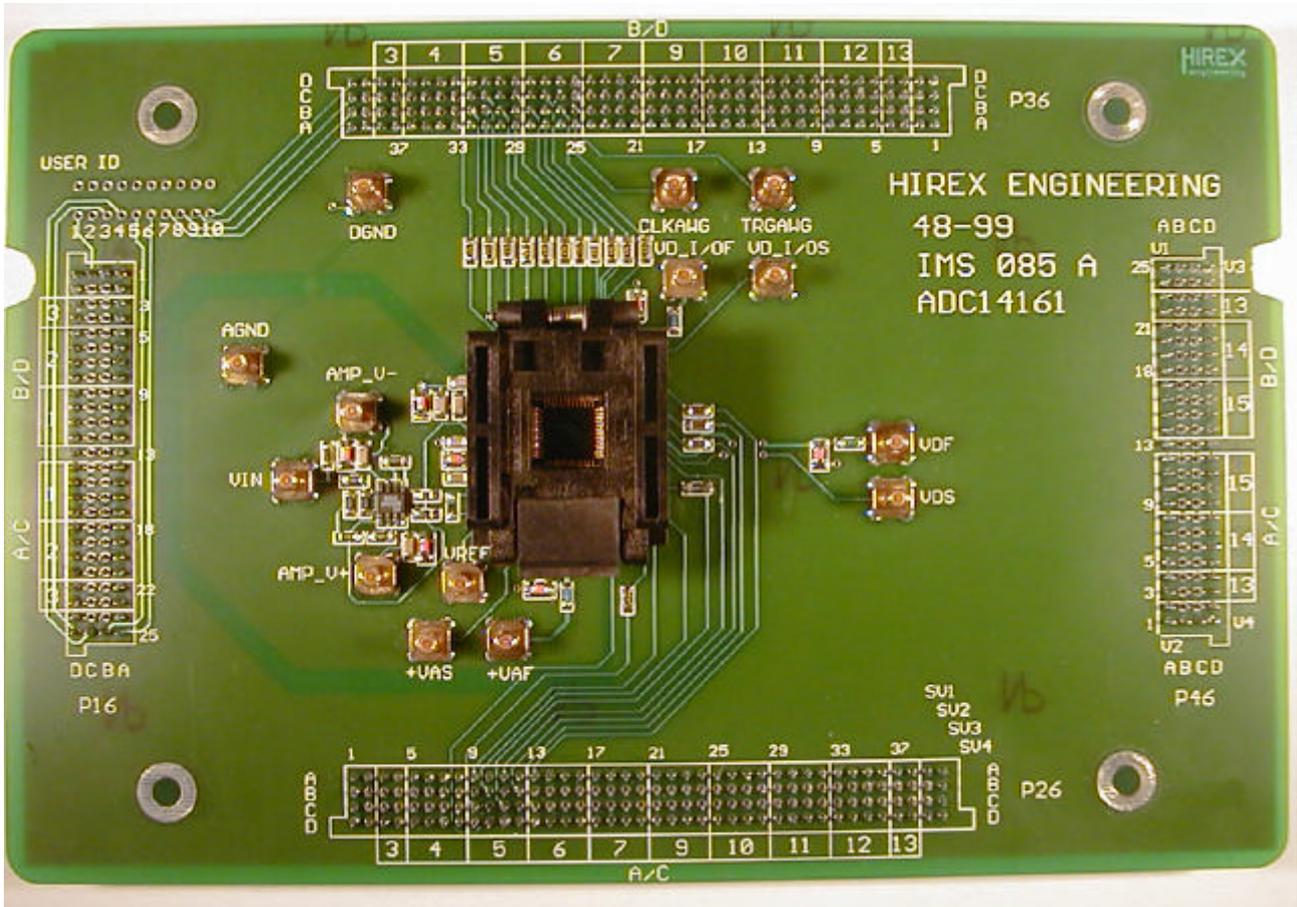


Figure 3 : ADC14161 Test Fixture Board

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor

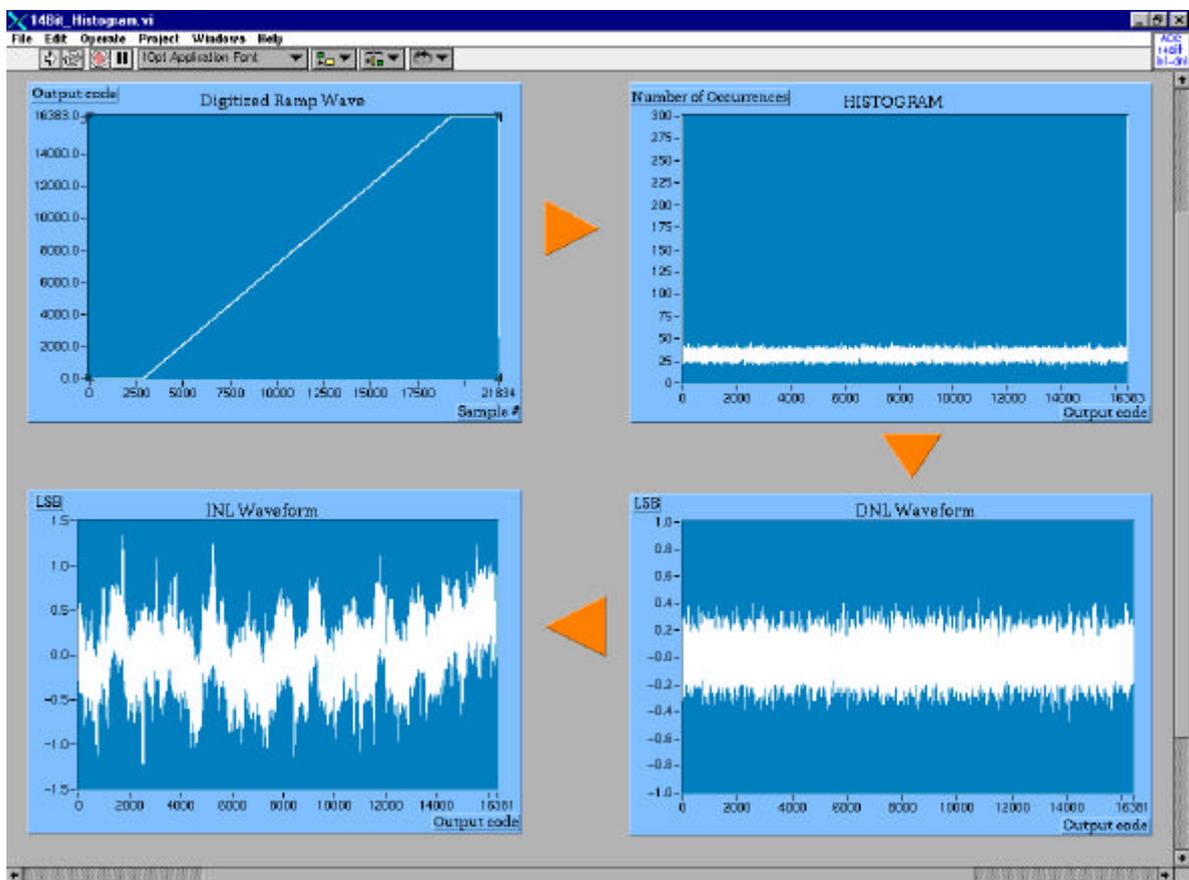
### 5.2.2.2 Conversion Characteristics Test Principle

For conversion characteristics including Differential Non Linearity, Integral Non Linearity, Offset Error, Gain Error, a histogram test technique was used.

A full scale pure ramp is input to the ADC. Thousands samples of the input signal are taken and processed by the histogram software. At the end of sampling, the histogram is plotted with possible output codes along the X axis and frequency of occurrence along Y axis. Above each possible output code, a point is plotted whose height is proportional to the total number of times that code occurred.

From histogram test data, dedicated math routines calculate the different parameter values.

An example of histogram obtained and typical waveforms for Integral and Differential Non linearities is shown on Figure 4.



**Figure 4 : Conversion Characteristics Example**

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
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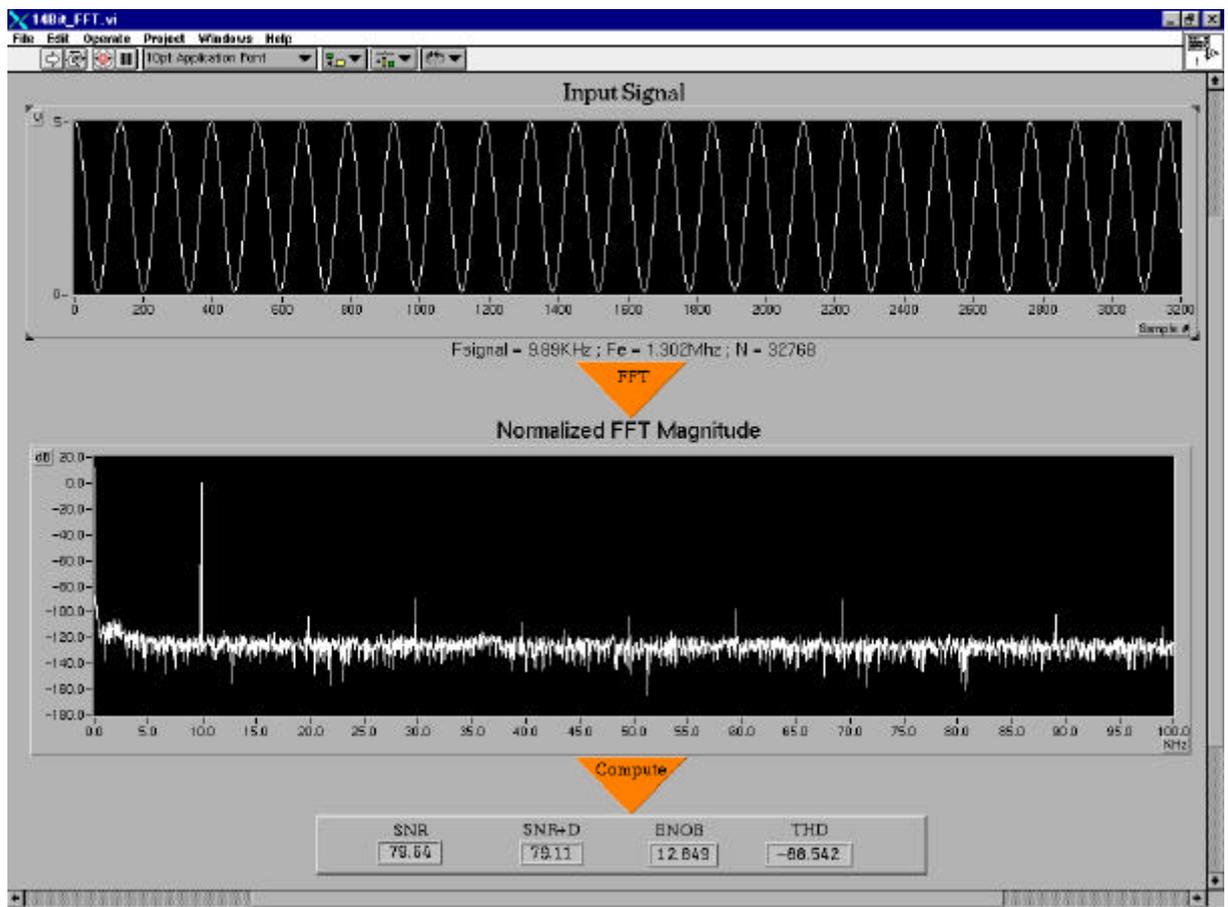
### 5.2.2.3 Dynamic Characteristics

For dynamic characteristics including Signal-to-Noise Ratio, Signal-to-Noise Plus Distortion Ratio, Effective Number of Bits, and Total Harmonic Distortion, a Fast Fourier Transform (FFT) algorithm was implemented.

A full scale sinewave of specified frequency is input to the device under test. Harmonics of the input sinewave, caused by the integral nonlinearity of the ADC, are aliased into the baseband spectrum and can be readily identified. The frequency of the input sinewave is not arbitrary and must be selected so that harmonics, aliased into baseband, do not coincide with the fundamental.

From FFT spectra test data, dedicated math routines calculate the different parameter values.

Figure 5 shows an example of results of FFT testing.



**Figure 5 : Dynamic Characteristics Example**

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### 5.3 Electrical parameters test conditions and limits

Electrical parameters test conditions and limits used for performing this test are given in the following table.

Symbol	Test Parameter	Test Conditions	Min limit	Max limit	Unit
SNR	Signal-to-Noise Ratio	VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: $\pm 2V$ , 10KHz; Fsample=1.3MHz	77		dB
SNR/D	Signal-to-Noise Plus Distortion Ratio	VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: $\pm 2V$ , 10KHz; Fsample=1.3MHz	76		dB
ENOB	Effective Number Of Bits	VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: $\pm 2V$ , 10KHz; Fsample=1.3MHz	12.3		LSB
THD	Total Harmonic Distortion	VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: $\pm 2V$ , 10KHz; Fsample=1.3MHz; Nine Harmonics		-80	dB
INL	Integral Nonlinearity	VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: $\pm 2V$		2.5	LSB
DNL	Differential Nonlinearity	VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: $\pm 2V$		1	LSB
ZOE	Zero Offset Error	VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: 0V	-0.6	0.6	% FSR
FSE	Full-Scale Error	VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: 2V	-2.8	2.8	% FSR
IA	Analog Supply Current	VA=+5V; VD=+5V; VDI/O=+5V		0.085	A
ID	Digital Supply Current	VA=+5V; VD=+5V; VDI/O=+5V		0.008	A
IDI/O	Digital Output Bus Supply Current	VA=+5V; VD=+5V; VDI/O=+5V		0.002	A
Vih	High Level Input Voltage	VA=+5V; VD=+5V; VDI/O=+5V		3.5	V
Vil	Low Level Input Voltage	VA=+5V; VD=+5V; VDI/O=+5V	1		V
VOH13	High Level Output Voltage Pin 38	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH12	High Level Output Voltage Pin 37	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V

**Table 3 : Measured electrical parameters**

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
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Symbol	Test Parameter	Test Conditions	Min limit	Max limit	Unit
VOH11	High Level Output Voltage Pin 36	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH10	High Level Output Voltage Pin 35	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH9	High Level Output Voltage Pin 32	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH8	High Level Output Voltage Pin 31	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH7	High Level Output Voltage Pin 30	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH6	High Level Output Voltage Pin 29	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH5	High Level Output Voltage Pin 28	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH4	High Level Output Voltage Pin 27	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH3	High Level Output Voltage Pin 26	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH2	High Level Output Voltage Pin 25	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH1	High Level Output Voltage Pin 24	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOH0	High Level Output Voltage Pin 23	VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA	2.5		V
VOL13	Low Level Output Voltage Pin 38	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL12	Low Level Output Voltage Pin 37	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL11	Low Level Output Voltage Pin 36	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL10	Low Level Output Voltage Pin 35	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL9	Low Level Output Voltage Pin 32	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V

**Table 3 : Measured electrical parameters (continued)**

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
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Symbol	Test Parameter	Test Conditions	Min limit	Max limit	Unit
VOL8	Low Level Output Voltage Pin 31	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL7	Low Level Output Voltage Pin 30	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL6	Low Level Output Voltage Pin 29	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL5	Low Level Output Voltage Pin 28	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL4	Low Level Output Voltage Pin 27	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V
VOL3	Low Level Output Voltage Pin 26	VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA		0.4	V

**Table 3 : Measured electrical parameters (continued)**

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
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## 6 Conclusion

A Total Ionizing Dose assessment was carried out by Hirex Engineering under ESA contract on the National Semiconductor ADC14161 14-Bit Analog to Digital Converter. 2 groups of 3 samples each plus one control sample were used during testing. The first group was exposed to radiation using a dose rate of 1000 rad(Si)/hour. The second group of 3 samples was exposed to radiation using a lower dose rate of 300 rad(Si)/hour. All devices were irradiated and tested at room temperature.

At high dose rate, the most affected parameters are ID and IDI/O the digital supply current and the digital output bus supply current respectively.

ID went out of specification at 22 Krad(Si), continued to degrade during subsequent exposures but recovered completely during last annealing step. The same phenomenon is observed for IDI/O that is however outside specification limit at a higher dose level of 43 Krad(Si).

SNR, SND+D, ENOB, and DNL exhibited a rebound effect during 24 hours annealing step, but did recover during last annealing step.

All other measured parameters remained within specification limits all along testing.

At low dose rate, a lost of functionality was observed at 50 Krad(Si) on some samples but the affected devices recovered during last annealing step.

This phenomenon can be observed on the drift of SNR, ENOB, THD, INL, ZOE and FSE parameters. ID and IDI/O have shown the same behaviour that was observed at high dose rate exposures. ID and IDI/O going outside specification limits at 21 Krad(Si) and 50 Krad(Si) respectively.

All other measured parameters remained within specification limits all along testing.

No significant changes were recorded depending on the dose rate conditions, except the lost of functionality during low dose rate experiment with recovery during annealing.

Some Time Dependent Effects (TDE) were recorded during this evaluation, leading most of the time to a recovery of affected parameters.

This device has shown some weaknesses at accumulated dose as low as 21 Krad(Si).

Details on test results can be found in Appendix 1 and Appendix 2 for high dose rate and low dose rate respectively.

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
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**APPENDIX 1 : TEST RESULTS - HIGH DOSE RATE**

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
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Test results including tables and graphics are provided in this section for each measured parameter corresponding to a high dose rate exposure.

**Parameter: Signal-to-Noise Ratio: SNR**

**A=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V, 10KHz; Fsample=1.3MHz**

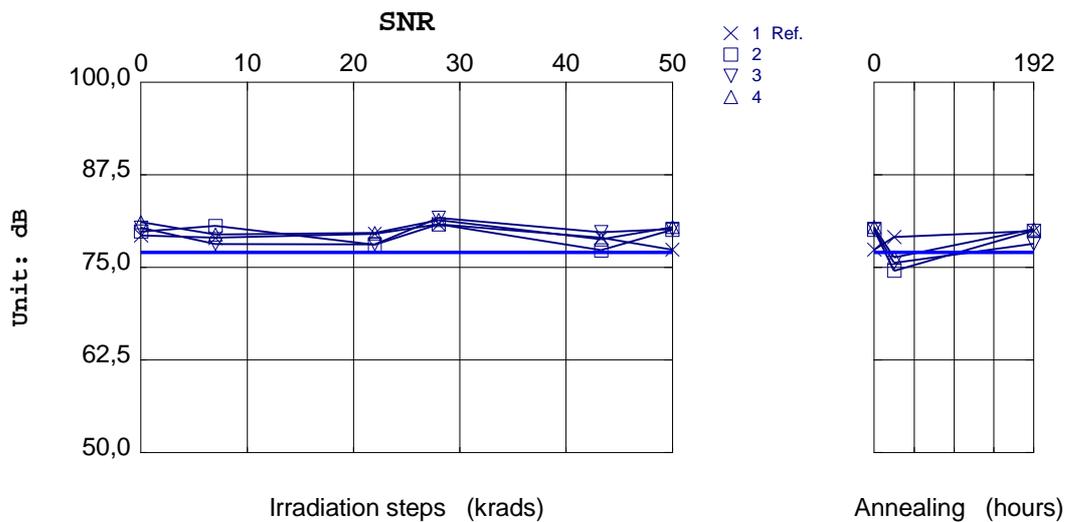
Unit= dB

Spec limit min: 77

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	7,929E +01	7,897E +01	7,952E +01	8,080E +01	7,900E +01	7,737E +01	7,909E +01
2	7,983E +01	8,059E +01	7,804E +01	8,079E +01	7,729E +01	8,007E +01	7,453E +01
3	8,034E +01	7,816E +01	7,810E +01	8,168E +01	7,974E +01	8,016E +01	7,560E +01
4	8,109E +01	7,943E +01	7,961E +01	8,140E +01	7,880E +01	8,043E +01	7,632E +01
Statistics							
Min	7,983E +01	7,815E +01	7,804E +01	8,079E +01	7,729E +01	8,007E +01	7,453E +01
Max	8,109E +01	8,059E +01	7,961E +01	8,168E +01	7,974E +01	8,043E +01	7,632E +01
Mean	8,042E +01	7,939E +01	7,858E +01	8,129E +01	7,861E +01	8,022E +01	7,548E +01
Sigma	6,340E -01	1,218E +00	8,899E -01	4,558E -01	1,237E +00	1,876E -01	8,994E -01

Test Step	192 hours
Serial #	
1 Ref.	7,992E +01
2	7,993E +01
3	7,817E +01
4	8,015E +01
Statistics	
Min	7,817E +01
Max	8,015E +01
Mean	7,942E +01
Sigma	1,086E +00

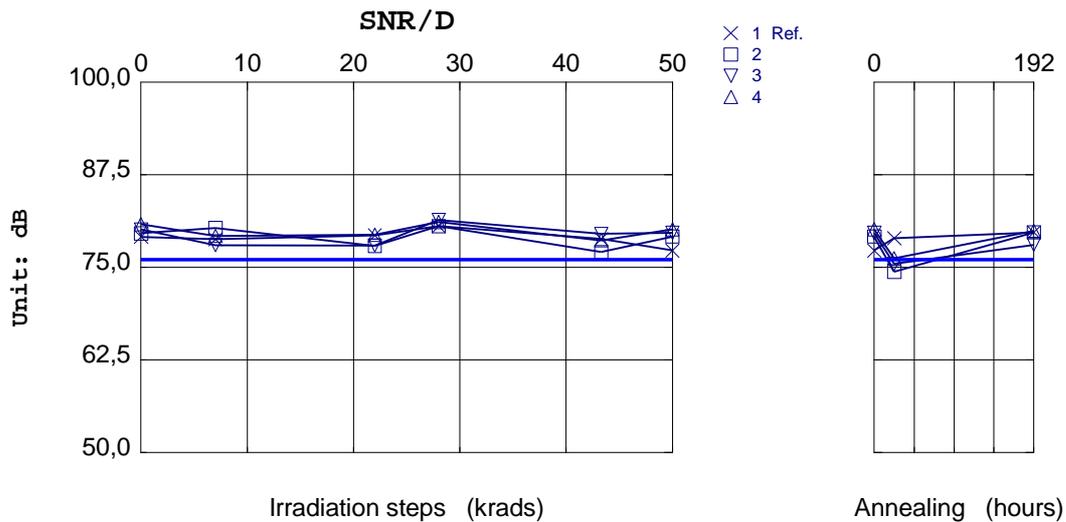


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Parameter: Signal-to-Noise Plus Distortion Ratio: SNR/D  
VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V, 10KHz; Fsample=1.3MHz  
Unit= dB  
Spec limit min: 76  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	7,910E +01	7,878E +01	7,929E +01	8,053E +01	7,883E +01	7,725E +01	7,892E +01
2	7,958E +01	8,029E +01	7,788E +01	8,054E +01	7,707E +01	7,914E +01	7,437E +01
3	8,010E +01	7,799E +01	7,795E +01	8,140E +01	7,950E +01	7,964E +01	7,544E +01
4	8,080E +01	7,922E +01	7,940E +01	8,112E +01	7,864E +01	8,013E +01	7,623E +01
Statistics							
Min	7,958E +01	7,799E +01	7,788E +01	8,054E +01	7,707E +01	7,914E +01	7,437E +01
Max	8,080E +01	8,029E +01	7,940E +01	8,140E +01	7,950E +01	8,013E +01	7,623E +01
Mean	8,016E +01	7,917E +01	7,841E +01	8,102E +01	7,840E +01	7,964E +01	7,534E +01
Sigma	6,144E -01	1,151E +00	8,565E -01	4,359E -01	1,234E +00	4,910E -01	9,339E -01

Test Step	192 hours
Serial #	
1 Ref.	7,971E +01
2	7,970E +01
3	7,804E +01
4	7,992E +01
Statistics	
Min	7,804E +01
Max	7,992E +01
Mean	7,922E +01
Sigma	1,027E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Effective Number Of Bits: ENOB**

VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V, 10KHz; Fsample=1.3MHz

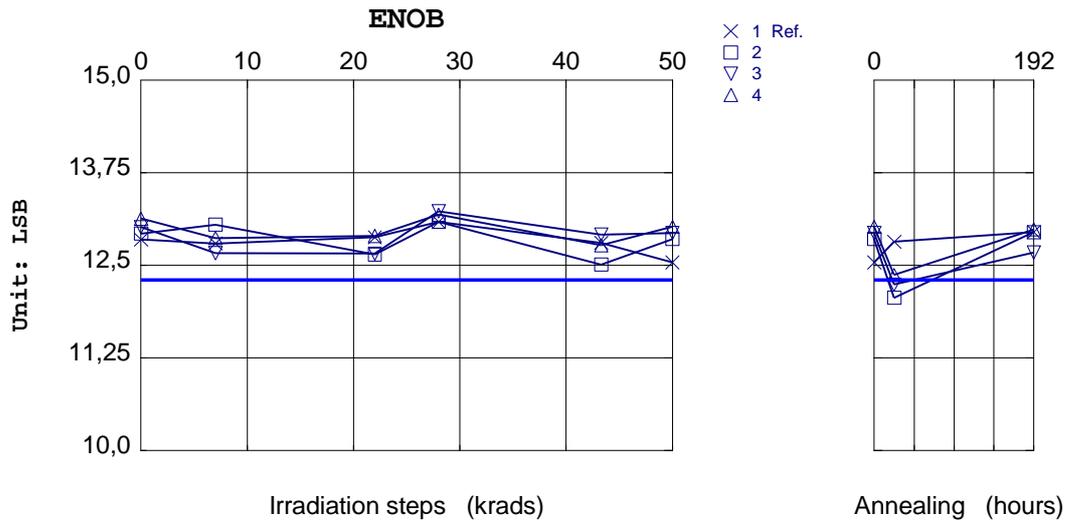
Unit= LSB

Spec limit min: 12.3

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,285E +01	1,279E +01	1,288E +01	1,309E +01	1,280E +01	1,254E +01	1,282E +01
2	1,293E +01	1,305E +01	1,265E +01	1,309E +01	1,251E +01	1,285E +01	1,206E +01
3	1,301E +01	1,266E +01	1,266E +01	1,323E +01	1,291E +01	1,294E +01	1,224E +01
4	1,313E +01	1,287E +01	1,290E +01	1,318E +01	1,277E +01	1,302E +01	1,237E +01
Statistics							
Min	1,293E +01	1,266E +01	1,265E +01	1,309E +01	1,251E +01	1,285E +01	1,206E +01
Max	1,313E +01	1,305E +01	1,290E +01	1,323E +01	1,291E +01	1,302E +01	1,237E +01
Mean	1,302E +01	1,286E +01	1,273E +01	1,317E +01	1,273E +01	1,294E +01	1,222E +01
Sigma	1,023E -01	1,916E -01	1,418E -01	7,245E -02	2,048E -01	8,200E -02	1,551E -01

Test Step	192 hours
Serial #	
1 Ref.	1,295E +01
2	1,295E +01
3	1,267E +01
4	1,298E +01
Statistics	
Min	1,267E +01
Max	1,298E +01
Mean	1,287E +01
Sigma	1,704E -01



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Total Harmonic Distortion: THD**

**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V, 10KHz; Fsample=1.3MHz; Nine Harmonics**

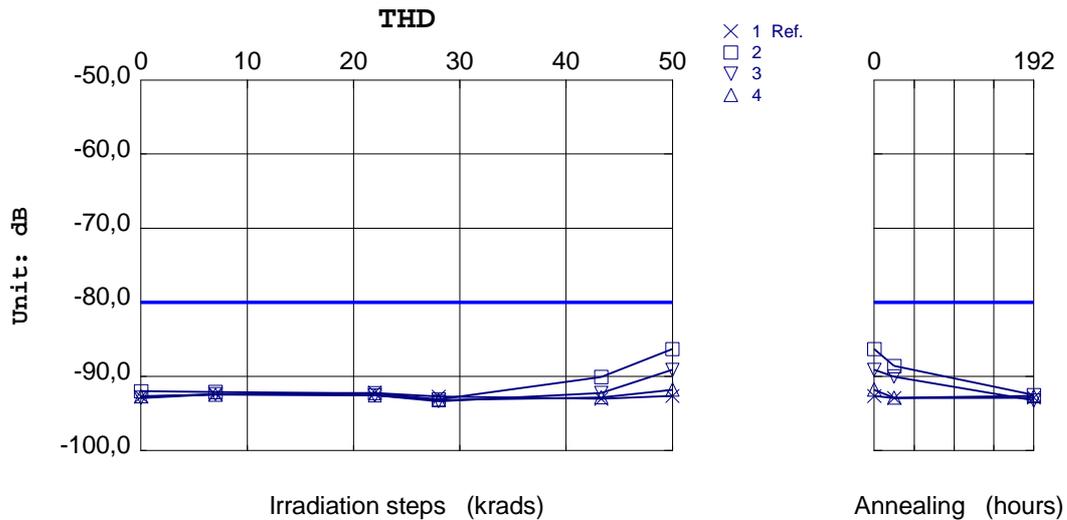
Unit= dB

Spec limit max: -80

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	-9,275E +01	-9,239E +01	-9,221E +01	-9,272E +01	-9,303E +01	-9,263E +01	-9,292E +01
2	-9,199E +01	-9,210E +01	-9,227E +01	-9,310E +01	-9,009E +01	-8,629E +01	-8,859E +01
3	-9,289E +01	-9,239E +01	-9,256E +01	-9,336E +01	-9,223E +01	-8,910E +01	-9,001E +01
4	-9,269E +01	-9,247E +01	-9,256E +01	-9,318E +01	-9,283E +01	-9,177E +01	-9,287E +01
Statistics							
Min	-9,289E +01	-9,247E +01	-9,256E +01	-9,336E +01	-9,283E +01	-9,177E +01	-9,287E +01
Max	-9,199E +01	-9,210E +01	-9,227E +01	-9,310E +01	-9,009E +01	-8,629E +01	-8,859E +01
Mean	-9,252E +01	-9,232E +01	-9,246E +01	-9,321E +01	-9,172E +01	-8,905E +01	-9,049E +01
Sigma	4,742E -01	1,945E -01	1,648E -01	1,333E -01	1,440E +00	2,740E +00	2,182E +00

Test Step	192 hours
Serial #	
1 Ref.	-9,288E +01
2	-9,252E +01
3	-9,324E +01
4	-9,264E +01
Statistics	
Min	-9,324E +01
Max	-9,252E +01
Mean	-9,280E +01
Sigma	3,842E -01

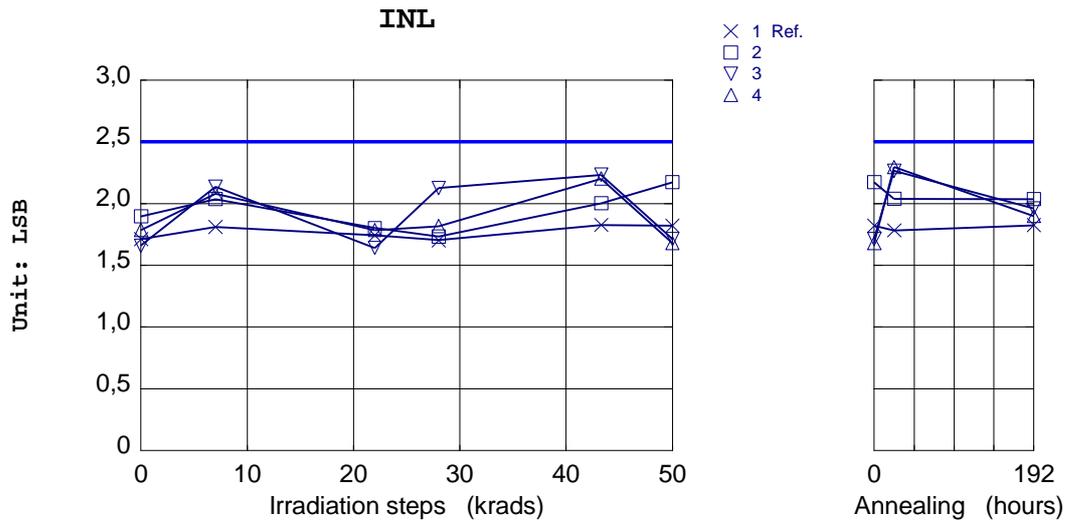


<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Integral Nonlinearity: INL**  
**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V**  
Unit= LSB  
Spec limit max: 2.5  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,712E +00	1,810E +00	1,743E +00	1,702E +00	1,826E +00	1,820E +00	1,782E +00
2	1,895E +00	2,035E +00	1,802E +00	1,733E +00	2,002E +00	2,172E +00	2,038E +00
3	1,659E +00	2,136E +00	1,640E +00	2,125E +00	2,233E +00	1,712E +00	2,265E +00
4	1,786E +00	2,079E +00	1,785E +00	1,817E +00	2,202E +00	1,679E +00	2,295E +00
Statistics							
Min	1,659E +00	2,035E +00	1,640E +00	1,733E +00	2,002E +00	1,679E +00	2,038E +00
Max	1,895E +00	2,136E +00	1,802E +00	2,125E +00	2,233E +00	2,172E +00	2,295E +00
Mean	1,780E +00	2,083E +00	1,742E +00	1,892E +00	2,146E +00	1,854E +00	2,199E +00
Sigma	1,181E -01	5,064E -02	8,903E -02	2,064E -01	1,254E -01	2,756E -01	1,405E -01

Test Step	192 hours
Serial #	
1 Ref.	1,824E +00
2	2,035E +00
3	1,961E +00
4	1,899E +00
Statistics	
Min	1,899E +00
Max	2,035E +00
Mean	1,965E +00
Sigma	6,809E -02

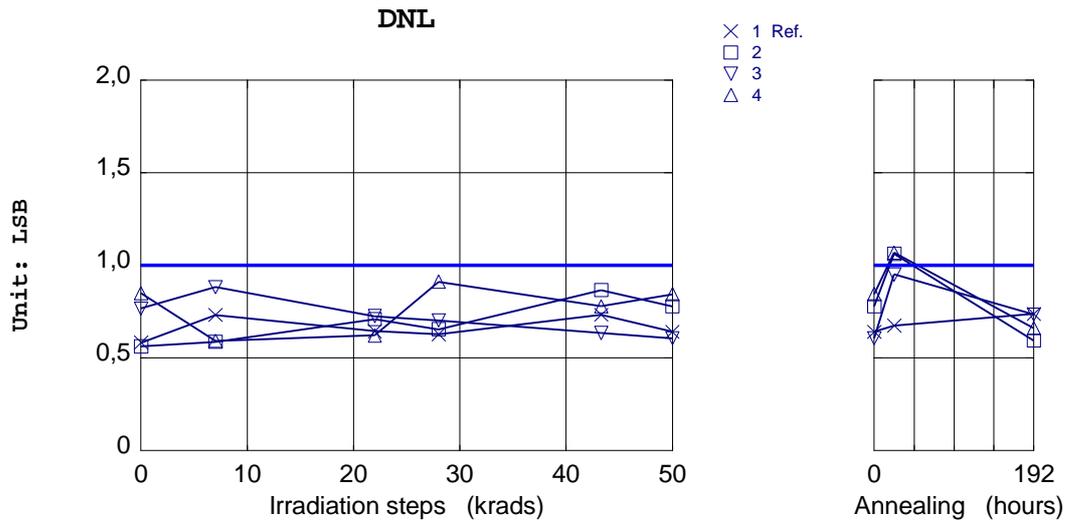


<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Differential Nonlinearity: DNL**  
**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V**  
Unit= LSB  
Spec limit max: 1  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	5,825E -01	7,309E -01	6,439E -01	6,278E -01	7,329E -01	6,411E -01	6,741E -01
2	5,621E -01	5,866E -01	7,095E -01	6,547E -01	8,662E -01	7,774E -01	1,062E +00
3	7,661E -01	8,823E -01	7,255E -01	7,024E -01	6,344E -01	6,060E -01	9,505E -01
4	8,496E -01	5,923E -01	6,215E -01	9,115E -01	7,788E -01	8,439E -01	1,068E +00
Statistics							
Min	5,621E -01	5,866E -01	6,215E -01	6,547E -01	6,344E -01	6,060E -01	9,505E -01
Max	8,496E -01	8,823E -01	7,255E -01	9,115E -01	8,662E -01	8,439E -01	1,068E +00
Mean	7,259E -01	6,870E -01	6,855E -01	7,562E -01	7,598E -01	7,424E -01	1,027E +00
Sigma	1,479E -01	1,691E -01	5,595E -02	1,366E -01	1,170E -01	1,228E -01	6,618E -02

Test Step	192 hours
Serial #	
1 Ref.	7,374E -01
2	5,934E -01
3	7,338E -01
4	6,605E -01
Statistics	
Min	5,934E -01
Max	7,338E -01
Mean	6,626E -01
Sigma	7,020E -02



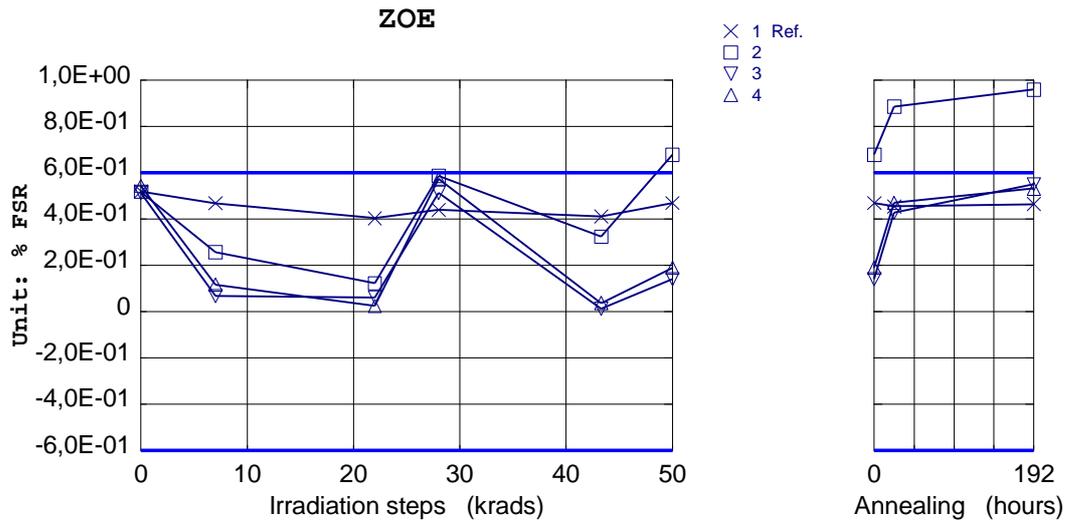
<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Zero Offset Error: ZOE**  
**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: 0V**

Unit= % FSR  
 Spec limit max: 0.6  
 Spec limit min: -0.6  
 Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	5,188E -01	4,671E -01	4,028E -01	4,395E -01	4,104E -01	4,686E -01	4,540E -01
2	5,174E -01	2,563E -01	1,221E -01	5,859E -01	3,235E -01	6,775E -01	8,850E -01
3	5,127E -01	6,714E -02	6,104E -02	5,127E -01	1,221E -02	1,404E -01	4,272E -01
4	5,432E -01	1,160E -01	2,441E -02	5,737E -01	3,662E -02	1,892E -01	4,700E -01
Statistics							
Min	5,127E -01	6,714E -02	2,441E -02	5,127E -01	1,221E -02	1,404E -01	4,272E -01
Max	5,432E -01	2,563E -01	1,221E -01	5,859E -01	3,235E -01	6,775E -01	8,850E -01
Mean	5,244E -01	1,465E -01	6,917E -02	5,575E -01	1,241E -01	3,357E -01	5,941E -01
Sigma	1,644E -02	9,823E -02	4,933E -02	3,924E -02	1,731E -01	2,970E -01	2,529E -01

Test Step	192 hours
Serial #	
1 Ref.	4,639E -01
2	9,583E -01
3	5,493E -01
4	5,310E -01
Statistics	
Min	5,310E -01
Max	9,583E -01
Mean	6,795E -01
Sigma	2,416E -01

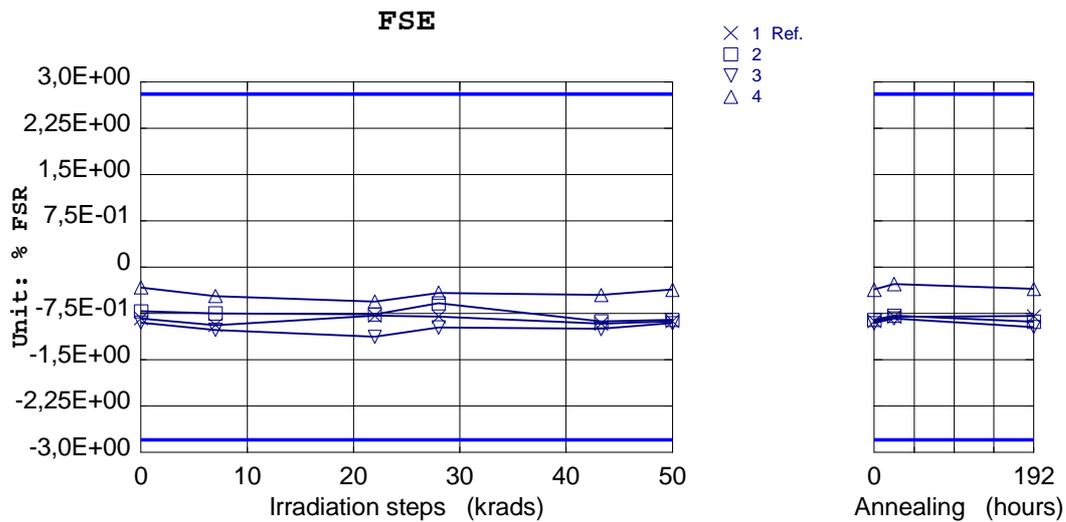


<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Full-Scale Error: FSE  
VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: 2V  
Unit= % FSR  
Spec limit max: 2.8  
Spec limit min: -2.8  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	-8,301E -01	-9,399E -01	-7,874E -01	-7,996E -01	-9,155E -01	-8,789E -01	-8,057E -01
2	-7,141E -01	-7,507E -01	-7,690E -01	-5,859E -01	-8,789E -01	-8,545E -01	-7,874E -01
3	-8,972E -01	-1,019E +00	-1,129E +00	-9,766E -01	-1,001E +00	-9,094E -01	-8,301E -01
4	-3,296E -01	-4,700E -01	-5,554E -01	-4,150E -01	-4,517E -01	-3,662E -01	-2,747E -01
Statistics							
Min	-8,972E -01	-1,019E +00	-1,129E +00	-9,766E -01	-1,001E +00	-9,094E -01	-8,301E -01
Max	-3,296E -01	-4,700E -01	-5,554E -01	-4,150E -01	-4,517E -01	-3,662E -01	-2,747E -01
Mean	-6,470E -01	-7,466E -01	-8,178E -01	-6,592E -01	-7,772E -01	-7,100E -01	-6,307E -01
Sigma	2,897E -01	2,745E -01	2,899E -01	2,878E -01	2,885E -01	2,990E -01	3,091E -01

Test Step	192 hours
Serial #	
1 Ref.	-7,935E -01
2	-8,850E -01
3	-9,705E -01
4	-3,540E -01
Statistics	
Min	-9,705E -01
Max	-3,540E -01
Mean	-7,365E -01
Sigma	3,340E -01



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Analog Supply Current: IA**

**VA=+5V; VD=+5V; VDI/O=+5V**

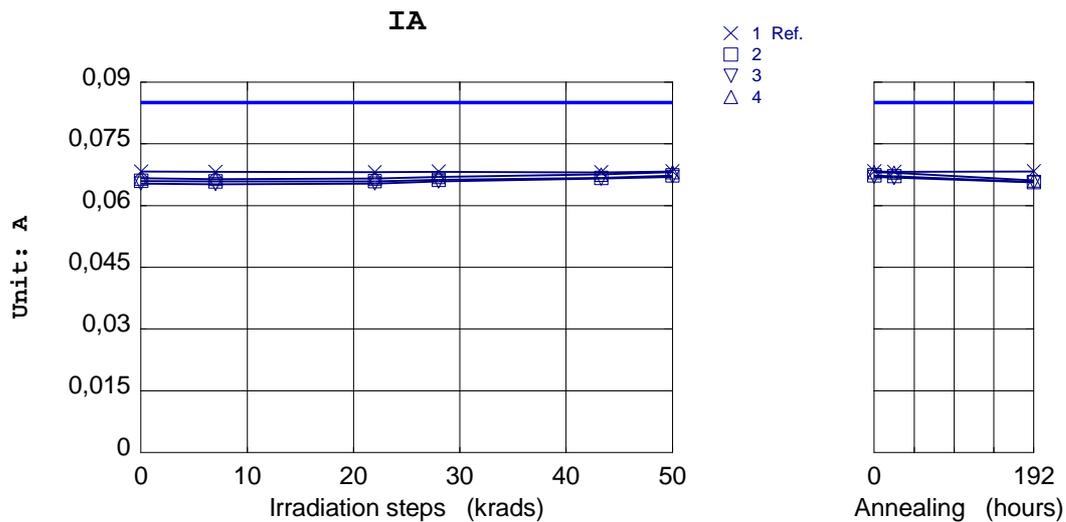
Unit= A

Spec limit max: 0.085

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	6,826E -02	6,821E -02	6,811E -02	6,823E -02	6,808E -02	6,830E -02	6,819E -02
2	6,598E -02	6,586E -02	6,591E -02	6,623E -02	6,671E -02	6,728E -02	6,712E -02
3	6,534E -02	6,519E -02	6,534E -02	6,585E -02	6,655E -02	6,696E -02	6,673E -02
4	6,659E -02	6,642E -02	6,653E -02	6,691E -02	6,752E -02	6,809E -02	6,797E -02
Statistics							
Min	6,534E -02	6,519E -02	6,534E -02	6,585E -02	6,655E -02	6,696E -02	6,673E -02
Max	6,659E -02	6,642E -02	6,653E -02	6,691E -02	6,752E -02	6,809E -02	6,797E -02
Mean	6,597E -02	6,582E -02	6,593E -02	6,633E -02	6,693E -02	6,744E -02	6,727E -02
Sigma	6,241E -04	6,130E -04	5,971E -04	5,392E -04	5,246E -04	5,830E -04	6,336E -04

Test Step	192 hours
Serial #	
1 Ref.	6,830E -02
2	6,570E -02
3	6,560E -02
4	6,608E -02
Statistics	
Min	6,560E -02
Max	6,608E -02
Mean	6,579E -02
Sigma	2,544E -04



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Digital Supply Current: ID**

VA=+5V; VD=+5V; VDI/O=+5V

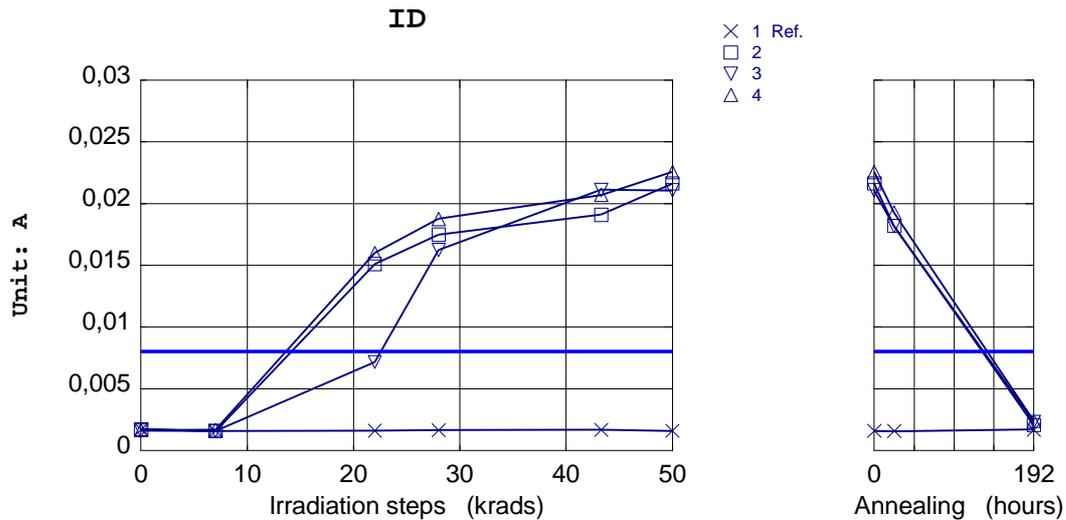
Unit= A

Spec limit max: 0.008

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,702E -03	1,589E -03	1,619E -03	1,651E -03	1,685E -03	1,586E -03	1,570E -03
2	1,728E -03	1,558E -03	1,510E -02	1,748E -02	1,909E -02	2,162E -02	1,819E -02
3	1,619E -03	1,587E -03	7,166E -03	1,625E -02	2,111E -02	2,106E -02	1,817E -02
4	1,661E -03	1,685E -03	1,598E -02	1,876E -02	2,070E -02	2,255E -02	1,926E -02
Statistics							
Min	1,619E -03	1,558E -03	7,166E -03	1,625E -02	1,909E -02	2,106E -02	1,817E -02
Max	1,728E -03	1,685E -03	1,598E -02	1,876E -02	2,111E -02	2,255E -02	1,926E -02
Mean	1,669E -03	1,610E -03	1,275E -02	1,749E -02	2,030E -02	2,174E -02	1,854E -02
Sigma	5,498E -05	6,655E -05	4,855E -03	1,255E -03	1,069E -03	7,557E -04	6,225E -04

Test Step	192 hours
Serial #	
1 Ref.	1,698E -03
2	2,068E -03
3	2,332E -03
4	2,400E -03
Statistics	
Min	2,068E -03
Max	2,400E -03
Mean	2,267E -03
Sigma	1,754E -04



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Digital Output Bus Supply Current: IDI/O**

**VA=+5V; VD=+5V; VDI/O=+5V**

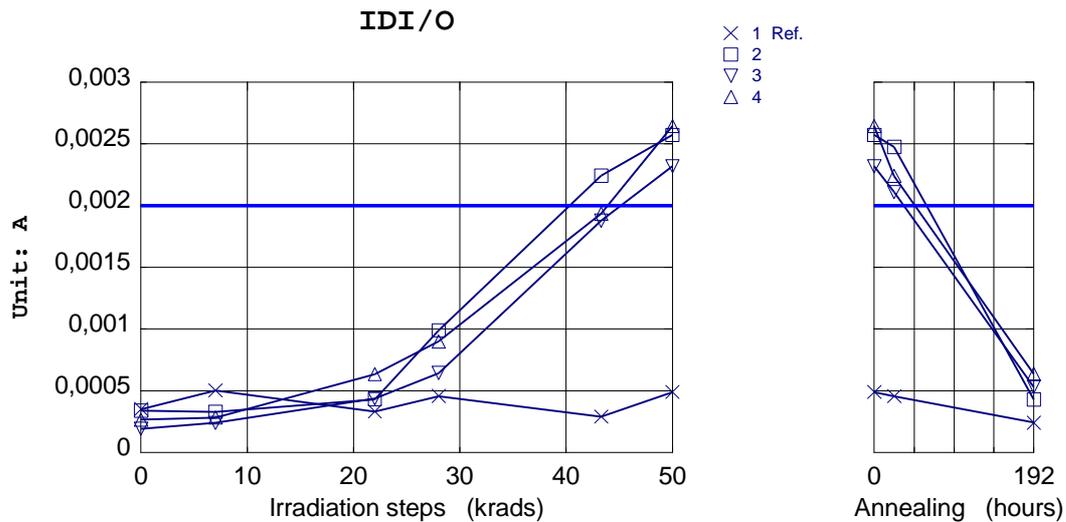
Unit= A

Spec limit max: 0.002

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	3,518E -04	5,027E -04	3,327E -04	4,577E -04	2,912E -04	4,898E -04	4,569E -04
2	3,396E -04	3,288E -04	4,314E -04	9,879E -04	2,241E -03	2,572E -03	2,474E -03
3	1,923E -04	2,406E -04	4,372E -04	6,430E -04	1,877E -03	2,318E -03	2,109E -03
4	2,666E -04	2,833E -04	6,350E -04	8,992E -04	1,933E -03	2,644E -03	2,239E -03
Statistics							
Min	1,923E -04	2,406E -04	4,314E -04	6,430E -04	1,877E -03	2,318E -03	2,109E -03
Max	3,396E -04	3,288E -04	6,350E -04	9,879E -04	2,241E -03	2,644E -03	2,474E -03
Mean	2,661E -04	2,842E -04	5,012E -04	8,433E -04	2,017E -03	2,511E -03	2,274E -03
Sigma	7,365E -05	4,415E -05	1,159E -04	1,791E -04	1,960E -04	1,713E -04	1,850E -04

Test Step	192 hours
Serial #	
1 Ref.	2,416E -04
2	4,292E -04
3	5,320E -04
4	6,362E -04
Statistics	
Min	4,292E -04
Max	6,362E -04
Mean	5,325E -04
Sigma	1,035E -04



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Input Voltage: Vih**

VA=+5V; VD=+5V; VDI/O=+5V

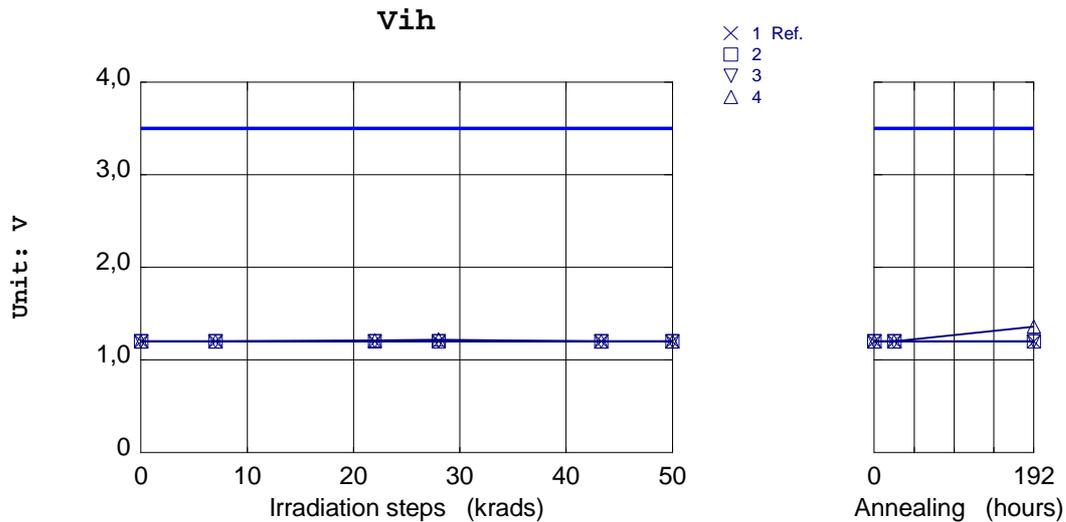
Unit= V

Spec limit max: 3.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,200E +00						
2	1,200E +00						
3	1,200E +00						
4	1,200E +00	1,200E +00	1,210E +00	1,220E +00	1,200E +00	1,200E +00	1,200E +00
Statistics							
Min	1,200E +00						
Max	1,200E +00	1,200E +00	1,210E +00	1,220E +00	1,200E +00	1,200E +00	1,200E +00
Mean	1,200E +00	1,200E +00	1,203E +00	1,207E +00	1,200E +00	1,200E +00	1,200E +00
Sigma	0,000E +00	0,000E +00	5,773E -03	1,155E -02	0,000E +00	0,000E +00	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	1,200E +00
2	1,200E +00
3	1,200E +00
4	1,360E +00
Statistics	
Min	1,200E +00
Max	1,360E +00
Mean	1,253E +00
Sigma	9,238E -02



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Input Voltage: Vil

VA=+5V; VD=+5V; VDI/O=+5V

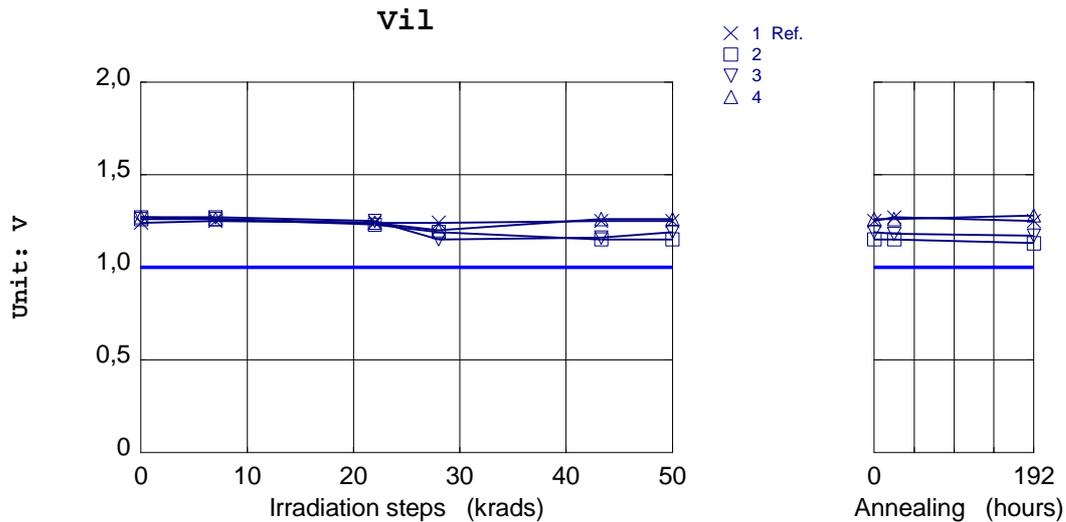
Unit= V

Spec limit min: 1

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,240E +00	1,250E +00	1,240E +00	1,240E +00	1,250E +00	1,250E +00	1,270E +00
2	1,260E +00	1,260E +00	1,230E +00	1,190E +00	1,150E +00	1,150E +00	1,150E +00
3	1,270E +00	1,270E +00	1,250E +00	1,150E +00	1,160E +00	1,190E +00	1,180E +00
4	1,270E +00	1,260E +00	1,240E +00	1,200E +00	1,260E +00	1,260E +00	1,260E +00
Statistics							
Min	1,260E +00	1,260E +00	1,230E +00	1,150E +00	1,150E +00	1,150E +00	1,150E +00
Max	1,270E +00	1,270E +00	1,250E +00	1,200E +00	1,260E +00	1,260E +00	1,260E +00
Mean	1,267E +00	1,263E +00	1,240E +00	1,180E +00	1,190E +00	1,200E +00	1,197E +00
Sigma	5,773E -03	5,773E -03	1,000E -02	2,646E -02	6,083E -02	5,568E -02	5,686E -02

Test Step	192 hours
Serial #	
1 Ref.	1,250E +00
2	1,130E +00
3	1,170E +00
4	1,280E +00
Statistics	
Min	1,130E +00
Max	1,280E +00
Mean	1,193E +00
Sigma	7,767E -02



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 38: VOH13**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

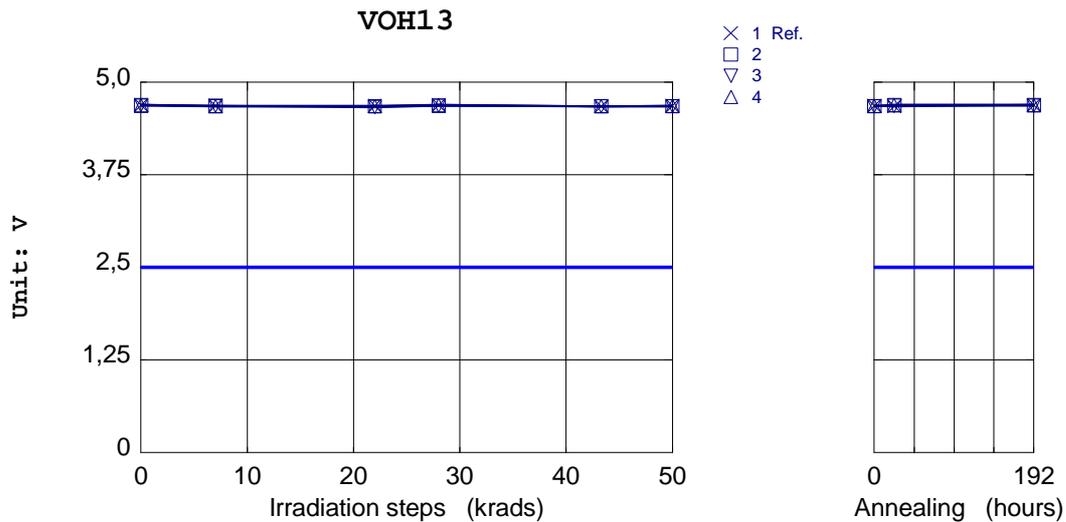
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,680E +00	4,680E +00	4,690E +00	4,670E +00	4,680E +00	4,670E +00
2	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,690E +00
3	4,690E +00	4,680E +00	4,660E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
4	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,670E +00	4,680E +00	4,690E +00
Statistics							
Min	4,680E +00	4,670E +00	4,660E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
Max	4,690E +00	4,680E +00	4,670E +00	4,690E +00	4,670E +00	4,680E +00	4,690E +00
Mean	4,687E +00	4,673E +00	4,667E +00	4,683E +00	4,670E +00	4,673E +00	4,687E +00
Sigma	5,774E -03	5,773E -03	5,774E -03	5,774E -03	2,634E -09	5,773E -03	5,774E -03

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,680E +00
4	4,690E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,687E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 37: VOH12**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

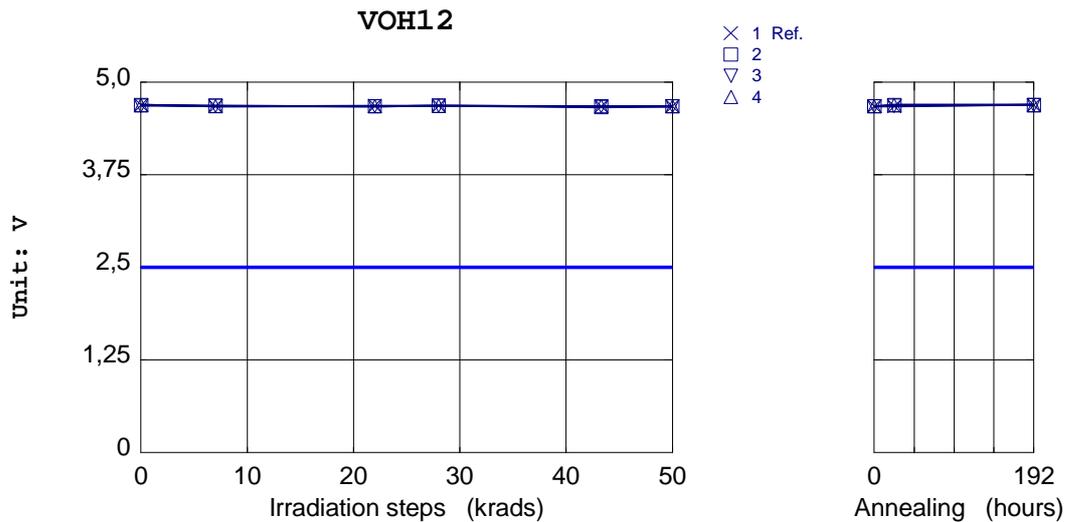
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00
2	4,690E +00	4,680E +00	4,670E +00	4,680E +00	4,660E +00	4,670E +00	4,690E +00
3	4,680E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
4	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,690E +00
Statistics							
Min	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,660E +00	4,670E +00	4,680E +00
Max	4,690E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,690E +00
Mean	4,687E +00	4,677E +00	4,670E +00	4,680E +00	4,667E +00	4,670E +00	4,687E +00
Sigma	5,774E -03	5,773E -03	2,634E -09	0,000E +00	5,774E -03	2,634E -09	5,774E -03

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 36: VOH11**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

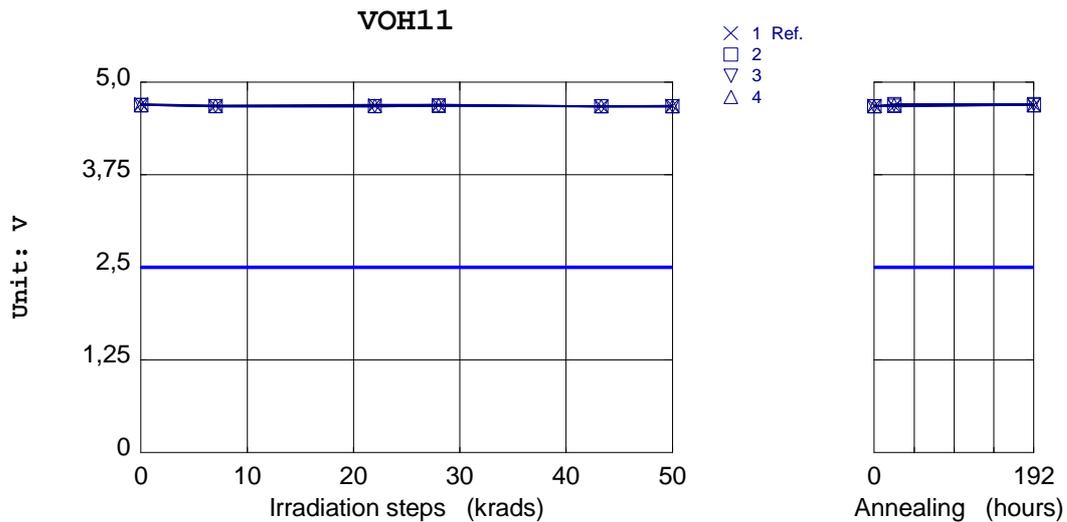
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,700E +00	4,680E +00	4,690E +00	4,690E +00	4,670E +00	4,680E +00	4,670E +00
2	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
3	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,700E +00
4	4,690E +00	4,680E +00	4,680E +00	4,690E +00	4,670E +00	4,670E +00	4,690E +00
Statistics							
Min	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
Max	4,690E +00	4,680E +00	4,680E +00	4,690E +00	4,670E +00	4,670E +00	4,700E +00
Mean	4,690E +00	4,673E +00	4,673E +00	4,683E +00	4,670E +00	4,670E +00	4,690E +00
Sigma	0,000E +00	5,773E -03	5,773E -03	5,774E -03	2,634E -09	2,634E -09	1,000E -02

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,700E +00
4	4,690E +00
Statistics	
Min	4,690E +00
Max	4,700E +00
Mean	4,693E +00
Sigma	5,773E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 35: VOH10**

VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA

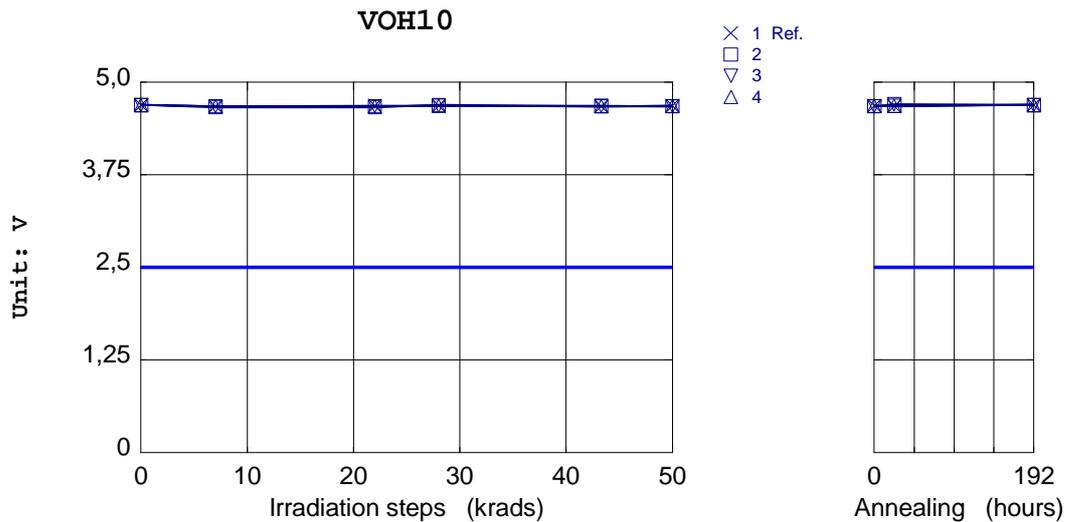
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00
2	4,690E +00	4,660E +00	4,660E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
3	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00	4,700E +00
4	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00
Statistics							
Min	4,690E +00	4,660E +00	4,660E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
Max	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,680E +00	4,680E +00	4,700E +00
Mean	4,690E +00	4,667E +00	4,667E +00	4,683E +00	4,673E +00	4,673E +00	4,687E +00
Sigma	0,000E +00	5,774E -03	5,774E -03	5,774E -03	5,773E -03	5,773E -03	1,155E -02

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 32: VOH9**

VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA

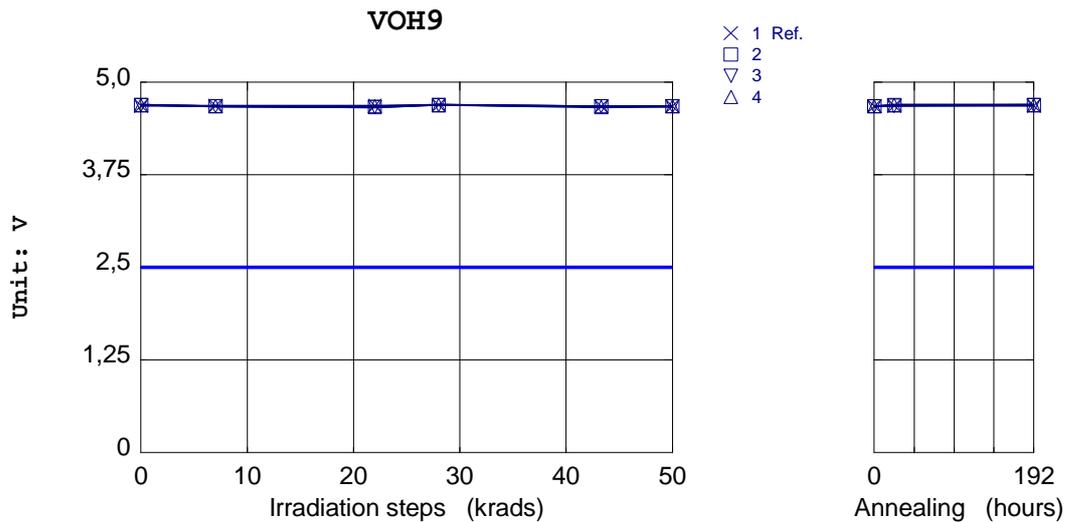
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,680E +00	4,680E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
2	4,690E +00	4,670E +00	4,660E +00	4,690E +00	4,670E +00	4,670E +00	4,690E +00
3	4,690E +00	4,670E +00	4,660E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
4	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,660E +00	4,670E +00	4,690E +00
Statistics							
Min	4,690E +00	4,670E +00	4,660E +00	4,690E +00	4,660E +00	4,670E +00	4,680E +00
Max	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,690E +00
Mean	4,690E +00	4,670E +00	4,663E +00	4,690E +00	4,667E +00	4,670E +00	4,687E +00
Sigma	0,000E +00	2,634E -09	5,774E -03	0,000E +00	5,774E -03	2,634E -09	5,774E -03

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
2	4,690E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 31: VOH8**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

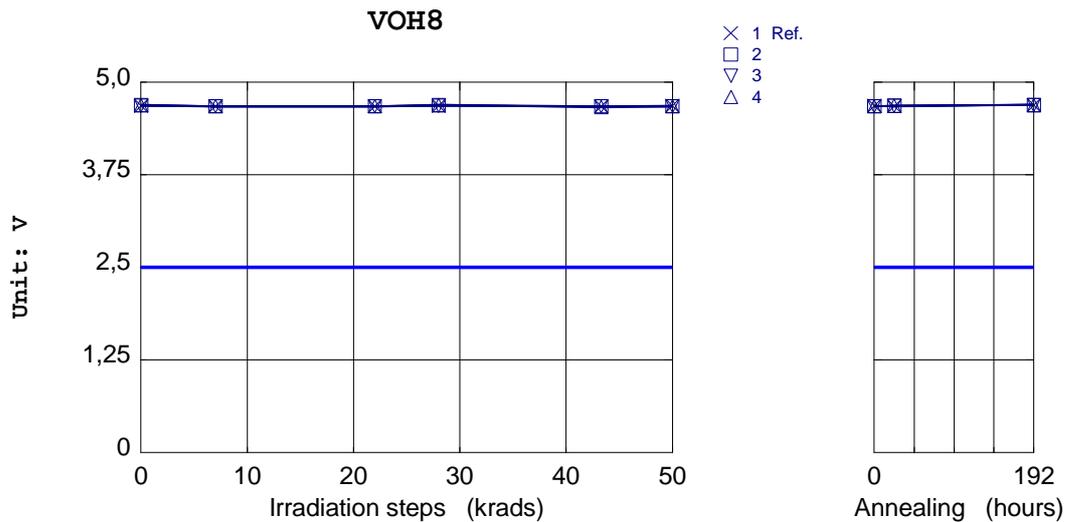
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00
2	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
3	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
4	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,660E +00	4,670E +00	4,680E +00
Statistics							
Min	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,660E +00	4,670E +00	4,680E +00
Max	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
Mean	4,687E +00	4,670E +00	4,670E +00	4,687E +00	4,667E +00	4,670E +00	4,680E +00
Sigma	5,774E -03	2,634E -09	2,634E -09	5,774E -03	5,774E -03	2,634E -09	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 30: VOH7**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

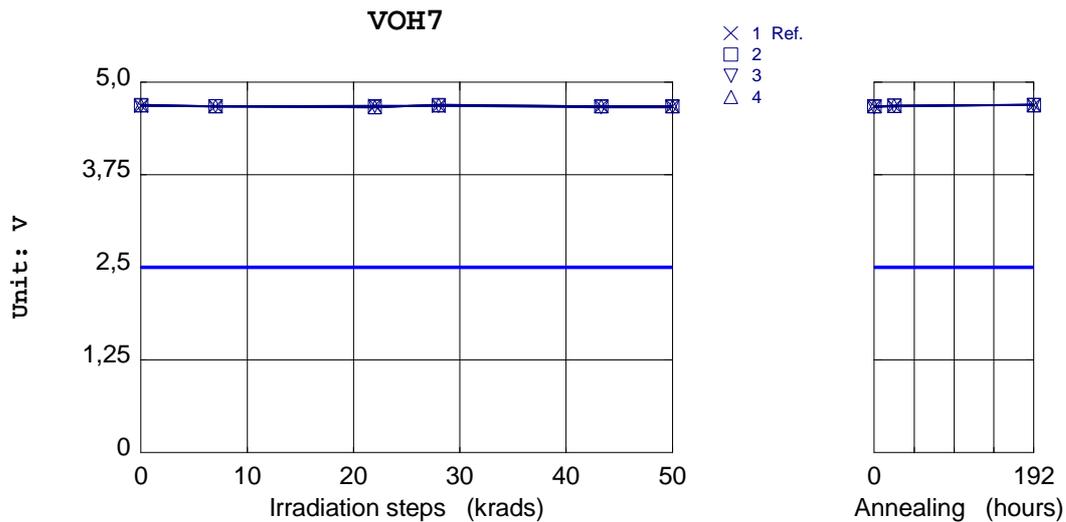
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00
2	4,690E +00	4,670E +00	4,660E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
3	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
4	4,690E +00	4,670E +00	4,660E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
Statistics							
Min	4,680E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
Max	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
Mean	4,687E +00	4,670E +00	4,663E +00	4,687E +00	4,667E +00	4,667E +00	4,680E +00
Sigma	5,774E -03	2,634E -09	5,774E -03	5,774E -03	5,774E -03	5,774E -03	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 29: VOH6**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

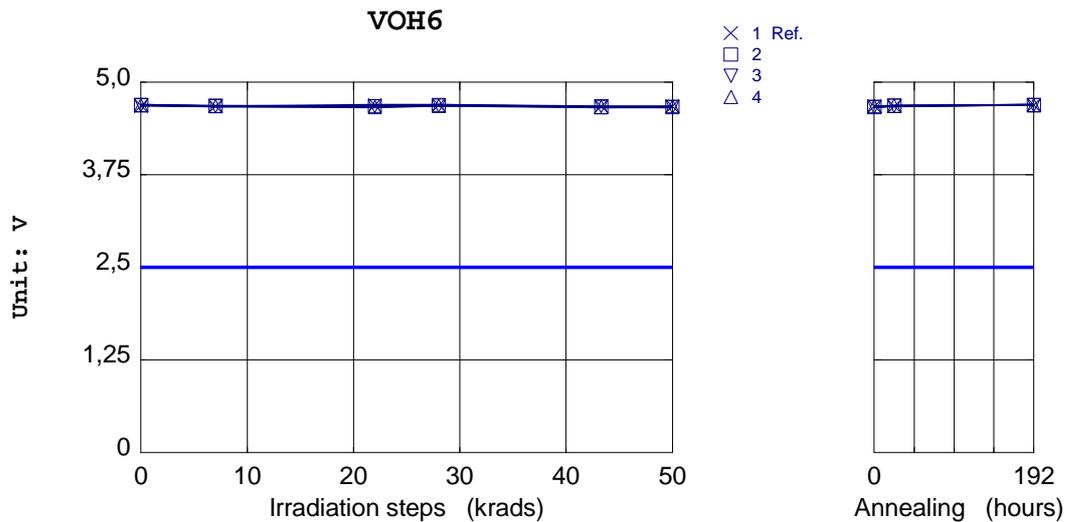
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,690E +00	4,690E +00	4,670E +00	4,670E +00	4,670E +00
2	4,690E +00	4,680E +00	4,670E +00	4,690E +00	4,660E +00	4,660E +00	4,680E +00
3	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,660E +00	4,680E +00
4	4,690E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,670E +00	4,680E +00
Statistics							
Min	4,690E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
Max	4,690E +00	4,680E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
Mean	4,690E +00	4,673E +00	4,667E +00	4,683E +00	4,663E +00	4,663E +00	4,680E +00
Sigma	0,000E +00	5,773E -03	5,774E -03	5,774E -03	5,774E -03	5,774E -03	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 28: VOH5**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

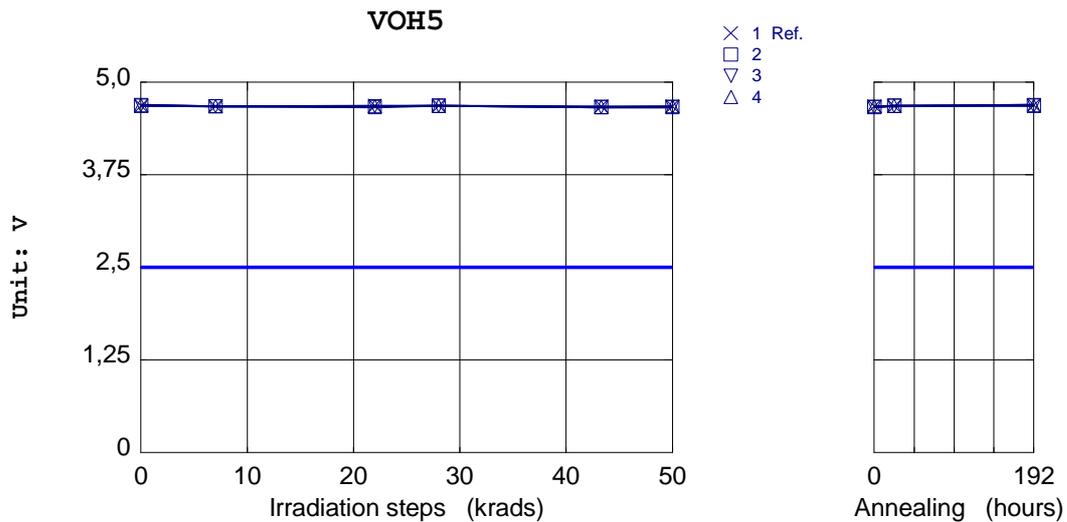
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00
2	4,680E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
3	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
4	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,660E +00	4,670E +00	4,680E +00
Statistics							
Min	4,680E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
Max	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,660E +00	4,670E +00	4,680E +00
Mean	4,687E +00	4,670E +00	4,667E +00	4,680E +00	4,660E +00	4,663E +00	4,680E +00
Sigma	5,774E -03	2,634E -09	5,774E -03	0,000E +00	2,634E -09	5,774E -03	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,680E +00
4	4,680E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,683E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 27: VOH4**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

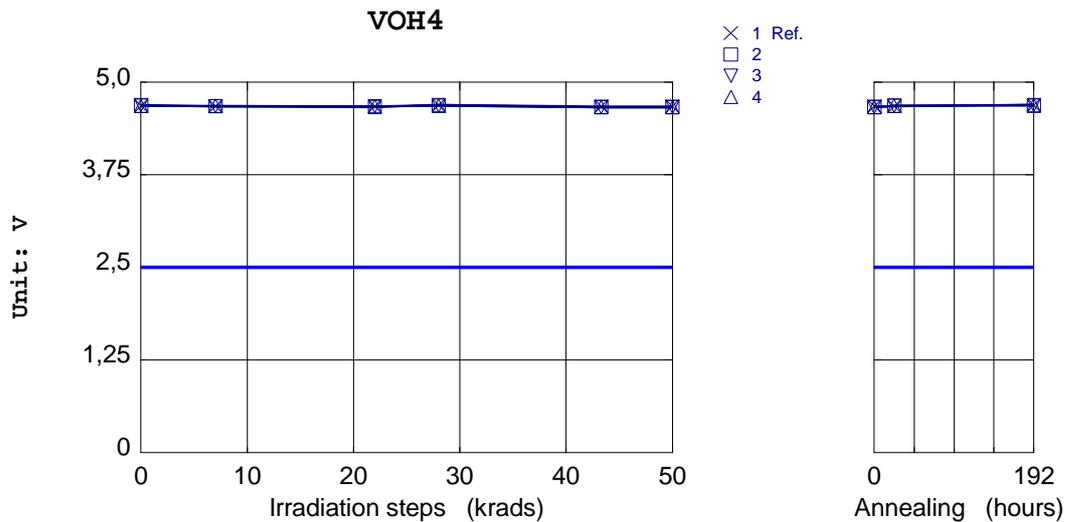
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,670E +00
2	4,680E +00	4,670E +00	4,660E +00	4,690E +00	4,660E +00	4,660E +00	4,680E +00
3	4,690E +00	4,670E +00	4,670E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
4	4,680E +00	4,680E +00	4,670E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
Statistics							
Min	4,680E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
Max	4,690E +00	4,680E +00	4,670E +00	4,690E +00	4,660E +00	4,660E +00	4,680E +00
Mean	4,683E +00	4,673E +00	4,667E +00	4,683E +00	4,660E +00	4,660E +00	4,680E +00
Sigma	5,774E -03	5,773E -03	5,774E -03	5,774E -03	2,634E -09	2,634E -09	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,680E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,687E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 26: VOH3**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

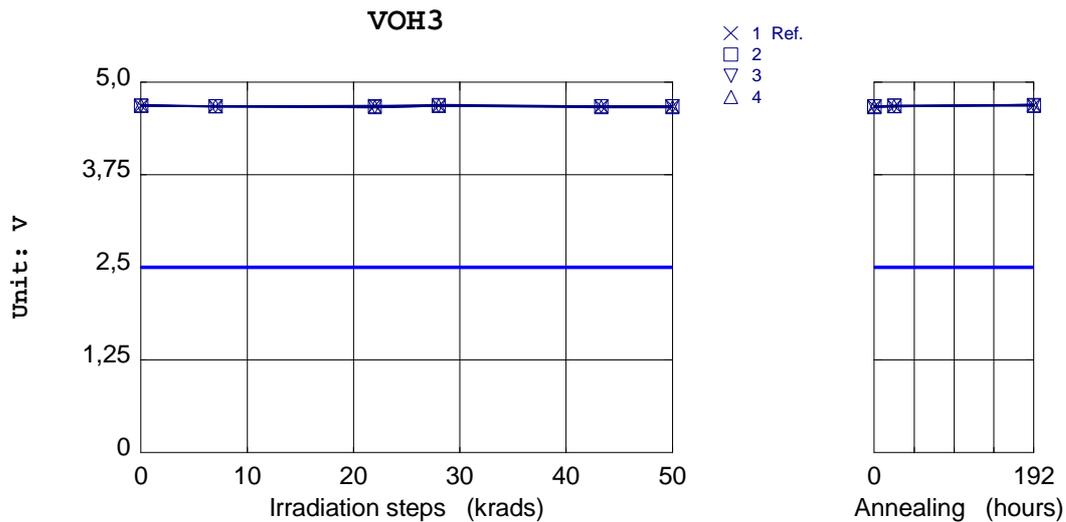
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00
2	4,680E +00	4,670E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
3	4,680E +00	4,670E +00	4,660E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
4	4,690E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,670E +00
Statistics							
Min	4,680E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,670E +00
Max	4,690E +00	4,670E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,680E +00
Mean	4,683E +00	4,670E +00	4,663E +00	4,683E +00	4,667E +00	4,667E +00	4,677E +00
Sigma	5,774E -03	2,634E -09	5,774E -03	5,774E -03	5,774E -03	5,774E -03	5,773E -03

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,680E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,687E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 25: VOH2**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

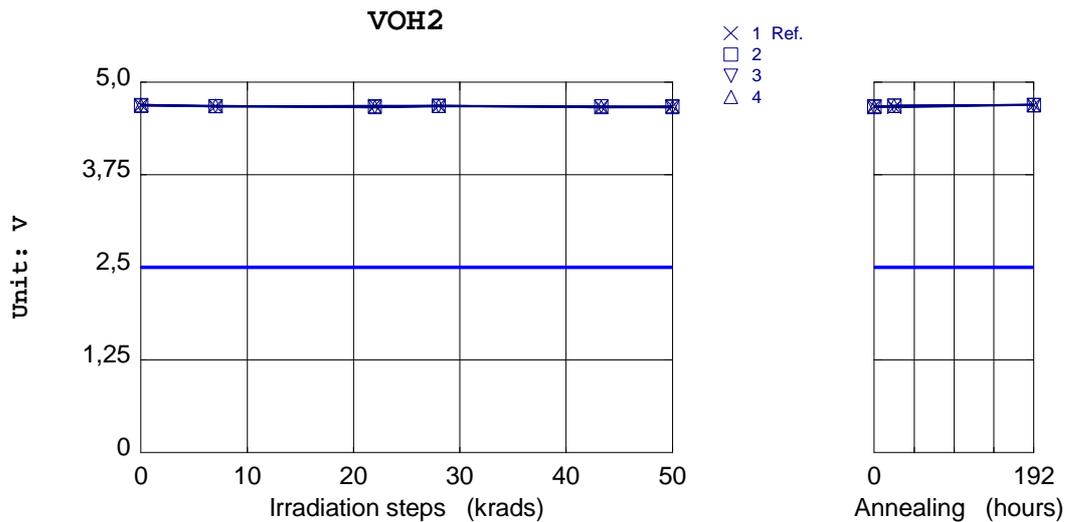
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,670E +00	4,680E +00	4,680E +00	4,660E +00	4,670E +00	4,660E +00
2	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
3	4,690E +00	4,670E +00	4,660E +00	4,670E +00	4,670E +00	4,660E +00	4,680E +00
4	4,690E +00	4,680E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
Statistics							
Min	4,680E +00	4,670E +00	4,660E +00	4,670E +00	4,660E +00	4,660E +00	4,680E +00
Max	4,690E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00
Mean	4,687E +00	4,673E +00	4,663E +00	4,677E +00	4,667E +00	4,663E +00	4,680E +00
Sigma	5,774E -03	5,773E -03	5,774E -03	5,773E -03	5,774E -03	5,774E -03	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,690E +00
3	4,690E +00
4	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 24: VOH1**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

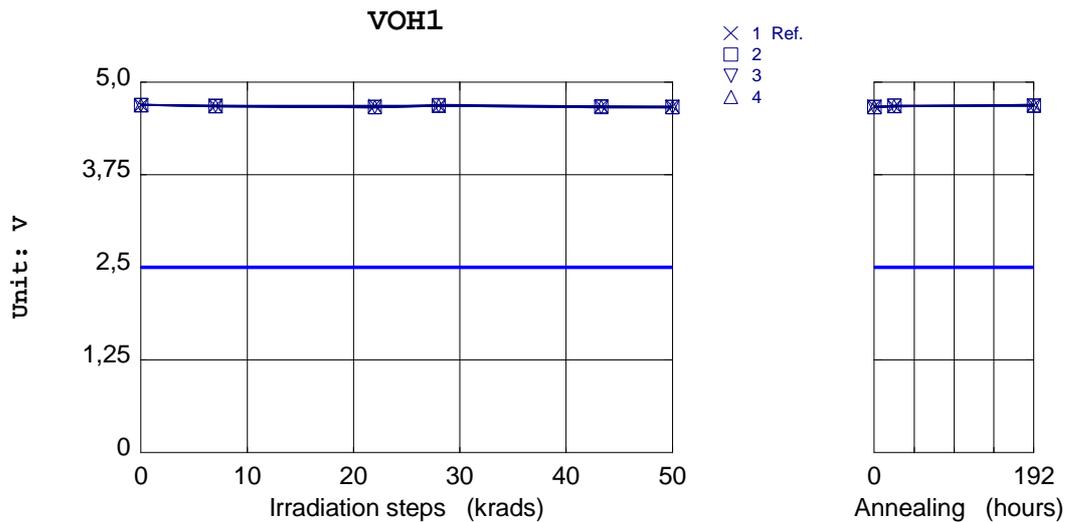
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,680E +00	4,680E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00
2	4,690E +00	4,670E +00	4,660E +00	4,690E +00	4,670E +00	4,660E +00	4,680E +00
3	4,690E +00	4,680E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
4	4,690E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,670E +00
Statistics							
Min	4,690E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,670E +00
Max	4,690E +00	4,680E +00	4,660E +00	4,690E +00	4,670E +00	4,660E +00	4,680E +00
Mean	4,690E +00	4,673E +00	4,660E +00	4,683E +00	4,663E +00	4,660E +00	4,677E +00
Sigma	0,000E +00	5,773E -03	2,634E -09	5,774E -03	5,774E -03	2,634E -09	5,773E -03

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
2	4,680E +00
3	4,680E +00
4	4,690E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,683E +00
Sigma	5,774E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 23: VOHO**

VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA

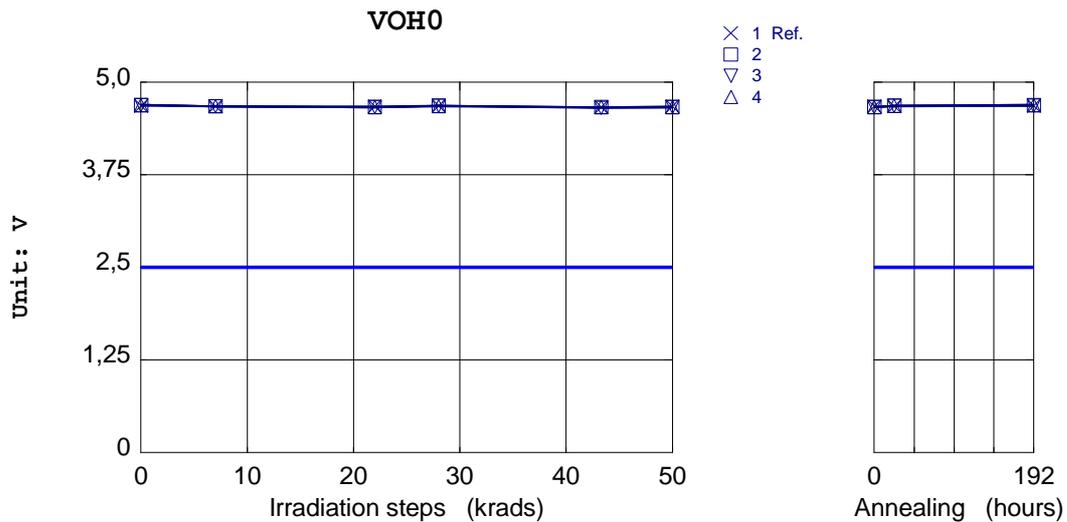
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,660E +00	4,670E +00	4,670E +00
2	4,690E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
3	4,690E +00	4,670E +00	4,660E +00	4,680E +00	4,650E +00	4,660E +00	4,680E +00
4	4,690E +00	4,670E +00	4,660E +00	4,670E +00	4,660E +00	4,660E +00	4,680E +00
Statistics							
Min	4,690E +00	4,670E +00	4,660E +00	4,670E +00	4,650E +00	4,660E +00	4,680E +00
Max	4,690E +00	4,670E +00	4,660E +00	4,680E +00	4,660E +00	4,660E +00	4,680E +00
Mean	4,690E +00	4,670E +00	4,660E +00	4,677E +00	4,657E +00	4,660E +00	4,680E +00
Sigma	0,000E +00	2,634E -09	2,634E -09	5,773E -03	5,773E -03	2,634E -09	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
2	4,690E +00
3	4,680E +00
4	4,690E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,687E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Output Voltage Pin 38: VOL13  
VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

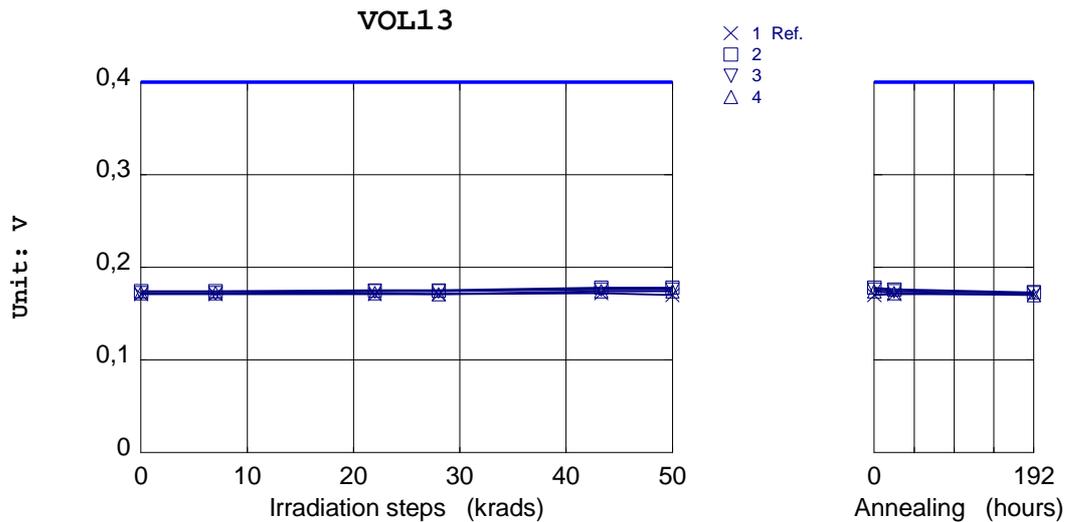
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,710E -01	1,710E -01	1,710E -01	1,710E -01	1,720E -01	1,700E -01	1,710E -01
2	1,740E -01	1,740E -01	1,750E -01	1,750E -01	1,780E -01	1,780E -01	1,760E -01
3	1,720E -01	1,720E -01	1,740E -01	1,740E -01	1,760E -01	1,760E -01	1,740E -01
4	1,720E -01	1,720E -01	1,720E -01	1,710E -01	1,740E -01	1,740E -01	1,720E -01
Statistics							
Min	1,720E -01	1,720E -01	1,720E -01	1,710E -01	1,740E -01	1,740E -01	1,720E -01
Max	1,740E -01	1,740E -01	1,750E -01	1,750E -01	1,780E -01	1,780E -01	1,760E -01
Mean	1,727E -01	1,727E -01	1,737E -01	1,733E -01	1,760E -01	1,760E -01	1,740E -01
Sigma	1,155E -03	1,155E -03	1,528E -03	2,082E -03	2,000E -03	2,000E -03	2,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,710E -01
2	1,730E -01
3	1,720E -01
4	1,700E -01
Statistics	
Min	1,700E -01
Max	1,730E -01
Mean	1,717E -01
Sigma	1,528E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 37: VOL12**  
**VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA**

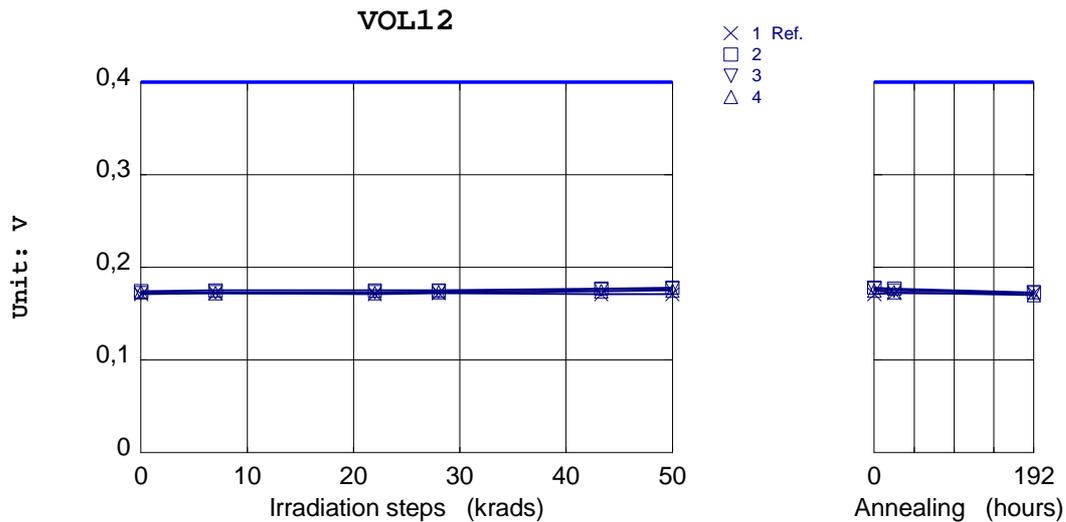
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,710E -01	1,720E -01	1,710E -01	1,720E -01	1,710E -01	1,710E -01	1,720E -01
2	1,740E -01	1,750E -01	1,750E -01	1,750E -01	1,770E -01	1,780E -01	1,770E -01
3	1,720E -01	1,730E -01	1,730E -01	1,740E -01	1,760E -01	1,770E -01	1,750E -01
4	1,730E -01	1,720E -01	1,720E -01	1,730E -01	1,740E -01	1,750E -01	1,730E -01
Statistics							
Min	1,720E -01	1,720E -01	1,720E -01	1,730E -01	1,740E -01	1,750E -01	1,730E -01
Max	1,740E -01	1,750E -01	1,750E -01	1,750E -01	1,770E -01	1,780E -01	1,770E -01
Mean	1,730E -01	1,733E -01	1,733E -01	1,740E -01	1,757E -01	1,767E -01	1,750E -01
Sigma	1,000E -03	1,528E -03	1,528E -03	1,000E -03	1,528E -03	1,528E -03	2,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,720E -01
2	1,730E -01
3	1,720E -01
4	1,700E -01
Statistics	
Min	1,700E -01
Max	1,730E -01
Mean	1,717E -01
Sigma	1,528E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 36: VOL11**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

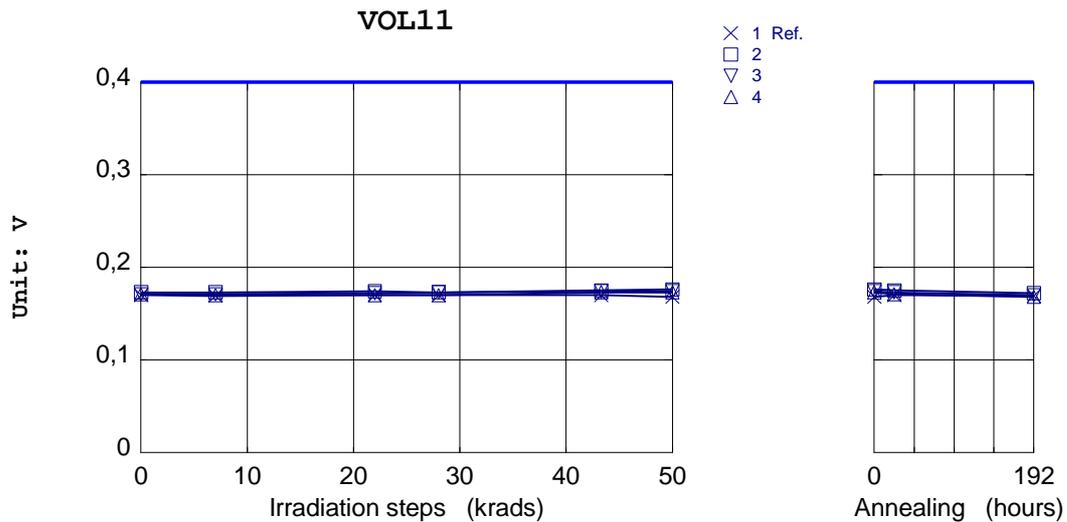
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,700E -01	1,690E -01	1,700E -01	1,700E -01	1,700E -01	1,680E -01	1,700E -01
2	1,730E -01	1,730E -01	1,740E -01	1,730E -01	1,750E -01	1,760E -01	1,750E -01
3	1,710E -01	1,710E -01	1,720E -01	1,730E -01	1,740E -01	1,740E -01	1,730E -01
4	1,710E -01	1,700E -01	1,700E -01	1,700E -01	1,730E -01	1,730E -01	1,710E -01
Statistics							
Min	1,710E -01	1,700E -01	1,700E -01	1,700E -01	1,730E -01	1,730E -01	1,710E -01
Max	1,730E -01	1,730E -01	1,740E -01	1,730E -01	1,750E -01	1,760E -01	1,750E -01
Mean	1,717E -01	1,713E -01	1,720E -01	1,720E -01	1,740E -01	1,743E -01	1,730E -01
Sigma	1,155E -03	1,528E -03	2,000E -03	1,732E -03	1,000E -03	1,528E -03	2,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,690E -01
2	1,720E -01
3	1,700E -01
4	1,680E -01
Statistics	
Min	1,680E -01
Max	1,720E -01
Mean	1,700E -01
Sigma	2,000E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Output Voltage Pin 35: VOL10  
VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

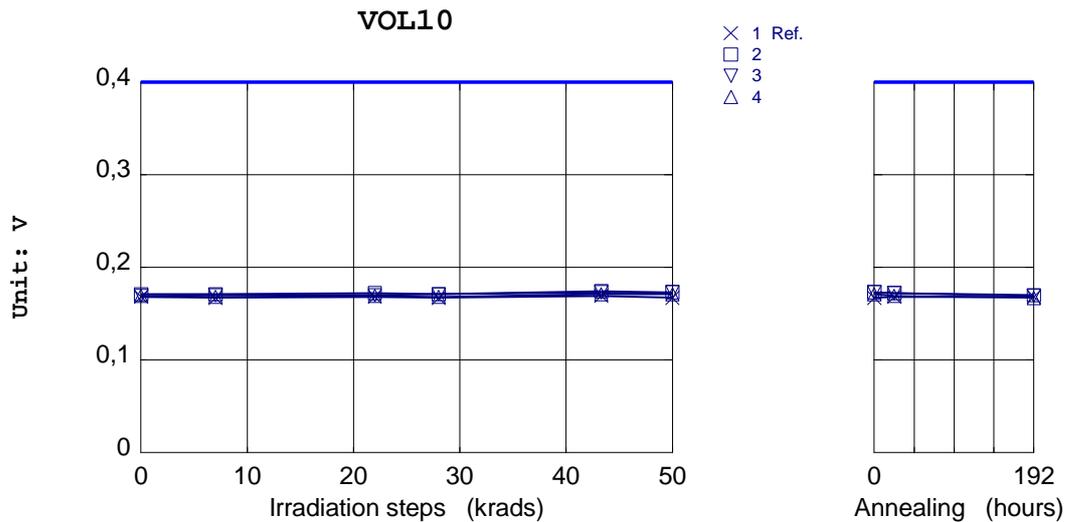
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,680E -01	1,670E -01	1,680E -01	1,670E -01	1,690E -01	1,670E -01	1,680E -01
2	1,710E -01	1,710E -01	1,720E -01	1,710E -01	1,740E -01	1,730E -01	1,720E -01
3	1,690E -01	1,700E -01	1,700E -01	1,710E -01	1,730E -01	1,730E -01	1,720E -01
4	1,690E -01	1,680E -01	1,690E -01	1,680E -01	1,710E -01	1,710E -01	1,690E -01
Statistics							
Min	1,690E -01	1,680E -01	1,690E -01	1,680E -01	1,710E -01	1,710E -01	1,690E -01
Max	1,710E -01	1,710E -01	1,720E -01	1,710E -01	1,740E -01	1,730E -01	1,720E -01
Mean	1,697E -01	1,697E -01	1,703E -01	1,700E -01	1,727E -01	1,723E -01	1,710E -01
Sigma	1,155E -03	1,528E -03	1,528E -03	1,732E -03	1,528E -03	1,155E -03	1,732E -03

Test Step	192 hours
Serial #	
1 Ref.	1,680E -01
2	1,700E -01
3	1,690E -01
4	1,670E -01
Statistics	
Min	1,670E -01
Max	1,700E -01
Mean	1,687E -01
Sigma	1,528E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Output Voltage Pin 32: VOL9  
VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

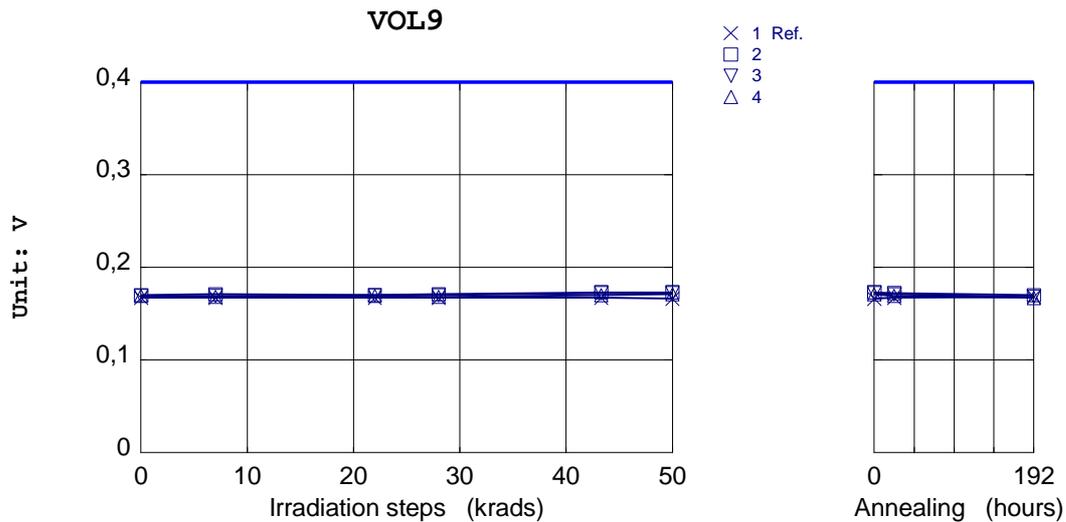
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,670E -01	1,660E -01	1,670E -01				
2	1,700E -01	1,710E -01	1,700E -01	1,710E -01	1,730E -01	1,730E -01	1,720E -01
3	1,690E -01	1,690E -01	1,700E -01	1,700E -01	1,720E -01	1,720E -01	1,710E -01
4	1,690E -01	1,680E -01	1,690E -01	1,680E -01	1,700E -01	1,710E -01	1,690E -01
Statistics							
Min	1,690E -01	1,680E -01	1,690E -01	1,680E -01	1,700E -01	1,710E -01	1,690E -01
Max	1,700E -01	1,710E -01	1,700E -01	1,710E -01	1,730E -01	1,730E -01	1,720E -01
Mean	1,693E -01	1,693E -01	1,697E -01	1,697E -01	1,717E -01	1,720E -01	1,707E -01
Sigma	5,774E -04	1,528E -03	5,774E -04	1,528E -03	1,528E -03	1,000E -03	1,528E -03

Test Step	192 hours
Serial #	
1 Ref.	1,680E -01
2	1,700E -01
3	1,680E -01
4	1,670E -01
Statistics	
Min	1,670E -01
Max	1,700E -01
Mean	1,683E -01
Sigma	1,528E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 31: VOL8**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

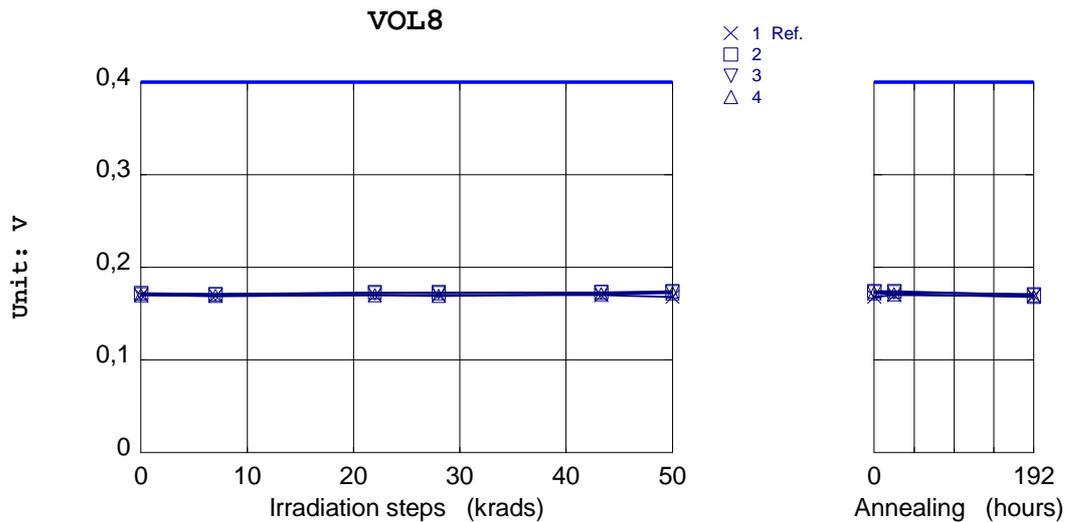
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,700E -01	1,690E -01	1,700E -01	1,700E -01	1,700E -01	1,680E -01	1,700E -01
2	1,720E -01	1,710E -01	1,730E -01	1,720E -01	1,730E -01	1,740E -01	1,740E -01
3	1,710E -01	1,710E -01	1,720E -01	1,730E -01	1,730E -01	1,730E -01	1,730E -01
4	1,700E -01	1,690E -01	1,700E -01	1,690E -01	1,710E -01	1,720E -01	1,710E -01
Statistics							
Min	1,700E -01	1,690E -01	1,700E -01	1,690E -01	1,710E -01	1,720E -01	1,710E -01
Max	1,720E -01	1,710E -01	1,730E -01	1,730E -01	1,730E -01	1,740E -01	1,740E -01
Mean	1,710E -01	1,703E -01	1,717E -01	1,713E -01	1,723E -01	1,730E -01	1,727E -01
Sigma	1,000E -03	1,155E -03	1,528E -03	2,082E -03	1,155E -03	1,000E -03	1,528E -03

Test Step	192 hours
Serial #	
1 Ref.	1,690E -01
2	1,700E -01
3	1,710E -01
4	1,680E -01
Statistics	
Min	1,680E -01
Max	1,710E -01
Mean	1,697E -01
Sigma	1,528E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 30: VOL7**

**VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA**

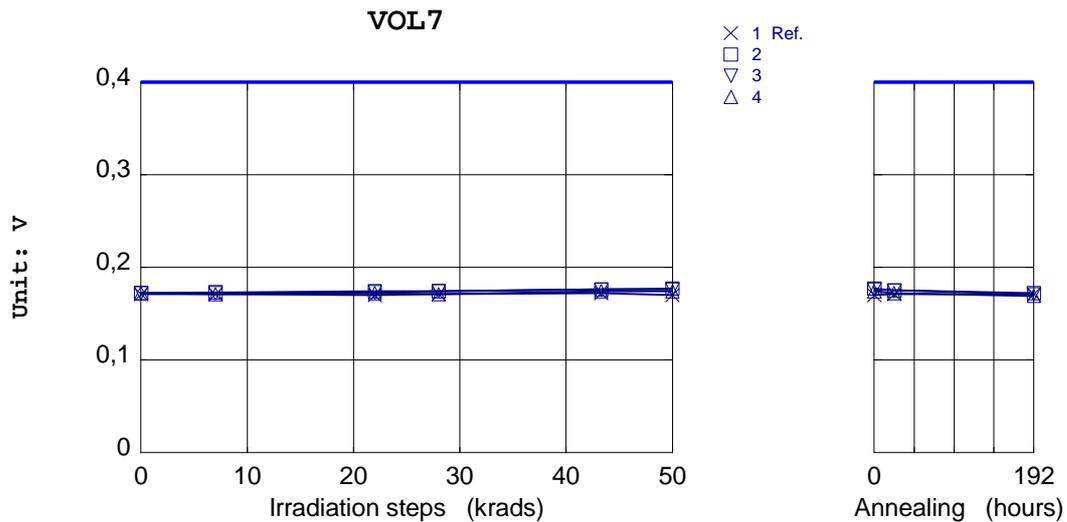
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,710E -01	1,710E -01	1,700E -01	1,710E -01	1,720E -01	1,700E -01	1,710E -01
2	1,720E -01	1,730E -01	1,740E -01	1,740E -01	1,760E -01	1,770E -01	1,750E -01
3	1,720E -01	1,720E -01	1,730E -01	1,740E -01	1,760E -01	1,760E -01	1,750E -01
4	1,720E -01	1,710E -01	1,720E -01	1,710E -01	1,740E -01	1,740E -01	1,720E -01
Statistics							
Min	1,720E -01	1,710E -01	1,720E -01	1,710E -01	1,740E -01	1,740E -01	1,720E -01
Max	1,720E -01	1,730E -01	1,740E -01	1,740E -01	1,760E -01	1,770E -01	1,750E -01
Mean	1,720E -01	1,720E -01	1,730E -01	1,730E -01	1,753E -01	1,757E -01	1,740E -01
Sigma	5,821E -11	1,000E -03	1,000E -03	1,732E -03	1,155E -03	1,528E -03	1,732E -03

Test Step	192 hours
Serial #	
1 Ref.	1,710E -01
2	1,720E -01
3	1,710E -01
4	1,690E -01
Statistics	
Min	1,690E -01
Max	1,720E -01
Mean	1,707E -01
Sigma	1,528E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 29: VOL6**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

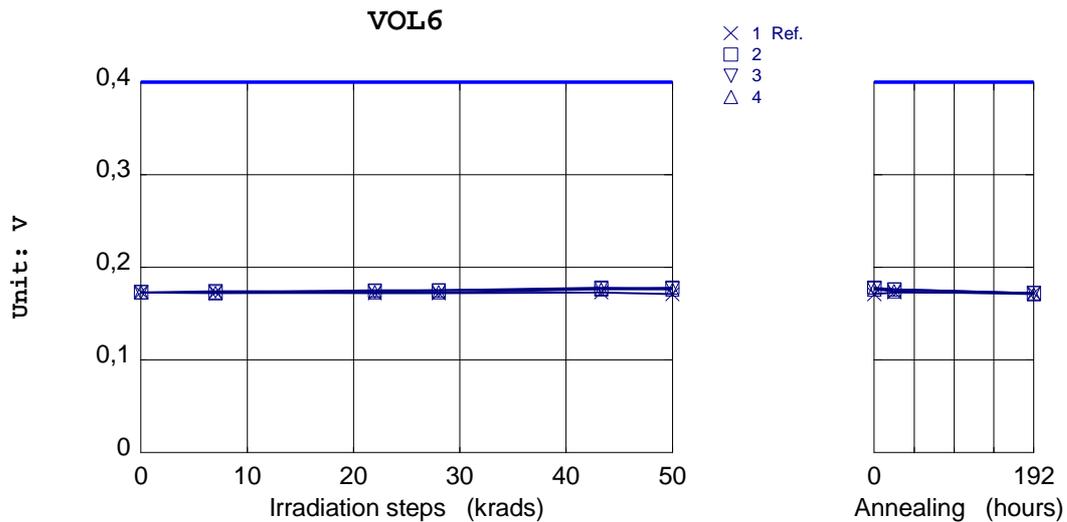
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,730E -01	1,730E -01	1,720E -01	1,720E -01	1,730E -01	1,710E -01	1,730E -01
2	1,730E -01	1,730E -01	1,750E -01	1,750E -01	1,770E -01	1,780E -01	1,760E -01
3	1,730E -01	1,740E -01	1,740E -01	1,750E -01	1,780E -01	1,770E -01	1,760E -01
4	1,730E -01	1,720E -01	1,730E -01	1,730E -01	1,760E -01	1,760E -01	1,740E -01
Statistics							
Min	1,730E -01	1,720E -01	1,730E -01	1,730E -01	1,760E -01	1,760E -01	1,740E -01
Max	1,730E -01	1,740E -01	1,750E -01	1,750E -01	1,780E -01	1,780E -01	1,760E -01
Mean	1,730E -01	1,730E -01	1,740E -01	1,743E -01	1,770E -01	1,770E -01	1,753E -01
Sigma	5,821E -11	1,000E -03	1,000E -03	1,155E -03	1,000E -03	1,000E -03	1,155E -03

Test Step	192 hours
Serial #	
1 Ref.	1,720E -01
2	1,720E -01
3	1,720E -01
4	1,710E -01
Statistics	
Min	1,710E -01
Max	1,720E -01
Mean	1,717E -01
Sigma	5,774E -04



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 28: VOL5**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

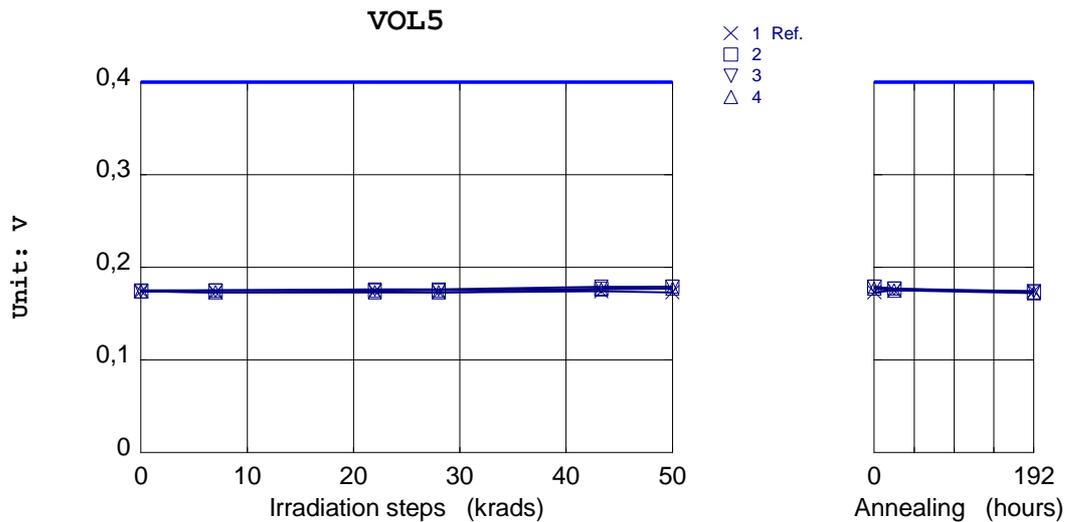
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,740E -01	1,730E -01	1,740E -01	1,730E -01	1,740E -01	1,730E -01	1,750E -01
2	1,740E -01	1,750E -01	1,750E -01	1,750E -01	1,770E -01	1,790E -01	1,770E -01
3	1,750E -01	1,750E -01	1,760E -01	1,760E -01	1,790E -01	1,790E -01	1,770E -01
4	1,740E -01	1,730E -01	1,730E -01	1,730E -01	1,760E -01	1,770E -01	1,750E -01
Statistics							
Min	1,740E -01	1,730E -01	1,730E -01	1,730E -01	1,760E -01	1,770E -01	1,750E -01
Max	1,750E -01	1,750E -01	1,760E -01	1,760E -01	1,790E -01	1,790E -01	1,770E -01
Mean	1,743E -01	1,743E -01	1,747E -01	1,747E -01	1,773E -01	1,783E -01	1,763E -01
Sigma	5,774E -04	1,155E -03	1,528E -03	1,528E -03	1,528E -03	1,155E -03	1,155E -03

Test Step	192 hours
Serial #	
1 Ref.	1,740E -01
2	1,730E -01
3	1,740E -01
4	1,720E -01
Statistics	
Min	1,720E -01
Max	1,740E -01
Mean	1,730E -01
Sigma	1,000E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Output Voltage Pin 27: VOL4  
VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

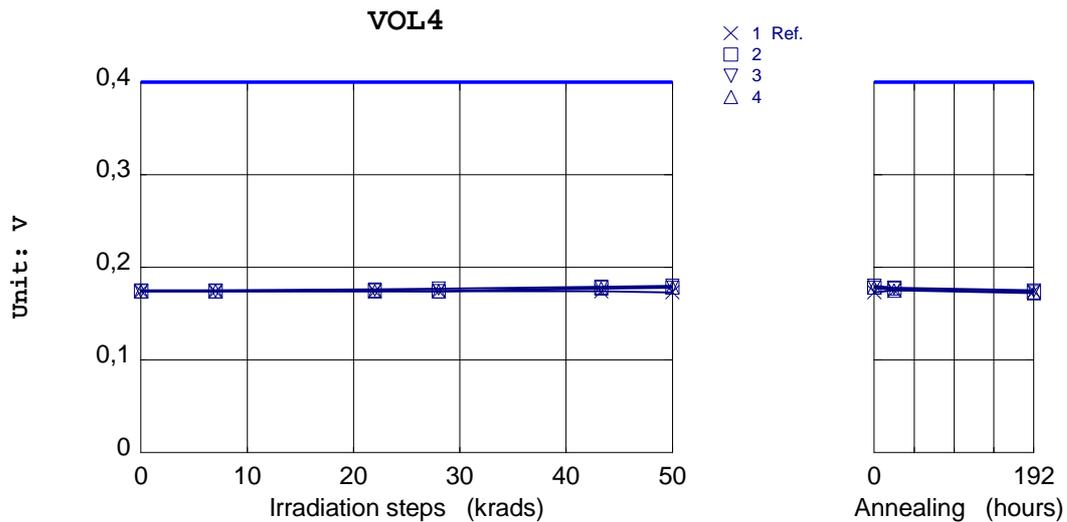
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,740E -01	1,730E -01	1,750E -01				
2	1,740E -01	1,740E -01	1,750E -01	1,740E -01	1,780E -01	1,780E -01	1,770E -01
3	1,750E -01	1,750E -01	1,760E -01	1,770E -01	1,790E -01	1,800E -01	1,780E -01
4	1,740E -01	1,740E -01	1,740E -01	1,740E -01	1,770E -01	1,780E -01	1,750E -01
Statistics							
Min	1,740E -01	1,740E -01	1,740E -01	1,740E -01	1,770E -01	1,780E -01	1,750E -01
Max	1,750E -01	1,750E -01	1,760E -01	1,770E -01	1,790E -01	1,800E -01	1,780E -01
Mean	1,743E -01	1,743E -01	1,750E -01	1,750E -01	1,780E -01	1,787E -01	1,767E -01
Sigma	5,774E -04	5,774E -04	1,000E -03	1,732E -03	1,000E -03	1,155E -03	1,528E -03

Test Step	192 hours
Serial #	
1 Ref.	1,740E -01
2	1,730E -01
3	1,750E -01
4	1,720E -01
Statistics	
Min	1,720E -01
Max	1,750E -01
Mean	1,733E -01
Sigma	1,528E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 26: VOL3**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

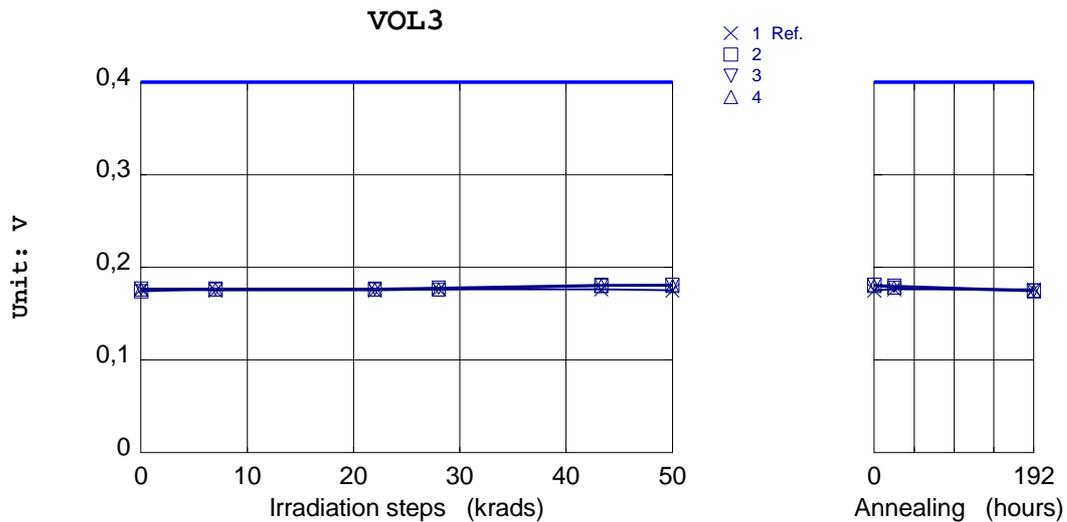
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7 krad	22 krad	28 krad	43,3 krad	50 krad	24 hours
Serial #							
1 Ref.	1,760E -01	1,750E -01	1,750E -01	1,760E -01	1,760E -01	1,750E -01	1,760E -01
2	1,740E -01	1,760E -01	1,760E -01	1,760E -01	1,800E -01	1,810E -01	1,780E -01
3	1,770E -01	1,770E -01	1,770E -01	1,780E -01	1,810E -01	1,810E -01	1,800E -01
4	1,760E -01	1,760E -01	1,760E -01	1,760E -01	1,800E -01	1,800E -01	1,780E -01
Statistics							
Min	1,740E -01	1,760E -01	1,760E -01	1,760E -01	1,800E -01	1,800E -01	1,780E -01
Max	1,770E -01	1,770E -01	1,770E -01	1,780E -01	1,810E -01	1,810E -01	1,800E -01
Mean	1,757E -01	1,763E -01	1,763E -01	1,767E -01	1,803E -01	1,807E -01	1,787E -01
Sigma	1,528E -03	5,774E -04	5,774E -04	1,155E -03	5,773E -04	5,773E -04	1,155E -03

Test Step	192 hours
Serial #	
1 Ref.	1,760E -01
2	1,750E -01
3	1,750E -01
4	1,740E -01
Statistics	
Min	1,740E -01
Max	1,750E -01
Mean	1,747E -01
Sigma	5,774E -04



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>		Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor

**APPENDIX 2 : TEST RESULTS - LOW DOSE RATE**

<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Test results including tables and graphics are provided in this section for each measured parameter corresponding to a low dose rate exposure.

**Parameter: Signal-to-Noise Ratio: SNR**

**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V, 10KHz; Fsample=1.3MHz**

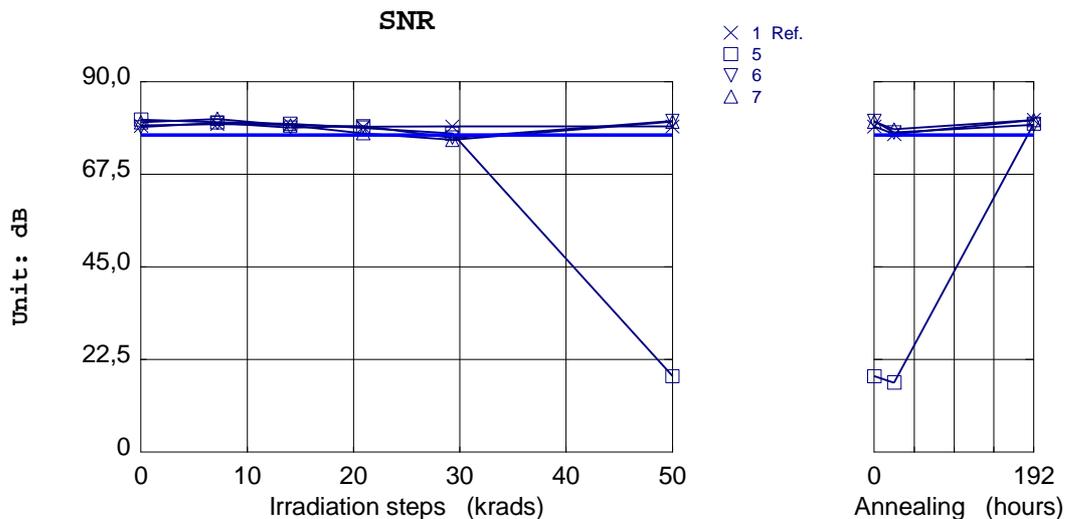
Unit= dB

Spec limit min: 77

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	7,929E +01	7,969E +01	7,952E +01	7,900E +01	7,909E +01	7,909E +01	7,721E +01
5	8,076E +01	8,011E +01	7,974E +01	7,876E +01	7,733E +01	1,847E +01	1,691E +01
6	7,896E +01	7,994E +01	7,881E +01	7,918E +01	7,639E +01	8,043E +01	7,763E +01
7	8,014E +01	8,092E +01	7,935E +01	7,742E +01	7,588E +01	8,027E +01	7,836E +01
Statistics							
Min	7,896E +01	7,994E +01	7,881E +01	7,742E +01	7,588E +01	1,847E +01	1,691E +01
Max	8,076E +01	8,092E +01	7,974E +01	7,918E +01	7,733E +01	8,043E +01	7,836E +01
Mean	7,995E +01	8,032E +01	7,930E +01	7,845E +01	7,654E +01	5,972E +01	5,763E +01
Sigma	9,142E -01	5,232E -01	4,683E -01	9,185E -01	7,370E -01	3,573E +01	3,527E +01

Test Step	192 hours
Serial #	
1 Ref.	8,069E +01
5	7,973E +01
6	7,950E +01
7	8,065E +01
Statistics	
Min	7,950E +01
Max	8,065E +01
Mean	7,996E +01
Sigma	6,085E -01

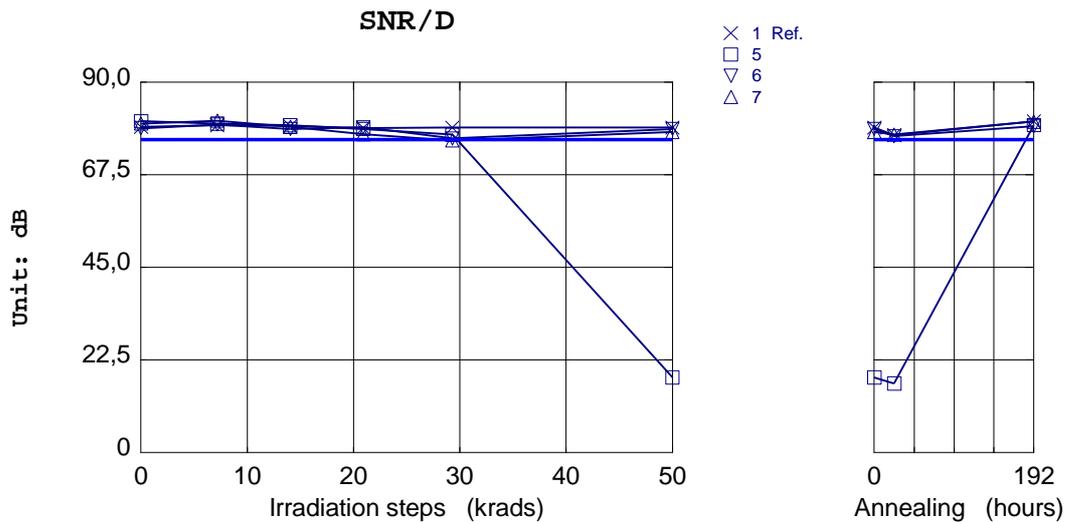


HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Signal-to-Noise Plus Distortion Ratio: SNR/D  
VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V, 10KHz; Fsample=1.3MHz  
Unit= dB  
Spec limit min: 76  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	7,910E +01	7,949E +01	7,929E +01	7,883E +01	7,892E +01	7,892E +01	7,711E +01
5	8,047E +01	7,987E +01	7,951E +01	7,860E +01	7,719E +01	1,822E +01	1,675E +01
6	7,876E +01	7,968E +01	7,859E +01	7,900E +01	7,627E +01	7,859E +01	7,683E +01
7	7,988E +01	8,061E +01	7,913E +01	7,730E +01	7,579E +01	7,784E +01	7,721E +01
Statistics							
Min	7,876E +01	7,968E +01	7,859E +01	7,730E +01	7,579E +01	1,822E +01	1,675E +01
Max	8,046E +01	8,061E +01	7,951E +01	7,900E +01	7,719E +01	7,859E +01	7,721E +01
Mean	7,970E +01	8,005E +01	7,908E +01	7,830E +01	7,642E +01	5,822E +01	5,693E +01
Sigma	8,684E -01	4,942E -01	4,627E -01	8,867E -01	7,085E -01	3,464E +01	3,479E +01

Test Step	192 hours
Serial #	
1 Ref.	8,042E +01
5	7,953E +01
6	7,926E +01
7	8,037E +01
Statistics	
Min	7,926E +01
Max	8,037E +01
Mean	7,972E +01
Sigma	5,802E -01



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Effective Number Of Bits: ENOB**

VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V, 10KHz; Fsample=1.3MHz

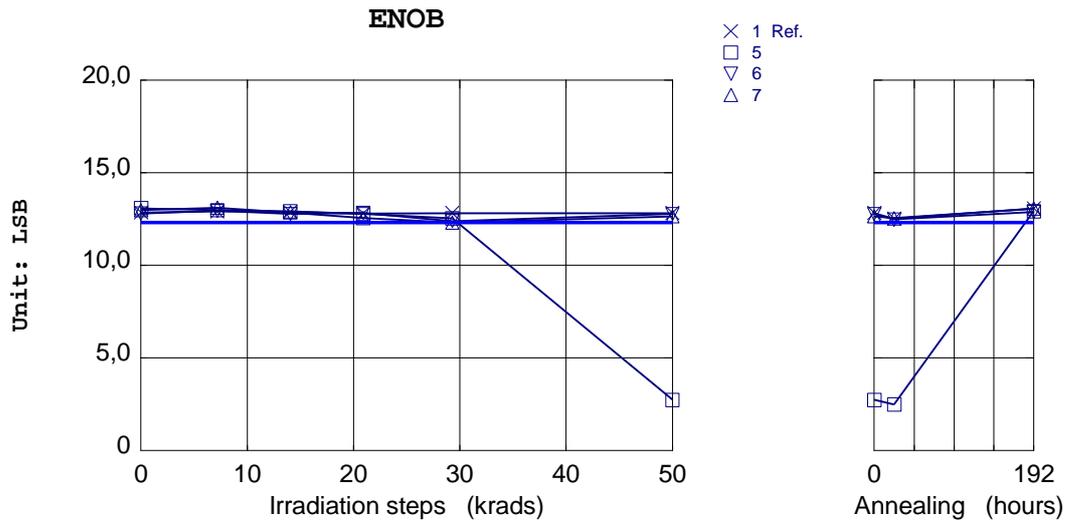
Unit= LSB

Spec limit min: 12.3

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,285E +01	1,291E +01	1,288E +01	1,280E +01	1,282E +01	1,282E +01	1,252E +01
5	1,307E +01	1,298E +01	1,292E +01	1,276E +01	1,253E +01	2,734E +00	2,491E +00
6	1,279E +01	1,294E +01	1,276E +01	1,283E +01	1,238E +01	1,276E +01	1,247E +01
7	1,298E +01	1,310E +01	1,285E +01	1,255E +01	1,230E +01	1,264E +01	1,253E +01
Statistics							
Min	1,279E +01	1,294E +01	1,276E +01	1,255E +01	1,230E +01	2,734E +00	2,491E +00
Max	1,307E +01	1,310E +01	1,291E +01	1,283E +01	1,253E +01	1,276E +01	1,253E +01
Mean	1,295E +01	1,301E +01	1,284E +01	1,271E +01	1,240E +01	9,378E +00	9,164E +00
Sigma	1,444E -01	8,202E -02	7,690E -02	1,475E -01	1,177E -01	5,754E +00	5,779E +00

Test Step	192 hours
Serial #	
1 Ref.	1,307E +01
5	1,292E +01
6	1,287E +01
7	1,306E +01
Statistics	
Min	1,287E +01
Max	1,306E +01
Mean	1,295E +01
Sigma	9,648E -02



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Total Harmonic Distortion: THD**

**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V, 10KHz; Fsample=1.3MHz; Nine Harmonics**

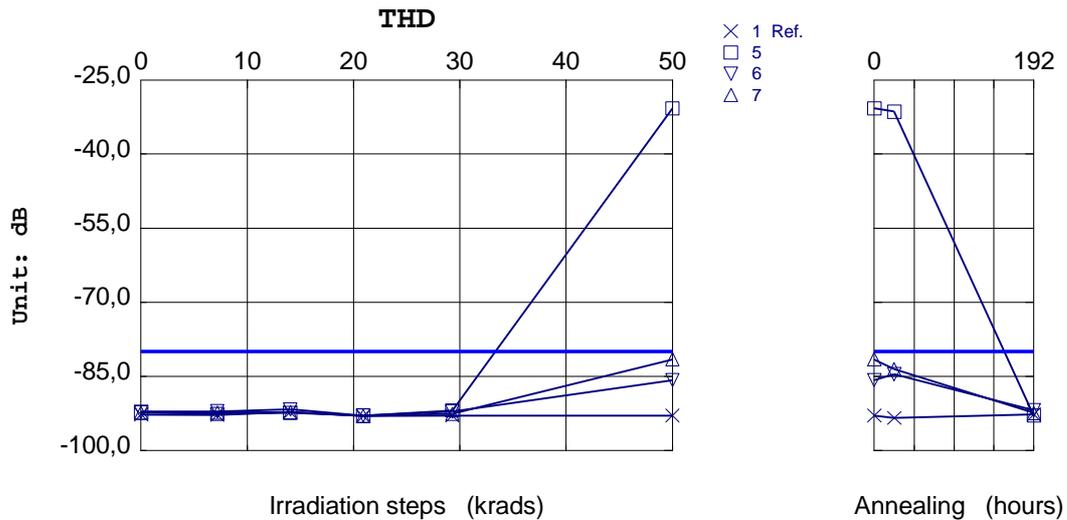
Unit= dB

Spec limit max: -80

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	-9,275E +01	-9,280E +01	-9,221E +01	-9,303E +01	-9,292E +01	-9,292E +01	-9,338E +01
5	-9,229E +01	-9,261E +01	-9,237E +01	-9,294E +01	-9,190E +01	-3,074E +01	-3,140E +01
6	-9,216E +01	-9,205E +01	-9,167E +01	-9,289E +01	-9,209E +01	-8,575E +01	-8,453E +01
7	-9,234E +01	-9,232E +01	-9,223E +01	-9,299E +01	-9,258E +01	-8,152E +01	-8,356E +01
Statistics							
Min	-9,234E +01	-9,261E +01	-9,237E +01	-9,299E +01	-9,258E +01	-8,575E +01	-8,453E +01
Max	-9,216E +01	-9,204E +01	-9,167E +01	-9,289E +01	-9,190E +01	-3,074E +01	-3,140E +01
Mean	-9,226E +01	-9,233E +01	-9,209E +01	-9,294E +01	-9,219E +01	-6,600E +01	-6,650E +01
Sigma	9,295E -02	2,845E -01	3,710E -01	4,901E -02	3,486E -01	3,061E +01	3,039E +01

Test Step	192 hours
Serial #	
1 Ref.	-9,270E +01
5	-9,292E +01
6	-9,186E +01
7	-9,240E +01
Statistics	
Min	-9,292E +01
Max	-9,186E +01
Mean	-9,239E +01
Sigma	5,300E -01

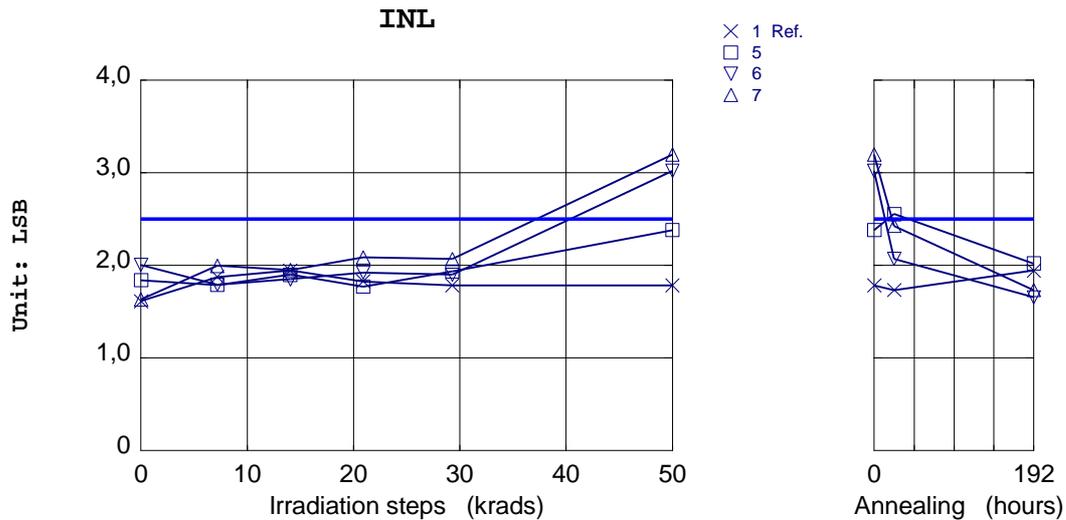


<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Integral Nonlinearity: INL**  
**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V**  
Unit= LSB  
Spec limit max: 2.5  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,612E +00	1,874E +00	1,943E +00	1,826E +00	1,782E +00	1,782E +00	1,731E +00
5	1,839E +00	1,786E +00	1,897E +00	1,770E +00	1,934E +00	2,380E +00	2,552E +00
6	2,005E +00	1,790E +00	1,849E +00	1,921E +00	1,898E +00	3,019E +00	2,070E +00
7	1,631E +00	1,994E +00	1,948E +00	2,085E +00	2,067E +00	3,196E +00	2,425E +00
Statistics							
Min	1,631E +00	1,786E +00	1,849E +00	1,770E +00	1,898E +00	2,380E +00	2,070E +00
Max	2,005E +00	1,994E +00	1,948E +00	2,085E +00	2,067E +00	3,196E +00	2,552E +00
Mean	1,825E +00	1,857E +00	1,898E +00	1,925E +00	1,966E +00	2,865E +00	2,349E +00
Sigma	1,874E -01	1,190E -01	4,951E -02	1,575E -01	8,902E -02	4,292E -01	2,498E -01

Test Step	192 hours
Serial #	
1 Ref.	1,942E +00
5	2,018E +00
6	1,654E +00
7	1,731E +00
Statistics	
Min	1,654E +00
Max	2,018E +00
Mean	1,801E +00
Sigma	1,918E -01

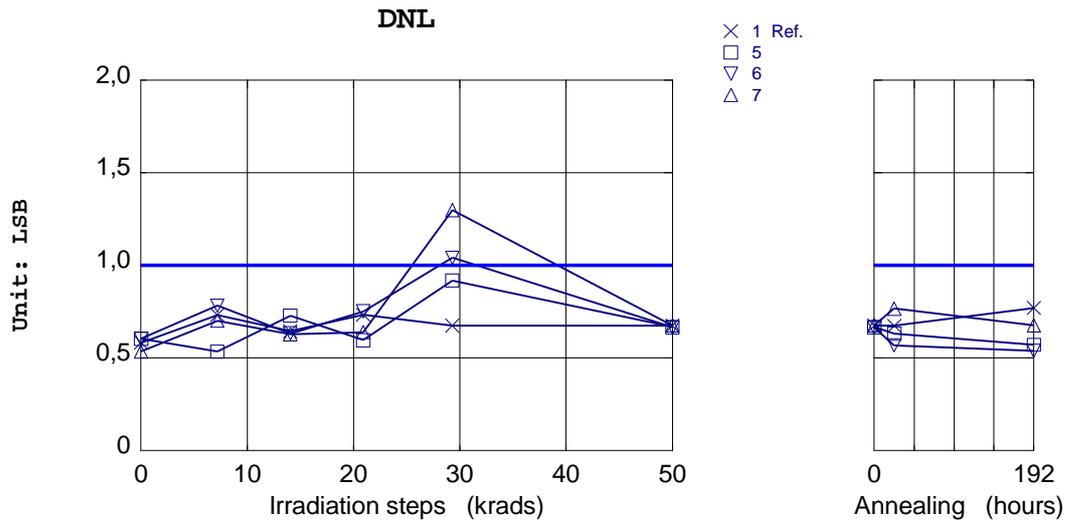


<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Differential Nonlinearity: DNL**  
**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: ±2V**  
Unit= LSB  
Spec limit max: 1  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	5,825E -01	7,315E -01	6,439E -01	7,329E -01	6,741E -01	6,741E -01	6,733E -01
5	6,033E -01	5,337E -01	7,276E -01	5,957E -01	9,171E -01	6,663E -01	6,312E -01
6	6,022E -01	7,828E -01	6,321E -01	7,510E -01	1,041E +00	6,648E -01	5,673E -01
7	5,341E -01	7,009E -01	6,277E -01	6,386E -01	1,298E +00	6,755E -01	7,660E -01
Statistics							
Min	5,341E -01	5,337E -01	6,277E -01	5,957E -01	9,171E -01	6,648E -01	5,673E -01
Max	6,033E -01	7,828E -01	7,276E -01	7,510E -01	1,298E +00	6,755E -01	7,660E -01
Mean	5,799E -01	6,725E -01	6,625E -01	6,618E -01	1,085E +00	6,688E -01	6,548E -01
Sigma	3,965E -02	1,269E -01	5,648E -02	8,018E -02	1,943E -01	5,782E -03	1,014E -01

Test Step	192 hours
Serial #	
1 Ref.	7,693E -01
5	5,711E -01
6	5,382E -01
7	6,760E -01
Statistics	
Min	5,382E -01
Max	6,760E -01
Mean	5,951E -01
Sigma	7,197E -02



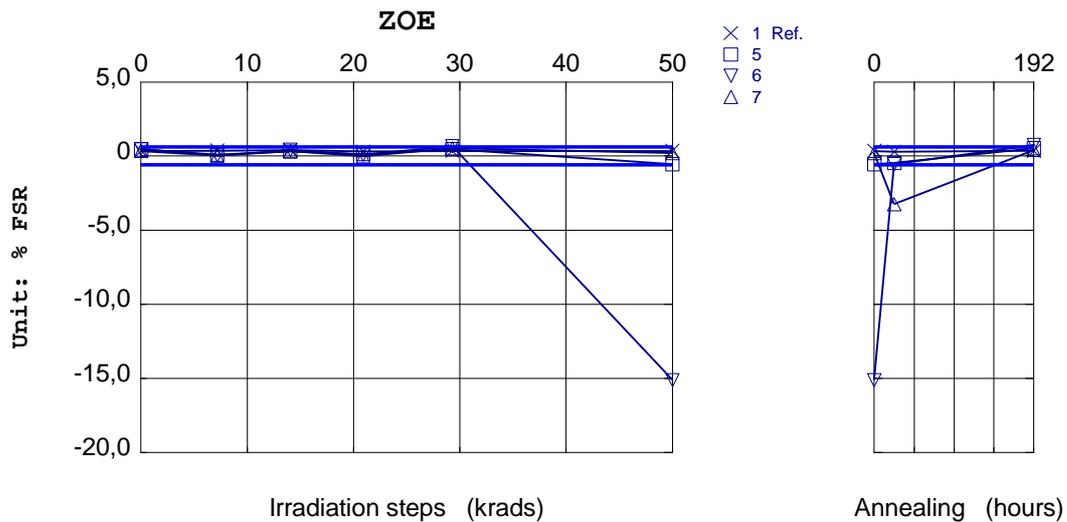
<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Zero Offset Error: ZOE**  
**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: 0V**

Unit= % FSR  
Spec limit max: 0.6  
Spec limit min: -0.6  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	3,519E -01	3,732E -01	4,030E -01	3,104E -01	3,540E -01	3,540E -01	2,930E -01
5	4,390E -01	9,766E -02	3,113E -01	1,282E -01	4,580E -01	-5,400E -01	-4,600E -01
6	4,880E -01	4,273E -02	4,150E -01	9,766E -02	6,650E -01	-1,511E +01	-5,400E -01
7	3,540E -01	2,441E -02	3,357E -01	-1,221E -02	5,250E -01	2,136E -01	-3,241E +00
Statistics							
Min	3,540E -01	2,441E -02	3,113E -01	-1,221E -02	4,580E -01	-1,511E +01	-3,241E +00
Max	4,880E -01	9,766E -02	4,150E -01	1,282E -01	6,650E -01	2,136E -01	-4,600E -01
Mean	4,270E -01	5,493E -02	3,540E -01	7,121E -02	5,493E -01	-5,146E +00	-1,414E +00
Sigma	6,780E -02	3,812E -02	5,425E -02	7,383E -02	1,056E -01	8,639E +00	1,583E +00

Test Step	192 hours
Serial #	
1 Ref.	3,578E -01
5	5,371E -01
6	7,507E -01
7	4,089E -01
Statistics	
Min	4,089E -01
Max	7,507E -01
Mean	5,656E -01
Sigma	1,727E -01

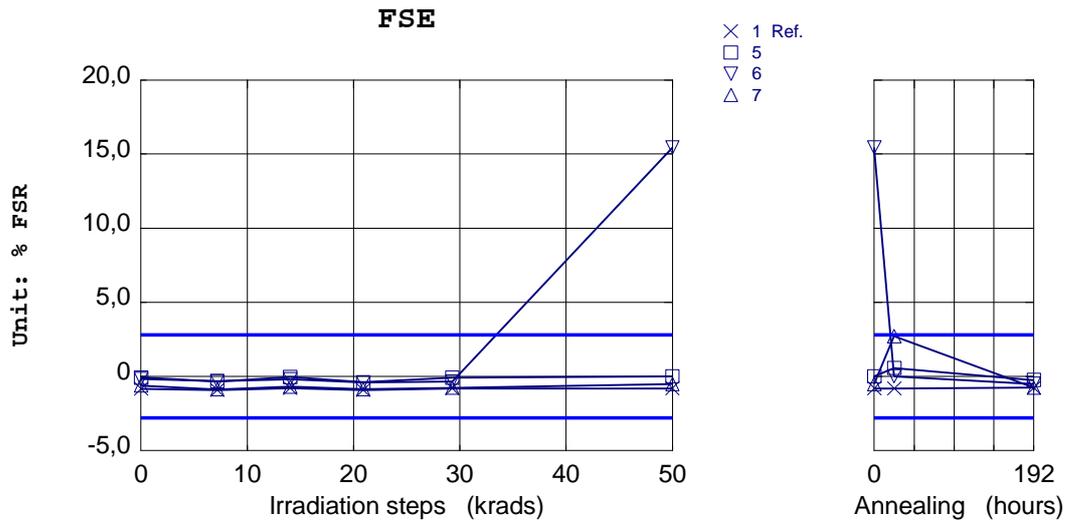


<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Full-Scale Error: FSE**  
**VA=+5V; VD=+5V; VDI/O=+5V; Vcm=Vref=+2V; Input signal: 2V**  
Unit= % FSR  
Spec limit max: 2.8  
Spec limit min: -2.8  
Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	-8,300E -01	-9,155E -01	-7,870E -01	-9,160E -01	-8,057E -01	-8,057E -01	-8,179E -01
5	-7,930E -02	-3,235E -01	-3,662E -02	-3,906E -01	-8,540E -02	1,000E -02	5,700E -01
6	-1,650E -01	-3,174E -01	-1,831E -01	-4,028E -01	-3,300E -01	1,545E +01	1,000E -02
7	-6,040E -01	-8,667E -01	-6,958E -01	-8,606E -01	-7,750E -01	-5,188E -01	2,722E +00
Statistics							
Min	-6,040E -01	-8,667E -01	-6,958E -01	-8,606E -01	-7,750E -01	-5,188E -01	1,000E -02
Max	-7,930E -02	-3,174E -01	-3,662E -02	-3,906E -01	-8,540E -02	1,545E +01	2,722E +00
Mean	-2,828E -01	-5,025E -01	-3,052E -01	-5,514E -01	-3,968E -01	4,980E +00	1,101E +00
Sigma	2,815E -01	3,154E -01	3,461E -01	2,679E -01	3,496E -01	9,070E +00	1,432E +00

Test Step	192 hours
Serial #	
1 Ref.	-7,507E -01
5	-2,441E -01
6	-5,066E -01
7	-7,568E -01
Statistics	
Min	-7,568E -01
Max	-2,441E -01
Mean	-5,025E -01
Sigma	2,564E -01



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Analog Supply Current: IA**

**VA=+5V; VD=+5V; VDI/O=+5V**

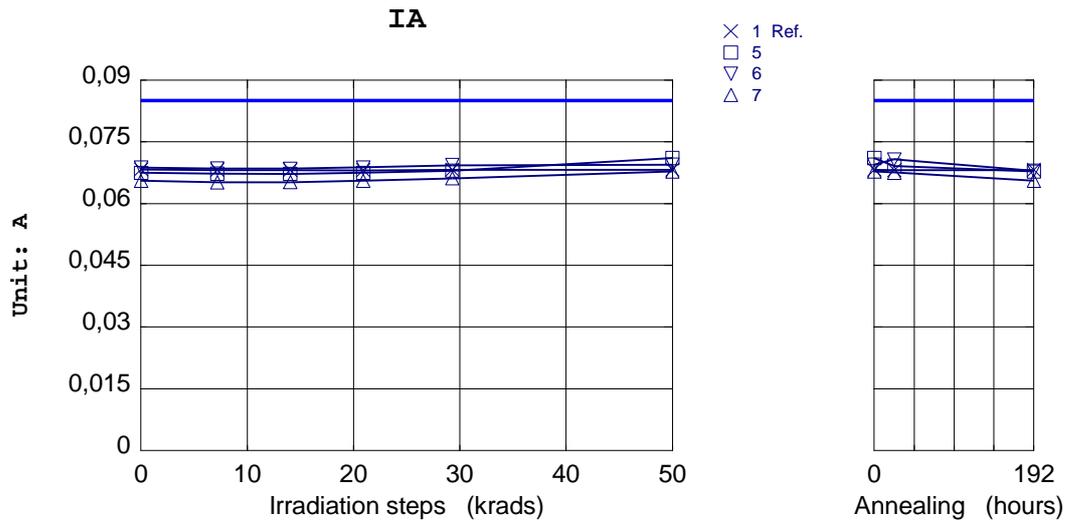
Unit= A

Spec limit max: 0.085

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	6,826E -02	6,811E -02	6,811E -02	6,808E -02	6,819E -02	6,819E -02	6,810E -02
5	6,747E -02	6,723E -02	6,720E -02	6,746E -02	6,796E -02	7,104E -02	6,916E -02
6	6,873E -02	6,850E -02	6,845E -02	6,879E -02	6,931E -02	6,941E -02	7,074E -02
7	6,553E -02	6,515E -02	6,516E -02	6,553E -02	6,610E -02	6,779E -02	6,751E -02
Statistics							
Min	6,553E -02	6,515E -02	6,516E -02	6,553E -02	6,610E -02	6,779E -02	6,751E -02
Max	6,873E -02	6,850E -02	6,845E -02	6,879E -02	6,931E -02	7,104E -02	7,074E -02
Mean	6,724E -02	6,696E -02	6,694E -02	6,726E -02	6,779E -02	6,941E -02	6,914E -02
Sigma	1,614E -03	1,694E -03	1,663E -03	1,638E -03	1,610E -03	1,624E -03	1,614E -03

Test Step	192 hours
Serial #	
1 Ref.	6,815E -02
5	6,778E -02
6	6,799E -02
7	6,555E -02
Statistics	
Min	6,555E -02
Max	6,799E -02
Mean	6,711E -02
Sigma	1,352E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Digital Supply Current: ID**

**VA=+5V; VD=+5V; VDI/O=+5V**

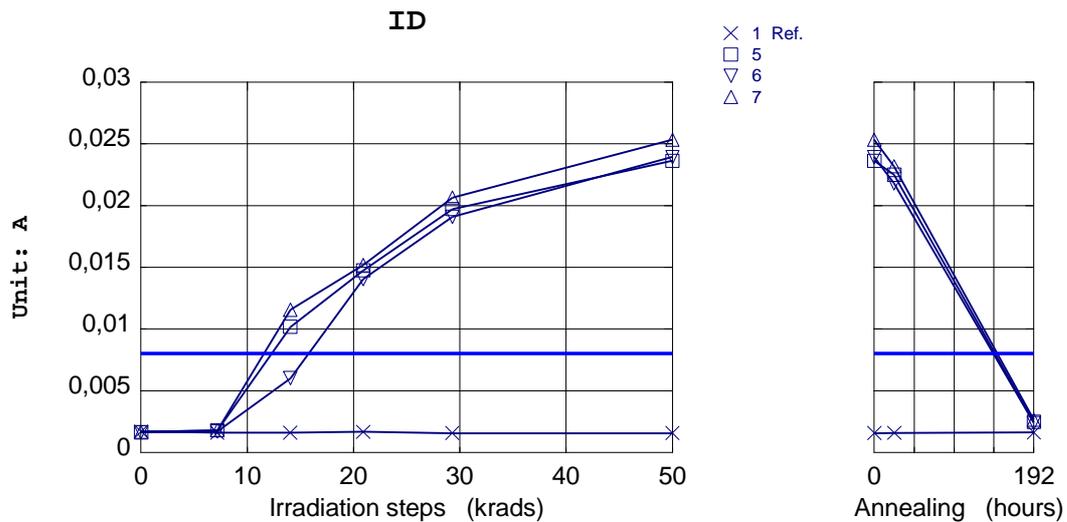
Unit= A

Spec limit max: 0.008

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,702E -03	1,602E -03	1,619E -03	1,685E -03	1,570E -03	1,570E -03	1,585E -03
5	1,649E -03	1,804E -03	1,018E -02	1,475E -02	1,971E -02	2,362E -02	2,250E -02
6	1,640E -03	1,712E -03	6,020E -03	1,404E -02	1,908E -02	2,393E -02	2,180E -02
7	1,681E -03	1,812E -03	1,156E -02	1,519E -02	2,063E -02	2,533E -02	2,317E -02
Statistics							
Min	1,640E -03	1,712E -03	6,020E -03	1,404E -02	1,908E -02	2,362E -02	2,180E -02
Max	1,681E -03	1,812E -03	1,156E -02	1,519E -02	2,063E -02	2,533E -02	2,317E -02
Mean	1,657E -03	1,776E -03	9,254E -03	1,466E -02	1,981E -02	2,429E -02	2,249E -02
Sigma	2,155E -05	5,557E -05	2,884E -03	5,781E -04	7,808E -04	9,096E -04	6,851E -04

Test Step	192 hours
Serial #	
1 Ref.	1,632E -03
5	2,485E -03
6	2,390E -03
7	2,664E -03
Statistics	
Min	2,390E -03
Max	2,664E -03
Mean	2,513E -03
Sigma	1,391E -04



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Digital Output Bus Supply Current: IDI/O**

**VA=+5V; VD=+5V; VDI/O=+5V**

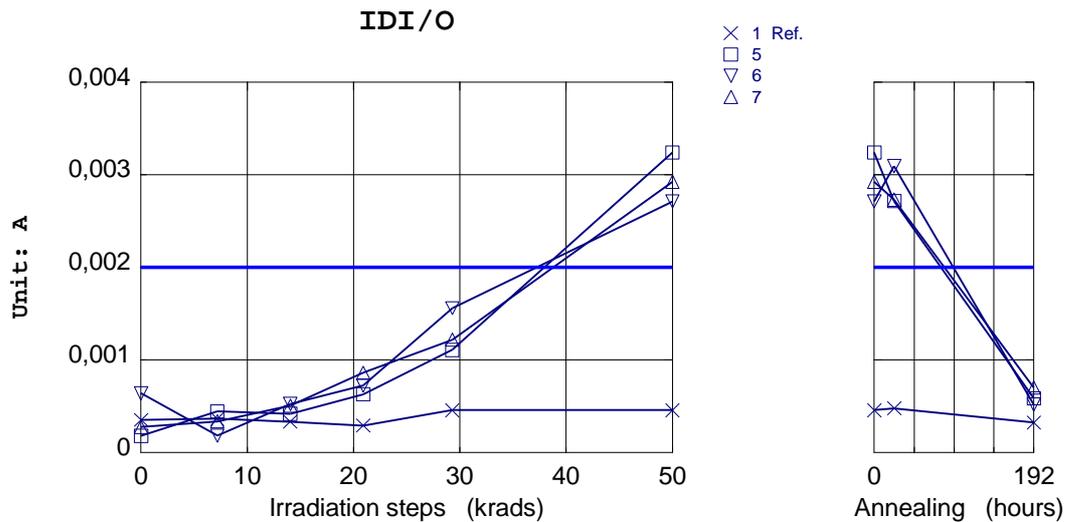
Unit= A

Spec limit max: 0.002

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	3,518E -04	3,638E -04	3,327E -04	2,912E -04	4,569E -04	4,569E -04	4,780E -04
5	1,801E -04	4,441E -04	4,175E -04	6,282E -04	1,108E -03	3,240E -03	2,714E -03
6	6,400E -04	1,817E -04	5,240E -04	7,240E -04	1,558E -03	2,710E -03	3,093E -03
7	2,748E -04	3,363E -04	5,056E -04	8,613E -04	1,218E -03	2,923E -03	2,731E -03
Statistics							
Min	1,801E -04	1,817E -04	4,175E -04	6,282E -04	1,108E -03	2,710E -03	2,714E -03
Max	6,400E -04	4,441E -04	5,240E -04	8,613E -04	1,558E -03	3,240E -03	3,093E -03
Mean	3,650E -04	3,207E -04	4,823E -04	7,378E -04	1,295E -03	2,958E -03	2,846E -03
Sigma	2,429E -04	1,319E -04	5,692E -05	1,172E -04	2,346E -04	2,667E -04	2,141E -04

Test Step	192 hours
Serial #	
1 Ref.	3,237E -04
5	5,871E -04
6	5,183E -04
7	7,021E -04
Statistics	
Min	5,183E -04
Max	7,021E -04
Mean	6,025E -04
Sigma	9,283E -05



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Input Voltage: Vih**  
**VA=+5V; VD=+5V; VDI/O=+5V**

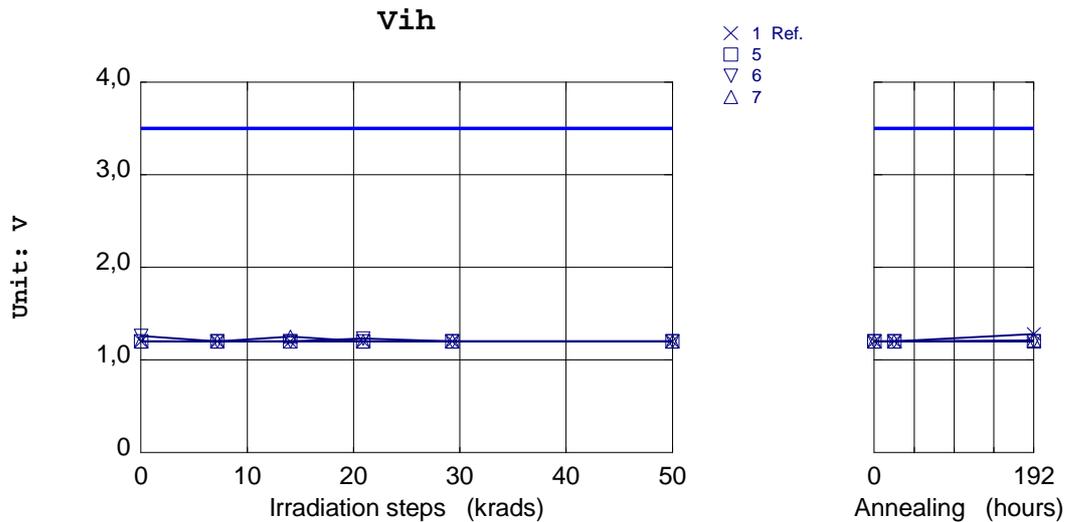
Unit= V

Spec limit max: 3.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,200E +00						
5	1,200E +00						
6	1,260E +00	1,200E +00	1,200E +00	1,230E +00	1,200E +00	1,200E +00	1,200E +00
7	1,200E +00	1,200E +00	1,250E +00	1,200E +00	1,200E +00	1,200E +00	1,200E +00
Statistics							
Min	1,200E +00						
Max	1,260E +00	1,200E +00	1,250E +00	1,230E +00	1,200E +00	1,200E +00	1,200E +00
Mean	1,220E +00	1,200E +00	1,217E +00	1,210E +00	1,200E +00	1,200E +00	1,200E +00
Sigma	3,464E -02	0,000E +00	2,887E -02	1,732E -02	0,000E +00	0,000E +00	0,000E +00

Test Step	192 hours
Serial #	
1 Ref.	1,280E +00
5	1,200E +00
6	1,200E +00
7	1,210E +00
Statistics	
Min	1,200E +00
Max	1,210E +00
Mean	1,203E +00
Sigma	5,773E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Input Voltage: Vil**

**VA=+5V; VD=+5V; VDI/O=+5V**

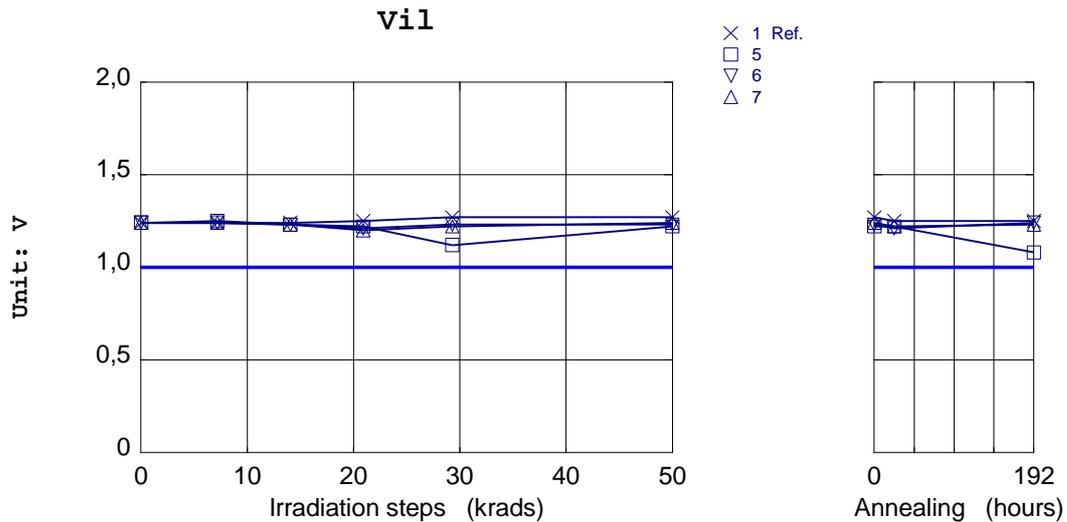
Unit= V

Spec limit min: 1

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,240E +00	1,240E +00	1,240E +00	1,250E +00	1,270E +00	1,270E +00	1,250E +00
5	1,240E +00	1,250E +00	1,230E +00	1,220E +00	1,120E +00	1,220E +00	1,220E +00
6	1,240E +00	1,240E +00	1,230E +00	1,210E +00	1,230E +00	1,230E +00	1,210E +00
7	1,240E +00	1,240E +00	1,230E +00	1,200E +00	1,220E +00	1,240E +00	1,220E +00
Statistics							
Min	1,240E +00	1,240E +00	1,230E +00	1,200E +00	1,120E +00	1,220E +00	1,210E +00
Max	1,240E +00	1,250E +00	1,230E +00	1,220E +00	1,230E +00	1,240E +00	1,220E +00
Mean	1,240E +00	1,243E +00	1,230E +00	1,210E +00	1,190E +00	1,230E +00	1,217E +00
Sigma	0,000E +00	5,773E -03	0,000E +00	1,000E -02	6,083E -02	1,000E -02	5,773E -03

Test Step	192 hours
Serial #	
1 Ref.	1,250E +00
5	1,080E +00
6	1,240E +00
7	1,230E +00
Statistics	
Min	1,080E +00
Max	1,240E +00
Mean	1,183E +00
Sigma	8,963E -02



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 38: VOH13**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

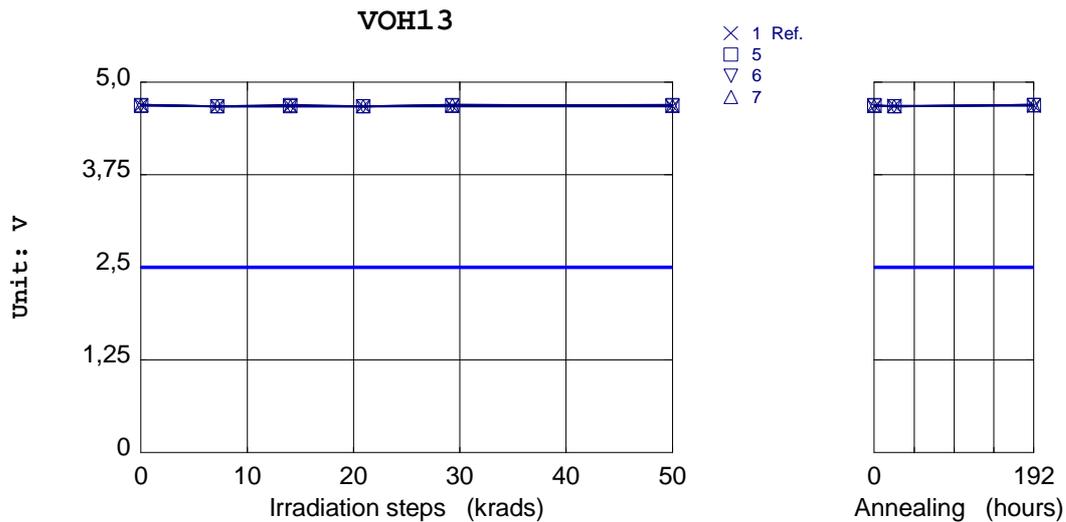
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00
5	4,680E +00	4,670E +00	4,690E +00	4,670E +00	4,680E +00	4,690E +00	4,670E +00
6	4,690E +00	4,670E +00	4,670E +00	4,670E +00	4,690E +00	4,680E +00	4,670E +00
7	4,690E +00	4,670E +00	4,670E +00	4,670E +00	4,690E +00	4,680E +00	4,670E +00
Statistics							
Min	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Max	4,690E +00	4,670E +00	4,690E +00	4,670E +00	4,690E +00	4,690E +00	4,670E +00
Mean	4,687E +00	4,670E +00	4,677E +00	4,670E +00	4,687E +00	4,683E +00	4,670E +00
Sigma	5,774E -03	2,634E -09	1,155E -02	2,634E -09	5,774E -03	5,774E -03	2,634E -09

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,690E +00
6	4,690E +00
7	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 37: VOH12**

VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA

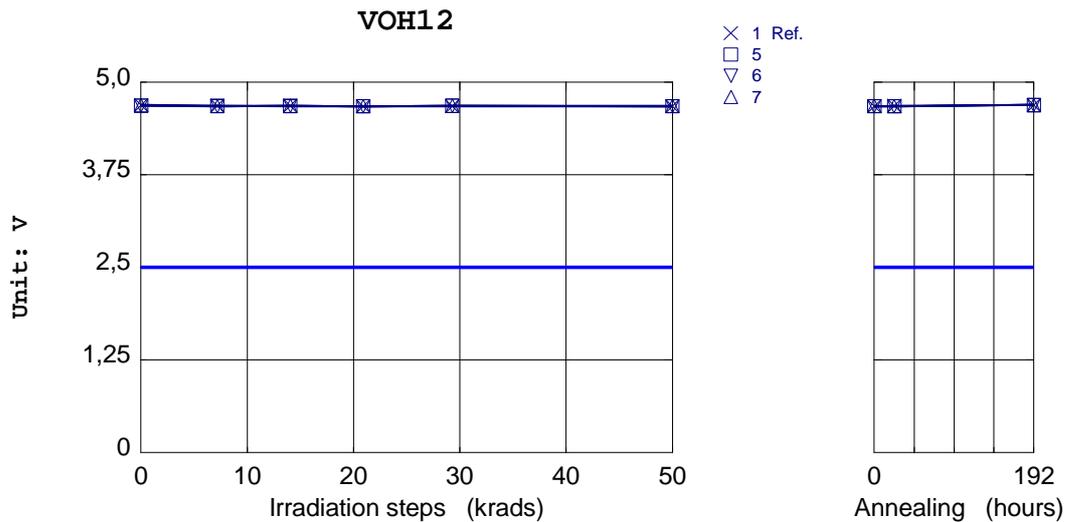
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00
5	4,680E +00	4,680E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00
6	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00
7	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Statistics							
Min	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00
Max	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Mean	4,683E +00	4,673E +00	4,677E +00	4,670E +00	4,680E +00	4,673E +00	4,670E +00
Sigma	5,774E -03	5,773E -03	5,773E -03	2,634E -09	0,000E +00	5,773E -03	2,634E -09

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
5	4,690E +00
6	4,690E +00
7	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 36: VOH11**

VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA

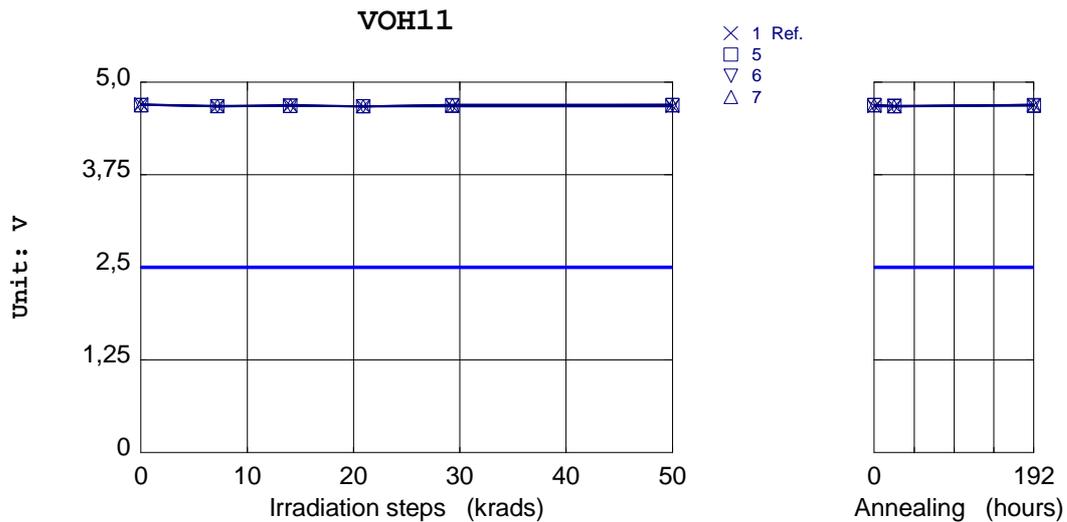
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,700E +00	4,670E +00	4,690E +00	4,670E +00	4,670E +00	4,670E +00	4,670E +00
5	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,690E +00	4,670E +00
6	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,690E +00	4,690E +00	4,680E +00
7	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,690E +00	4,690E +00	4,670E +00
Statistics							
Min	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,690E +00	4,670E +00
Max	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,690E +00	4,690E +00	4,680E +00
Mean	4,690E +00	4,673E +00	4,680E +00	4,670E +00	4,687E +00	4,690E +00	4,673E +00
Sigma	0,000E +00	5,773E -03	0,000E +00	2,634E -09	5,774E -03	0,000E +00	5,773E -03

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
5	4,680E +00
6	4,690E +00
7	4,690E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,687E +00
Sigma	5,774E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 35: VOH10**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

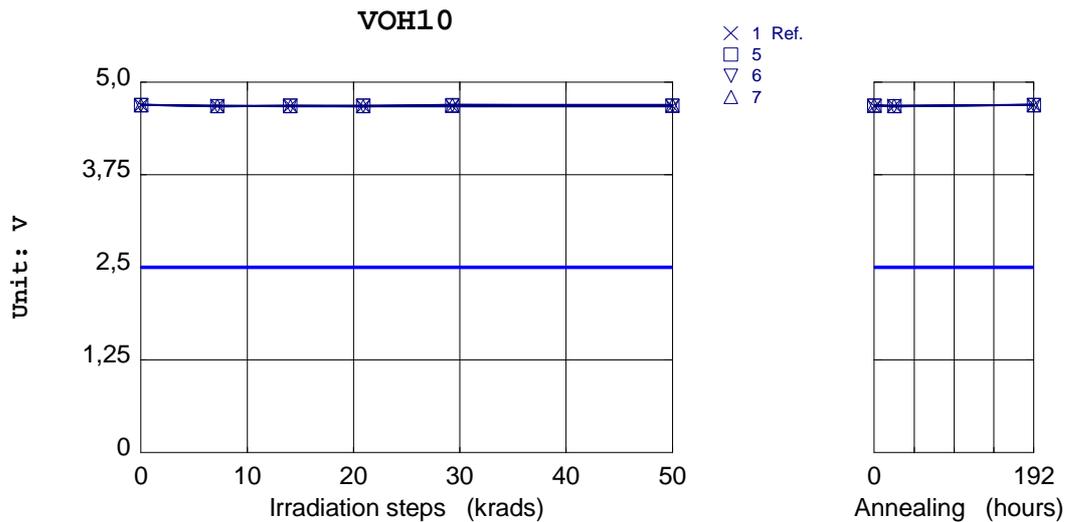
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00
5	4,690E +00	4,670E +00	4,680E +00	4,680E +00	4,680E +00	4,680E +00	4,670E +00
6	4,690E +00	4,670E +00	4,680E +00	4,680E +00	4,690E +00	4,680E +00	4,670E +00
7	4,690E +00	4,680E +00	4,670E +00	4,670E +00	4,690E +00	4,690E +00	4,680E +00
Statistics							
Min	4,690E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Max	4,690E +00	4,680E +00	4,680E +00	4,680E +00	4,690E +00	4,690E +00	4,680E +00
Mean	4,690E +00	4,673E +00	4,677E +00	4,677E +00	4,687E +00	4,683E +00	4,673E +00
Sigma	0,000E +00	5,773E -03	5,773E -03	5,773E -03	5,774E -03	5,774E -03	5,773E -03

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
5	4,690E +00
6	4,690E +00
7	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 32: VOH9**

**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

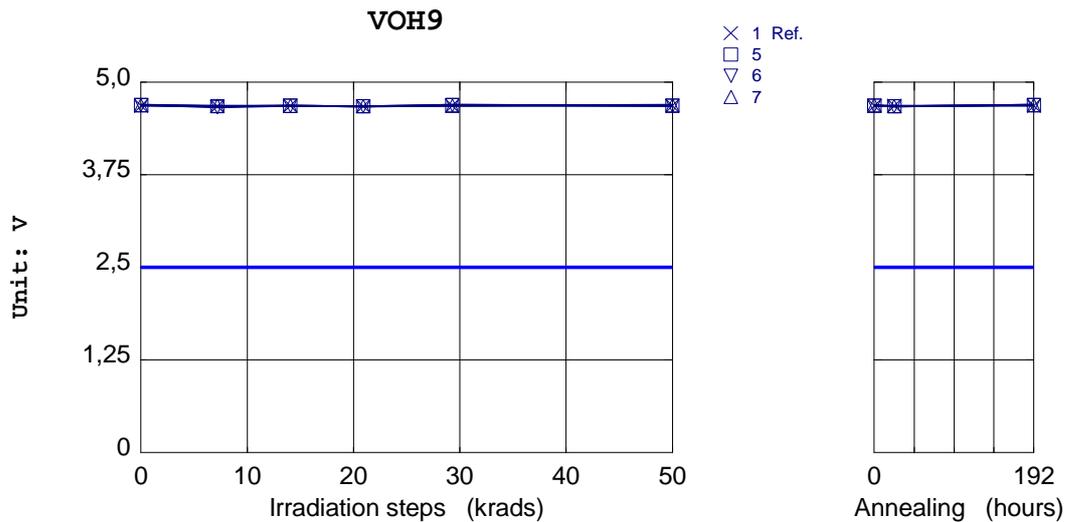
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,680E +00
5	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,690E +00	4,680E +00	4,670E +00
6	4,690E +00	4,660E +00	4,680E +00	4,670E +00	4,690E +00	4,680E +00	4,670E +00
7	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,680E +00	4,690E +00	4,670E +00
Statistics							
Min	4,690E +00	4,660E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Max	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,690E +00	4,690E +00	4,670E +00
Mean	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,687E +00	4,683E +00	4,670E +00
Sigma	0,000E +00	1,000E -02	0,000E +00	2,634E -09	5,774E -03	5,774E -03	2,634E -09

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,690E +00
6	4,690E +00
7	4,690E +00
Statistics	
Min	4,690E +00
Max	4,690E +00
Mean	4,690E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 31: VOH8**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

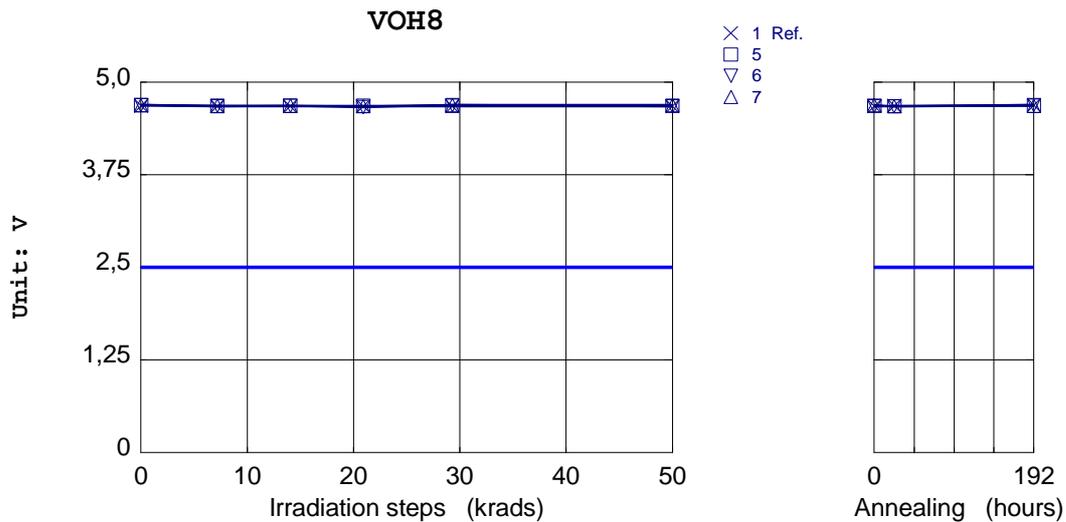
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,680E +00				
5	4,690E +00	4,670E +00	4,680E +00	4,680E +00	4,680E +00	4,680E +00	4,670E +00
6	4,690E +00	4,680E +00	4,680E +00	4,660E +00	4,690E +00	4,670E +00	4,670E +00
7	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,690E +00	4,690E +00	4,670E +00
Statistics							
Min	4,690E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,670E +00	4,670E +00
Max	4,690E +00	4,680E +00	4,680E +00	4,680E +00	4,690E +00	4,690E +00	4,670E +00
Mean	4,690E +00	4,677E +00	4,680E +00	4,670E +00	4,687E +00	4,680E +00	4,670E +00
Sigma	0,000E +00	5,773E -03	0,000E +00	1,000E -02	5,774E -03	1,000E -02	2,634E -09

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
5	4,680E +00
6	4,690E +00
7	4,680E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,683E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 30: VOH7**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

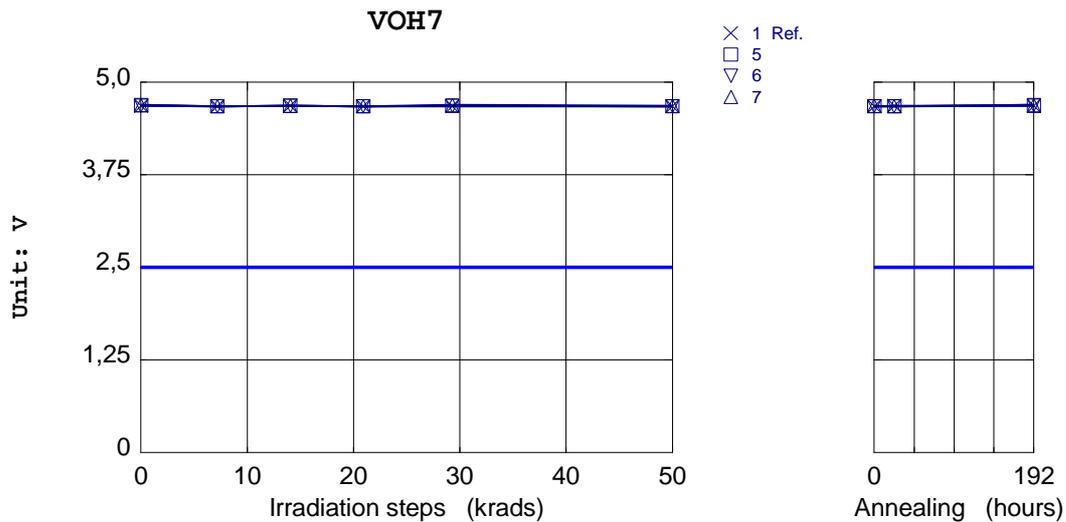
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00
5	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00
6	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00
7	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,690E +00	4,680E +00	4,670E +00
Statistics							
Min	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00
Max	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,690E +00	4,680E +00	4,670E +00
Mean	4,687E +00	4,670E +00	4,680E +00	4,670E +00	4,683E +00	4,673E +00	4,670E +00
Sigma	5,774E -03	2,634E -09	0,000E +00	2,634E -09	5,774E -03	5,773E -03	2,634E -09

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,680E +00
6	4,690E +00
7	4,690E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,687E +00
Sigma	5,774E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: High Level Output Voltage Pin 29: VOH6  
VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA

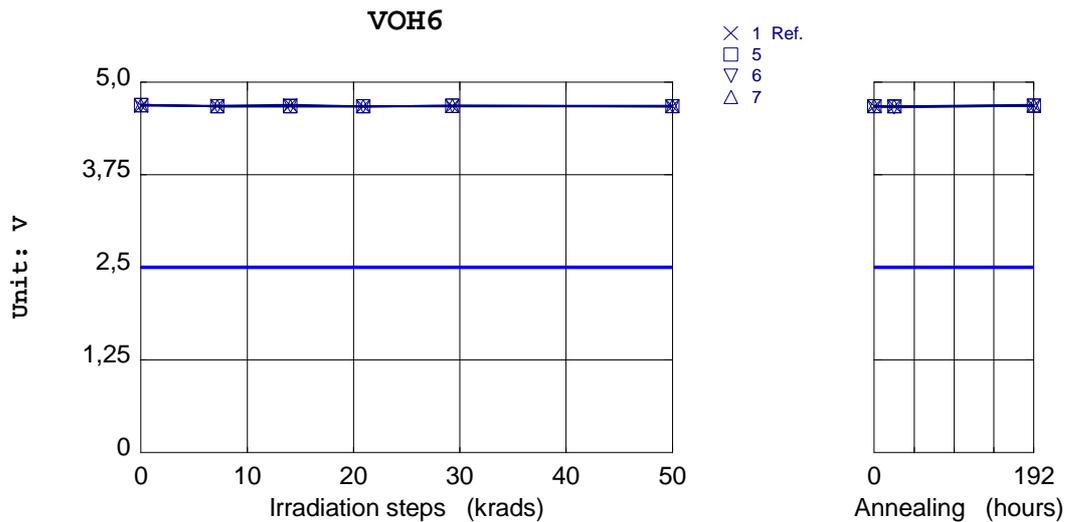
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,680E +00	4,690E +00	4,670E +00	4,670E +00	4,670E +00	4,670E +00
5	4,690E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00
6	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,660E +00
7	4,690E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Statistics							
Min	4,690E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,660E +00
Max	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Mean	4,690E +00	4,670E +00	4,673E +00	4,670E +00	4,680E +00	4,673E +00	4,667E +00
Sigma	0,000E +00	2,634E -09	5,773E -03	2,634E -09	0,000E +00	5,773E -03	5,774E -03

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,680E +00
6	4,680E +00
7	4,690E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,683E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 28: VOH5**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

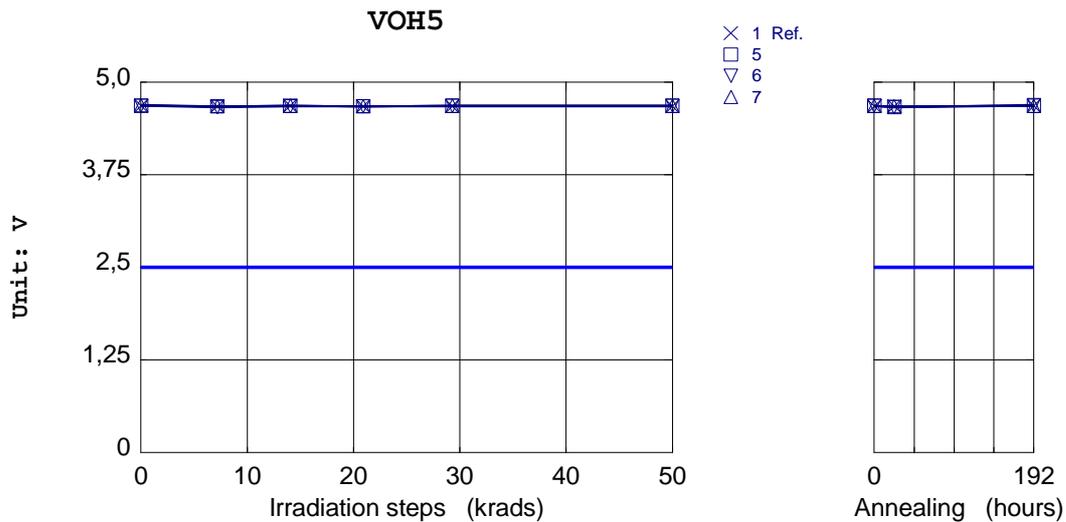
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,670E +00
5	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,660E +00
6	4,680E +00	4,660E +00	4,670E +00	4,670E +00	4,680E +00	4,680E +00	4,660E +00
7	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Statistics							
Min	4,680E +00	4,660E +00	4,670E +00	4,670E +00	4,680E +00	4,680E +00	4,660E +00
Max	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Mean	4,683E +00	4,667E +00	4,677E +00	4,670E +00	4,680E +00	4,680E +00	4,663E +00
Sigma	5,774E -03	5,774E -03	5,773E -03	2,634E -09	0,000E +00	0,000E +00	5,774E -03

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,680E +00
6	4,690E +00
7	4,680E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,683E +00
Sigma	5,774E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: High Level Output Voltage Pin 27: VOH4  
VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA

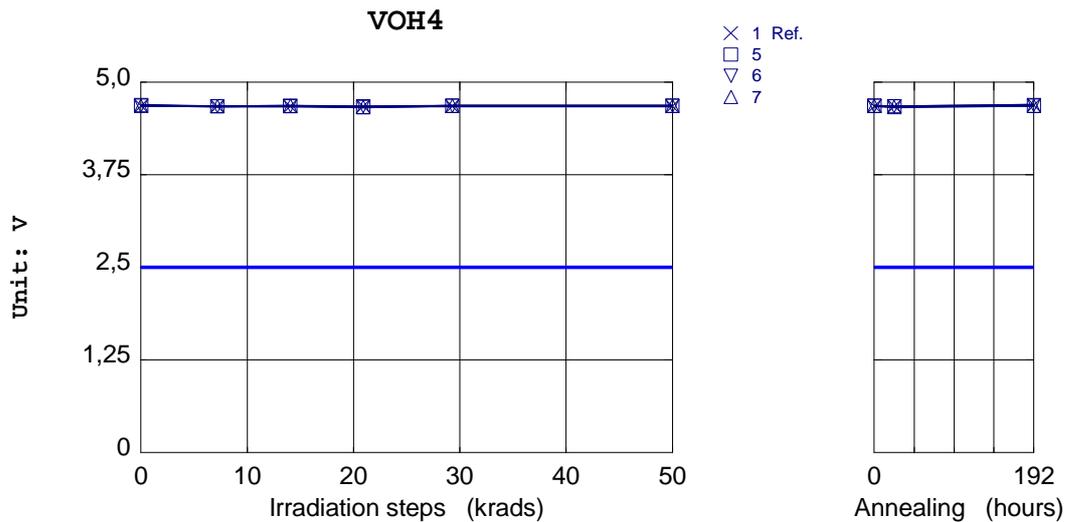
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00					
5	4,690E +00	4,670E +00	4,670E +00	4,660E +00	4,680E +00	4,680E +00	4,670E +00
6	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
7	4,680E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,680E +00	4,660E +00
Statistics							
Min	4,680E +00	4,670E +00	4,670E +00	4,660E +00	4,680E +00	4,680E +00	4,660E +00
Max	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,680E +00	4,670E +00
Mean	4,683E +00	4,670E +00	4,677E +00	4,663E +00	4,680E +00	4,680E +00	4,667E +00
Sigma	5,774E -03	2,634E -09	5,773E -03	5,774E -03	0,000E +00	0,000E +00	5,774E -03

Test Step	192 hours
Serial #	
1 Ref.	4,690E +00
5	4,680E +00
6	4,690E +00
7	4,680E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,683E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 26: VOH3**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

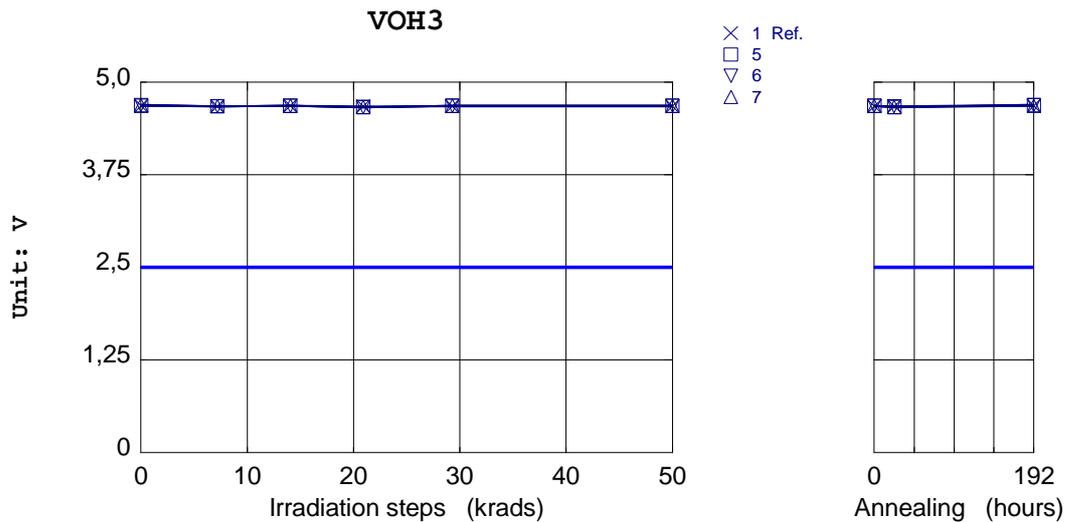
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,670E +00
5	4,680E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,680E +00	4,660E +00
6	4,690E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,680E +00	4,670E +00
7	4,690E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,680E +00	4,660E +00
Statistics							
Min	4,680E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,680E +00	4,660E +00
Max	4,690E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,680E +00	4,670E +00
Mean	4,687E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,680E +00	4,663E +00
Sigma	5,774E -03	2,634E -09	0,000E +00	2,634E -09	0,000E +00	0,000E +00	5,774E -03

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,690E +00
6	4,690E +00
7	4,680E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,687E +00
Sigma	5,774E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 25: VOH2**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

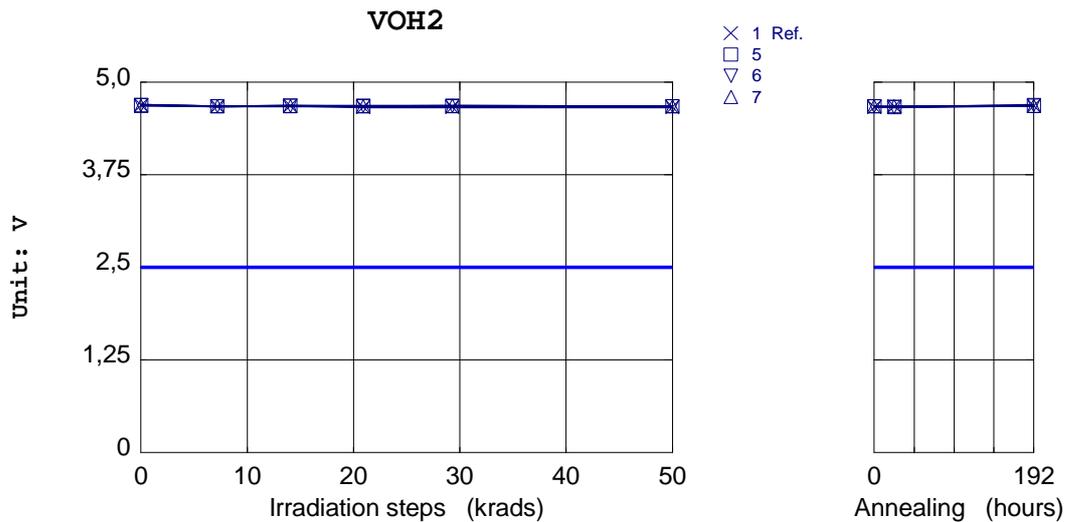
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,670E +00	4,680E +00	4,660E +00	4,660E +00	4,660E +00	4,670E +00
5	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,660E +00
6	4,690E +00	4,670E +00	4,680E +00	4,680E +00	4,680E +00	4,670E +00	4,660E +00
7	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00
Statistics							
Min	4,680E +00	4,670E +00	4,660E +00				
Max	4,690E +00	4,670E +00	4,680E +00	4,680E +00	4,680E +00	4,670E +00	4,670E +00
Mean	4,687E +00	4,670E +00	4,677E +00	4,673E +00	4,677E +00	4,670E +00	4,663E +00
Sigma	5,774E -03	2,634E -09	5,773E -03	5,773E -03	5,773E -03	2,634E -09	5,774E -03

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,680E +00
6	4,690E +00
7	4,680E +00
Statistics	
Min	4,680E +00
Max	4,690E +00
Mean	4,683E +00
Sigma	5,774E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: High Level Output Voltage Pin 24: VOH1  
VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA

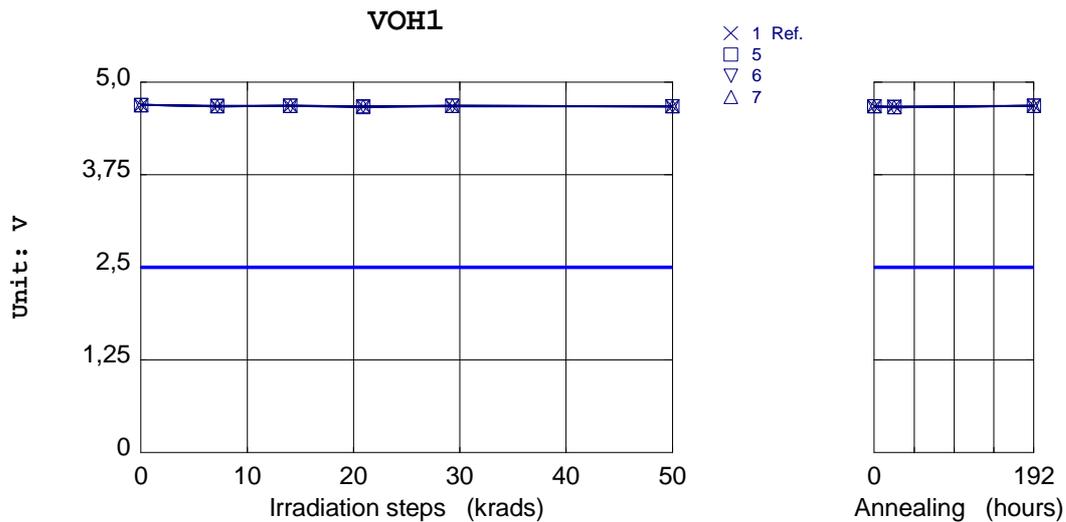
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,670E +00	4,670E +00	4,670E +00
5	4,690E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,670E +00	4,660E +00
6	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,660E +00
7	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,660E +00
Statistics							
Min	4,690E +00	4,670E +00	4,680E +00	4,660E +00	4,680E +00	4,670E +00	4,660E +00
Max	4,690E +00	4,680E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,660E +00
Mean	4,690E +00	4,673E +00	4,680E +00	4,667E +00	4,680E +00	4,670E +00	4,660E +00
Sigma	0,000E +00	5,773E -03	0,000E +00	5,774E -03	0,000E +00	2,634E -09	2,634E -09

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,680E +00
6	4,680E +00
7	4,680E +00
Statistics	
Min	4,680E +00
Max	4,680E +00
Mean	4,680E +00
Sigma	0,000E +00



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: High Level Output Voltage Pin 23: VOHO**  
**VA=+5V; VD=+5V; VDI/O=+4.75V; IOH=-360uA**

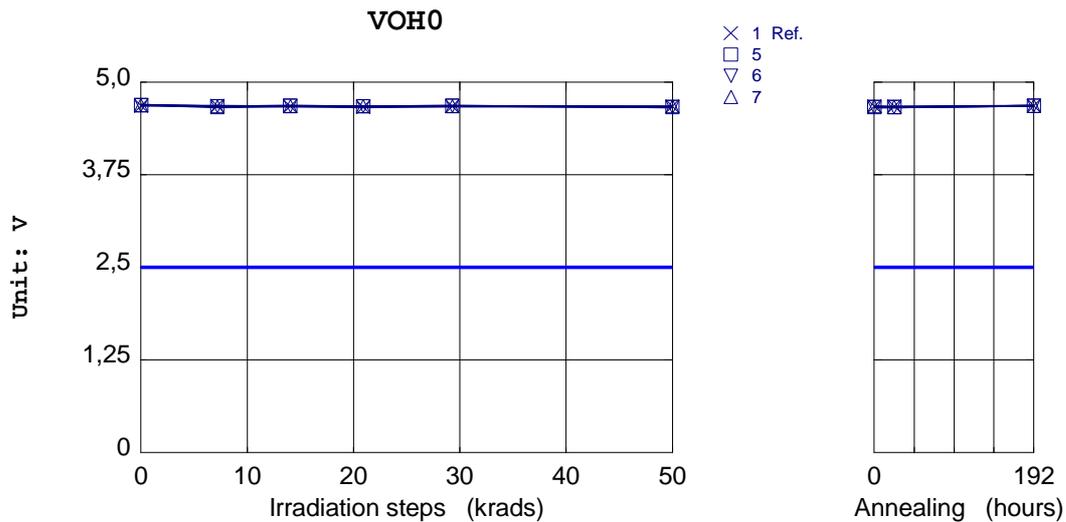
Unit= V

Spec limit min: 2.5

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	4,680E +00	4,680E +00	4,670E +00	4,660E +00	4,670E +00	4,670E +00	4,670E +00
5	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,660E +00	4,660E +00
6	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,660E +00	4,660E +00
7	4,690E +00	4,660E +00	4,670E +00	4,670E +00	4,670E +00	4,670E +00	4,660E +00
Statistics							
Min	4,690E +00	4,660E +00	4,670E +00	4,670E +00	4,670E +00	4,660E +00	4,660E +00
Max	4,690E +00	4,670E +00	4,680E +00	4,670E +00	4,680E +00	4,670E +00	4,660E +00
Mean	4,690E +00	4,667E +00	4,677E +00	4,670E +00	4,677E +00	4,663E +00	4,660E +00
Sigma	0,000E +00	5,774E -03	5,773E -03	2,634E -09	5,773E -03	5,774E -03	2,634E -09

Test Step	192 hours
Serial #	
1 Ref.	4,680E +00
5	4,680E +00
6	4,680E +00
7	4,680E +00
Statistics	
Min	4,680E +00
Max	4,680E +00
Mean	4,680E +00
Sigma	0,000E +00



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Output Voltage Pin 38: VOL13  
VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

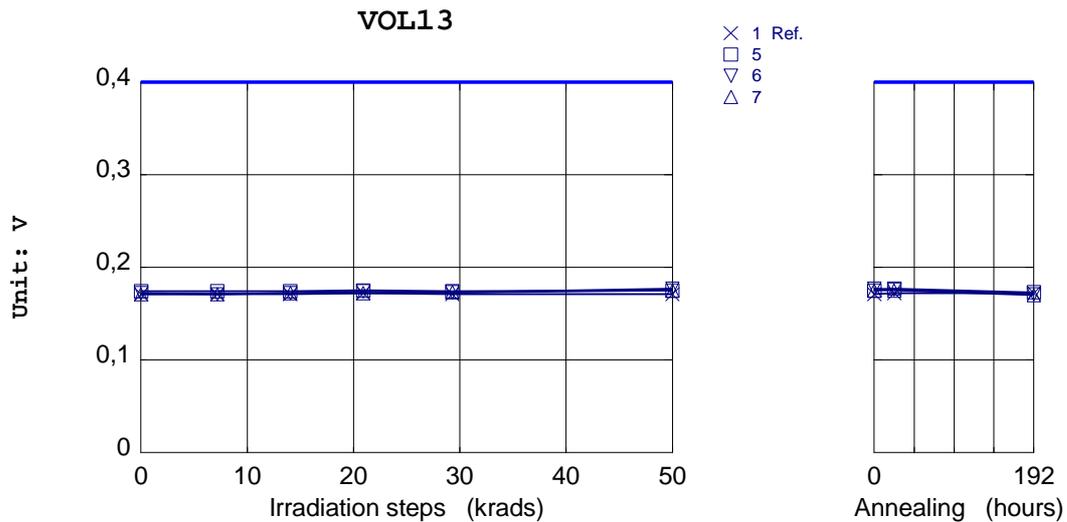
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,710E -01	1,710E -01	1,710E -01	1,720E -01	1,710E -01	1,710E -01	1,720E -01
5	1,740E -01	1,740E -01	1,740E -01	1,750E -01	1,740E -01	1,750E -01	1,770E -01
6	1,720E -01	1,710E -01	1,720E -01	1,740E -01	1,730E -01	1,770E -01	1,760E -01
7	1,710E -01	1,710E -01	1,720E -01	1,720E -01	1,730E -01	1,750E -01	1,750E -01
Statistics							
Min	1,710E -01	1,710E -01	1,720E -01	1,720E -01	1,730E -01	1,750E -01	1,750E -01
Max	1,740E -01	1,740E -01	1,740E -01	1,750E -01	1,740E -01	1,770E -01	1,770E -01
Mean	1,723E -01	1,720E -01	1,727E -01	1,737E -01	1,733E -01	1,757E -01	1,760E -01
Sigma	1,528E -03	1,732E -03	1,155E -03	1,528E -03	5,774E -04	1,155E -03	1,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,720E -01
5	1,730E -01
6	1,710E -01
7	1,700E -01
Statistics	
Min	1,700E -01
Max	1,730E -01
Mean	1,713E -01
Sigma	1,528E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Output Voltage Pin 37: VOL12  
VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

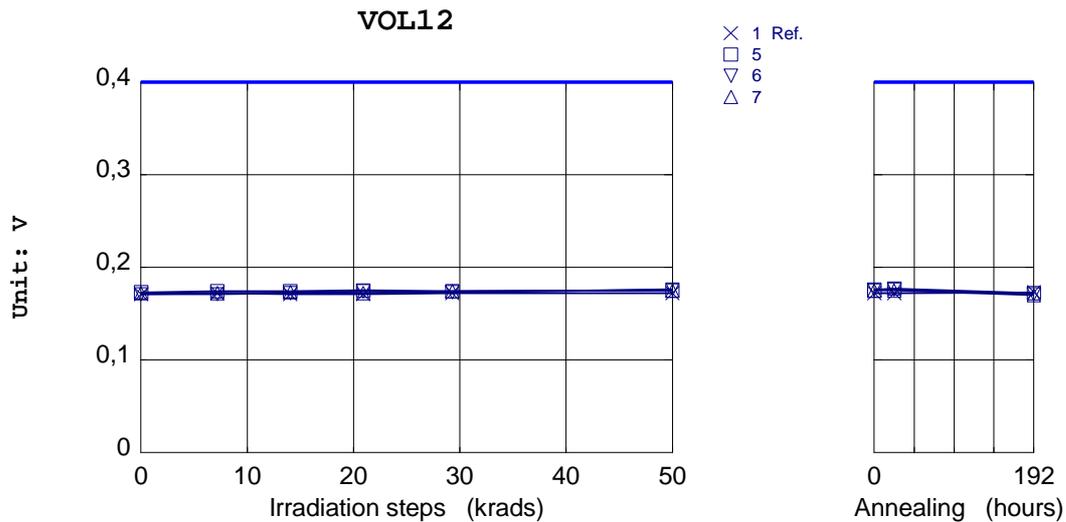
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,710E -01	1,720E -01	1,710E -01	1,710E -01	1,720E -01	1,720E -01	1,720E -01
5	1,730E -01	1,740E -01	1,740E -01	1,750E -01	1,740E -01	1,750E -01	1,770E -01
6	1,710E -01	1,710E -01	1,720E -01	1,740E -01	1,730E -01	1,760E -01	1,760E -01
7	1,720E -01	1,720E -01	1,730E -01	1,720E -01	1,740E -01	1,750E -01	1,750E -01
Statistics							
Min	1,710E -01	1,710E -01	1,720E -01	1,720E -01	1,730E -01	1,750E -01	1,750E -01
Max	1,730E -01	1,740E -01	1,740E -01	1,750E -01	1,740E -01	1,760E -01	1,770E -01
Mean	1,720E -01	1,723E -01	1,730E -01	1,737E -01	1,737E -01	1,753E -01	1,760E -01
Sigma	1,000E -03	1,528E -03	1,000E -03	1,528E -03	5,774E -04	5,774E -04	1,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,730E -01
5	1,720E -01
6	1,710E -01
7	1,700E -01
Statistics	
Min	1,700E -01
Max	1,720E -01
Mean	1,710E -01
Sigma	1,000E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Output Voltage Pin 36: VOL11  
VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

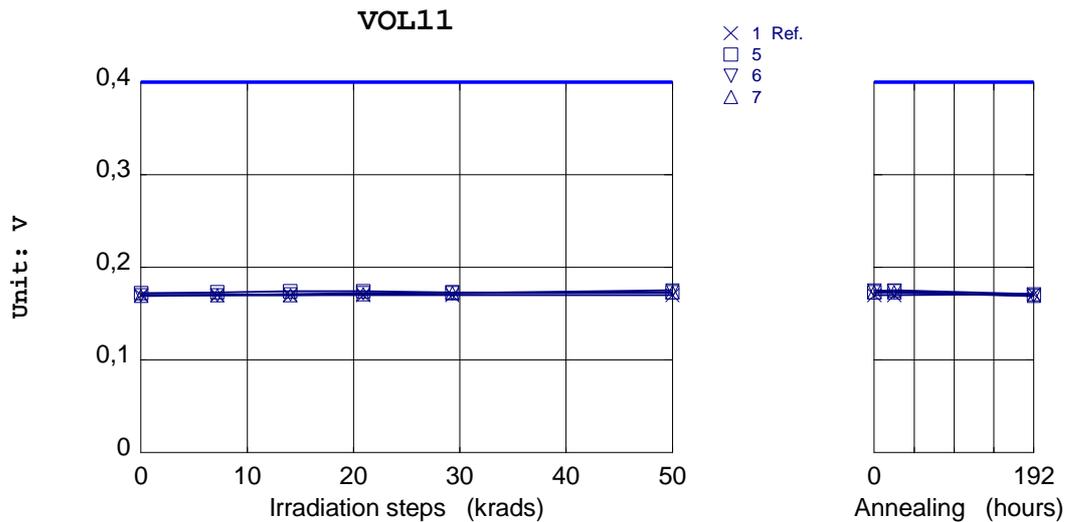
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,700E -01						
5	1,720E -01	1,730E -01	1,740E -01	1,740E -01	1,730E -01	1,730E -01	1,750E -01
6	1,700E -01	1,700E -01	1,710E -01	1,720E -01	1,720E -01	1,750E -01	1,740E -01
7	1,690E -01	1,700E -01	1,700E -01	1,710E -01	1,720E -01	1,730E -01	1,730E -01
Statistics							
Min	1,690E -01	1,700E -01	1,700E -01	1,710E -01	1,720E -01	1,730E -01	1,730E -01
Max	1,720E -01	1,730E -01	1,740E -01	1,740E -01	1,730E -01	1,750E -01	1,750E -01
Mean	1,703E -01	1,710E -01	1,717E -01	1,723E -01	1,723E -01	1,737E -01	1,740E -01
Sigma	1,528E -03	1,732E -03	2,082E -03	1,528E -03	5,773E -04	1,155E -03	1,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,710E -01
5	1,710E -01
6	1,690E -01
7	1,690E -01
Statistics	
Min	1,690E -01
Max	1,710E -01
Mean	1,697E -01
Sigma	1,155E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 35: VOL10**  
**VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA**

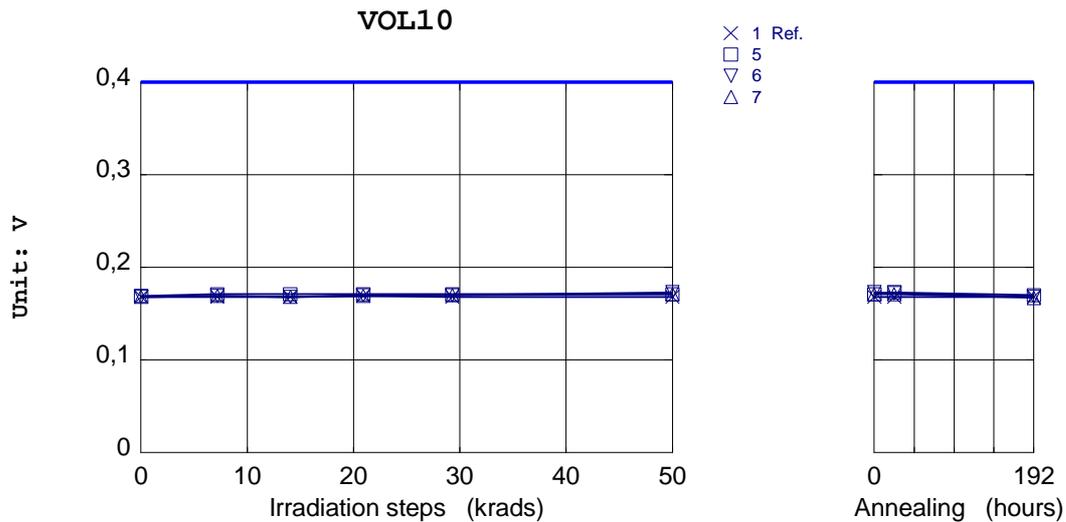
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,680E -01	1,680E -01	1,680E -01	1,690E -01	1,680E -01	1,680E -01	1,680E -01
5	1,690E -01	1,710E -01	1,730E -01				
6	1,680E -01	1,690E -01	1,680E -01	1,700E -01	1,700E -01	1,730E -01	1,720E -01
7	1,680E -01	1,690E -01	1,680E -01	1,690E -01	1,700E -01	1,710E -01	1,710E -01
Statistics							
Min	1,680E -01	1,690E -01	1,680E -01	1,690E -01	1,700E -01	1,710E -01	1,710E -01
Max	1,690E -01	1,710E -01	1,710E -01	1,710E -01	1,710E -01	1,730E -01	1,730E -01
Mean	1,683E -01	1,697E -01	1,690E -01	1,700E -01	1,703E -01	1,717E -01	1,720E -01
Sigma	5,774E -04	1,155E -03	1,732E -03	1,000E -03	5,774E -04	1,155E -03	1,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,680E -01
5	1,700E -01
6	1,680E -01
7	1,670E -01
Statistics	
Min	1,670E -01
Max	1,700E -01
Mean	1,683E -01
Sigma	1,528E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 32: VOL9**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

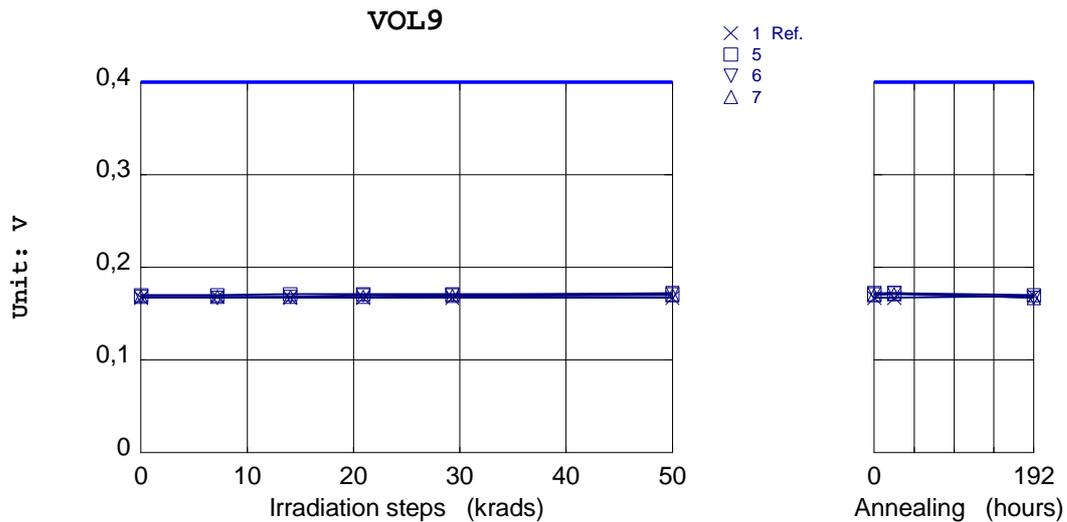
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,670E -01	1,680E -01	1,670E -01				
5	1,700E -01	1,700E -01	1,710E -01	1,710E -01	1,710E -01	1,710E -01	1,720E -01
6	1,680E -01	1,670E -01	1,680E -01	1,700E -01	1,700E -01	1,720E -01	1,720E -01
7	1,680E -01	1,680E -01	1,680E -01	1,680E -01	1,690E -01	1,700E -01	1,710E -01
Statistics							
Min	1,680E -01	1,670E -01	1,680E -01	1,680E -01	1,690E -01	1,700E -01	1,710E -01
Max	1,700E -01	1,700E -01	1,710E -01	1,710E -01	1,710E -01	1,720E -01	1,720E -01
Mean	1,687E -01	1,683E -01	1,690E -01	1,697E -01	1,700E -01	1,710E -01	1,717E -01
Sigma	1,155E -03	1,528E -03	1,732E -03	1,528E -03	1,000E -03	1,000E -03	5,774E -04

Test Step	192 hours
Serial #	
1 Ref.	1,690E -01
5	1,700E -01
6	1,670E -01
7	1,670E -01
Statistics	
Min	1,670E -01
Max	1,700E -01
Mean	1,680E -01
Sigma	1,732E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 31: VOL8**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

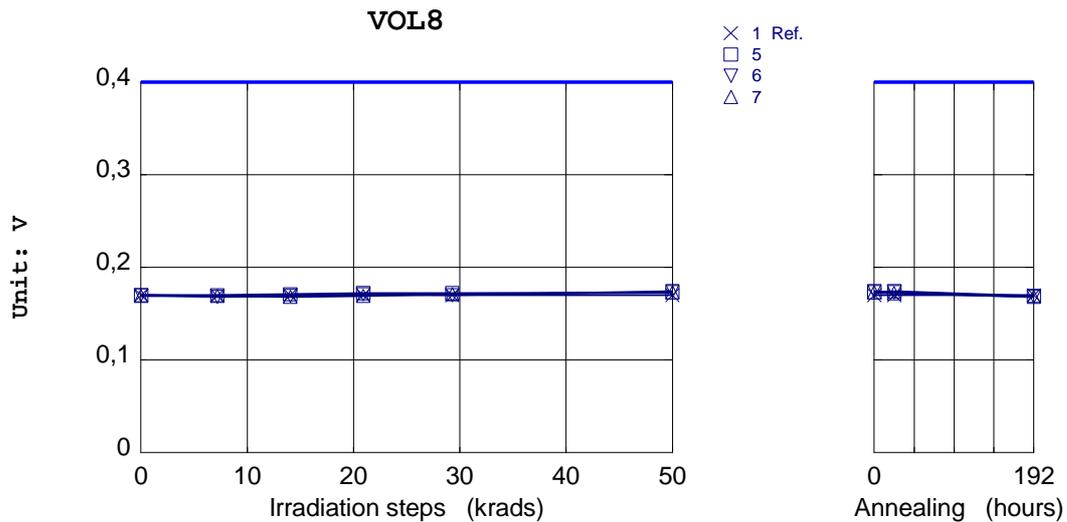
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,700E -01	1,690E -01	1,700E -01				
5	1,700E -01	1,700E -01	1,710E -01	1,720E -01	1,720E -01	1,730E -01	1,740E -01
6	1,700E -01	1,680E -01	1,690E -01	1,710E -01	1,700E -01	1,740E -01	1,730E -01
7	1,690E -01	1,690E -01	1,680E -01	1,690E -01	1,710E -01	1,730E -01	1,720E -01
Statistics							
Min	1,690E -01	1,680E -01	1,680E -01	1,690E -01	1,700E -01	1,730E -01	1,720E -01
Max	1,700E -01	1,700E -01	1,710E -01	1,720E -01	1,720E -01	1,740E -01	1,740E -01
Mean	1,697E -01	1,690E -01	1,693E -01	1,707E -01	1,710E -01	1,733E -01	1,730E -01
Sigma	5,774E -04	1,000E -03	1,528E -03	1,528E -03	1,000E -03	5,774E -04	1,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,700E -01
5	1,690E -01
6	1,680E -01
7	1,680E -01
Statistics	
Min	1,680E -01
Max	1,690E -01
Mean	1,683E -01
Sigma	5,774E -04



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 30: VOL7**

**VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA**

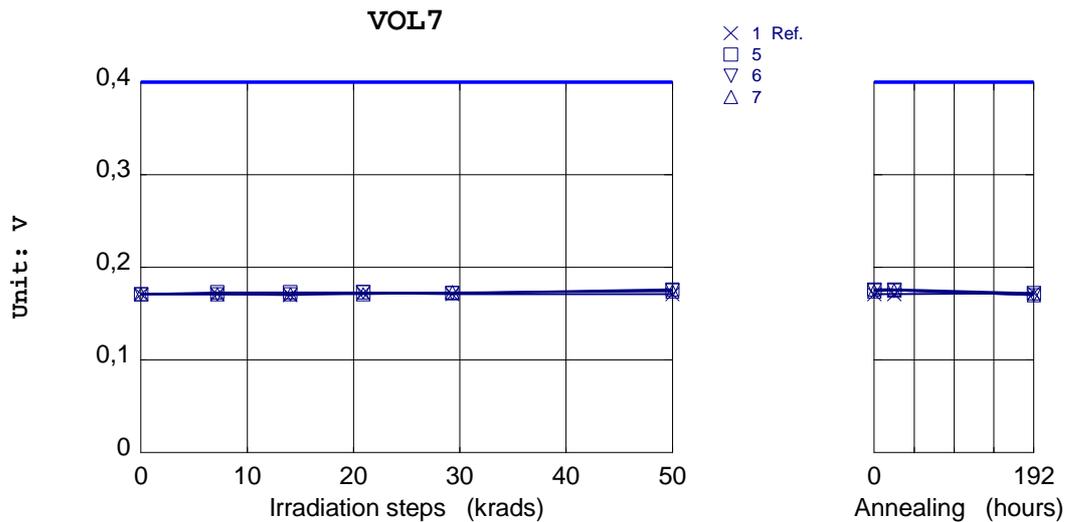
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,710E -01	1,710E -01	1,700E -01	1,720E -01	1,710E -01	1,710E -01	1,710E -01
5	1,710E -01	1,730E -01	1,730E -01	1,730E -01	1,720E -01	1,760E -01	1,760E -01
6	1,710E -01	1,710E -01	1,710E -01	1,730E -01	1,720E -01	1,750E -01	1,750E -01
7	1,710E -01	1,710E -01	1,710E -01	1,710E -01	1,730E -01	1,740E -01	1,750E -01
Statistics							
Min	1,710E -01	1,710E -01	1,710E -01	1,710E -01	1,720E -01	1,740E -01	1,750E -01
Max	1,710E -01	1,730E -01	1,730E -01	1,730E -01	1,730E -01	1,760E -01	1,760E -01
Mean	1,710E -01	1,717E -01	1,717E -01	1,723E -01	1,723E -01	1,750E -01	1,753E -01
Sigma	8,232E -11	1,155E -03	1,155E -03	1,155E -03	5,773E -04	1,000E -03	5,774E -04

Test Step	192 hours
Serial #	
1 Ref.	1,720E -01
5	1,720E -01
6	1,700E -01
7	1,700E -01
Statistics	
Min	1,700E -01
Max	1,720E -01
Mean	1,707E -01
Sigma	1,155E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 29: VOL6**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

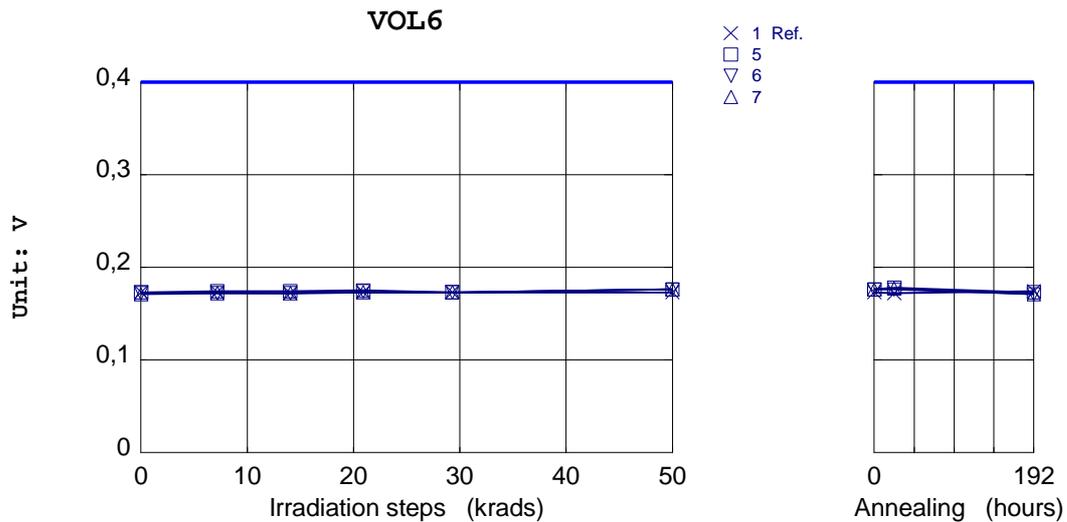
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,730E -01	1,730E -01	1,720E -01	1,730E -01	1,730E -01	1,730E -01	1,720E -01
5	1,730E -01	1,740E -01	1,740E -01	1,750E -01	1,730E -01	1,760E -01	1,780E -01
6	1,720E -01	1,720E -01	1,720E -01	1,740E -01	1,730E -01	1,760E -01	1,760E -01
7	1,710E -01	1,720E -01	1,720E -01	1,730E -01	1,730E -01	1,760E -01	1,770E -01
Statistics							
Min	1,710E -01	1,720E -01	1,720E -01	1,730E -01	1,730E -01	1,760E -01	1,760E -01
Max	1,730E -01	1,740E -01	1,740E -01	1,750E -01	1,730E -01	1,760E -01	1,780E -01
Mean	1,720E -01	1,727E -01	1,727E -01	1,740E -01	1,730E -01	1,760E -01	1,770E -01
Sigma	1,000E -03	1,155E -03	1,155E -03	1,000E -03	5,821E -11	0,000E +00	1,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,740E -01
5	1,730E -01
6	1,710E -01
7	1,710E -01
Statistics	
Min	1,710E -01
Max	1,730E -01
Mean	1,717E -01
Sigma	1,155E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 28: VOL5**

VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

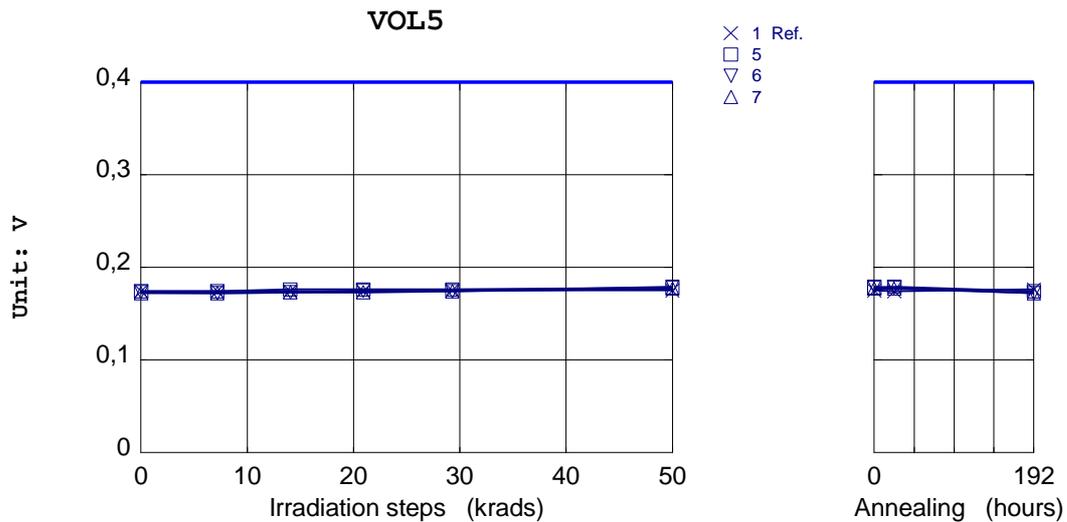
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,740E -01	1,740E -01	1,740E -01	1,740E -01	1,750E -01	1,750E -01	1,740E -01
5	1,740E -01	1,740E -01	1,760E -01	1,760E -01	1,760E -01	1,780E -01	1,790E -01
6	1,730E -01	1,720E -01	1,730E -01	1,750E -01	1,740E -01	1,790E -01	1,780E -01
7	1,720E -01	1,720E -01	1,730E -01	1,730E -01	1,740E -01	1,770E -01	1,770E -01
Statistics							
Min	1,720E -01	1,720E -01	1,730E -01	1,730E -01	1,740E -01	1,770E -01	1,770E -01
Max	1,740E -01	1,740E -01	1,760E -01	1,760E -01	1,760E -01	1,790E -01	1,790E -01
Mean	1,730E -01	1,727E -01	1,740E -01	1,747E -01	1,747E -01	1,780E -01	1,780E -01
Sigma	1,000E -03	1,155E -03	1,732E -03	1,528E -03	1,155E -03	1,000E -03	1,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,760E -01
5	1,740E -01
6	1,720E -01
7	1,720E -01
Statistics	
Min	1,720E -01
Max	1,740E -01
Mean	1,727E -01
Sigma	1,155E -03



HIREX Engineering	Total Dose Test Report			Réf. : HRX/99.5072
				Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

Parameter: Low Level Output Voltage Pin 27: VOL4  
VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA

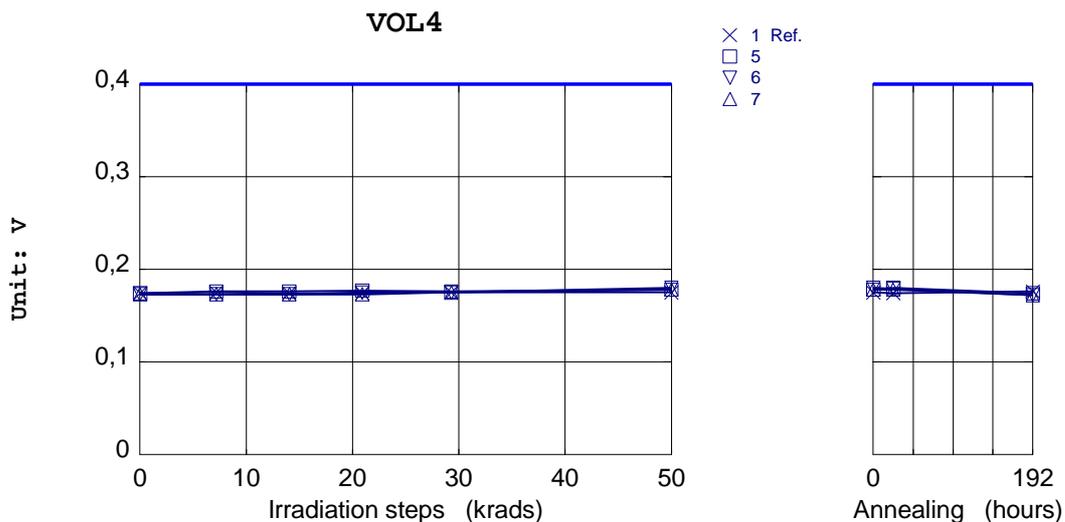
Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,740E -01	1,750E -01	1,740E -01	1,740E -01	1,750E -01	1,750E -01	1,740E -01
5	1,740E -01	1,760E -01	1,760E -01	1,770E -01	1,760E -01	1,780E -01	1,800E -01
6	1,730E -01	1,730E -01	1,730E -01	1,750E -01	1,750E -01	1,800E -01	1,790E -01
7	1,730E -01	1,730E -01	1,730E -01	1,730E -01	1,750E -01	1,780E -01	1,780E -01
Statistics							
Min	1,730E -01	1,730E -01	1,730E -01	1,730E -01	1,750E -01	1,780E -01	1,780E -01
Max	1,740E -01	1,760E -01	1,760E -01	1,770E -01	1,760E -01	1,800E -01	1,800E -01
Mean	1,733E -01	1,740E -01	1,740E -01	1,750E -01	1,753E -01	1,787E -01	1,790E -01
Sigma	5,774E -04	1,732E -03	1,732E -03	2,000E -03	5,774E -04	1,155E -03	1,000E -03

Test Step	192 hours
Serial #	
1 Ref.	1,760E -01
5	1,740E -01
6	1,720E -01
7	1,720E -01
Statistics	
Min	1,720E -01
Max	1,740E -01
Mean	1,727E -01
Sigma	1,155E -03



<b>HIREX Engineering</b>	<b>Total Dose Test Report</b>			Réf. : HRX/99.5072 Issue : 01
Part Type :	ADC14161	Manufacturer :	National Semiconductor	

**Parameter: Low Level Output Voltage Pin 26: VOL3**

**VA=+5V; VD=+5V; VDI/O=+5.25V; IOL=1.6mA**

Unit= V

Spec limit max: 0.4

Spec limits are represented in bold lines on the graphic.

Test Step	Initial	7,2 krad	14,1 krad	21 krad	29,4 krad	50,2 krad	24 hours
Serial #							
1 Ref.	1,760E -01	1,760E -01	1,750E -01	1,760E -01	1,760E -01	1,760E -01	1,760E -01
5	1,750E -01	1,770E -01	1,770E -01	1,780E -01	1,760E -01	1,810E -01	1,820E -01
6	1,760E -01	1,760E -01	1,760E -01	1,780E -01	1,780E -01	1,810E -01	1,810E -01
7	1,750E -01	1,760E -01	1,750E -01	1,760E -01	1,780E -01	1,810E -01	1,810E -01
Statistics							
Min	1,750E -01	1,760E -01	1,750E -01	1,760E -01	1,760E -01	1,810E -01	1,810E -01
Max	1,760E -01	1,770E -01	1,770E -01	1,780E -01	1,780E -01	1,810E -01	1,820E -01
Mean	1,753E -01	1,763E -01	1,760E -01	1,773E -01	1,773E -01	1,810E -01	1,813E -01
Sigma	5,774E -04	5,774E -04	1,000E -03	1,155E -03	1,155E -03	8,232E -11	5,774E -04

Test Step	192 hours
Serial #	
1 Ref.	1,770E -01
5	1,750E -01
6	1,750E -01
7	1,750E -01
Statistics	
Min	1,750E -01
Max	1,750E -01
Mean	1,750E -01
Sigma	8,232E -11

